

ಆರ್.ವಿ ಕಾಲೇಜ್.ಆಫ್.ಇಂಚನಿಯರಿಂಗ್

Master of Technology (M.Tech) in

VLSI DESIGN & EMBEDDED SYSTEM (MVE)

Scheme And Syllabus Of I & IV Semester (2022 Scheme)

B.E. Programs : AI, AS, BT, CH, CS, CV, CD, CY, EC, EE, EI, ET, IM, IS, ME. M. Tech (13) MCA, M.Sc. (Engg.) Ph.D. Programs : All Departments are recognized as Research Centres by VTU Except AI & AS





CURRICULUM STRUCTURE

CREDITS 23 CREDITS PROFESSIONAL **BASIC SCIENCE** CORES (PC) OTHER ELECTIVES CREDITS PROJECT WORK / ENGINEERING SCIENCE & AEC 2CREDITS CREDITS HUMANITIES & PROFESSIONAL 160 SOCIAL SCIENCE ELECTIVES CREDITS

"ABILITY ENHANCEMENT COURSES (AEC), UNIVERSAL HUMAN VALUES (UHV), INDIAN KNOWLEDGE SYSTEM (IKS), YOGA,

Centers of Excellence



1699 Citations

Skill Based Laboratories Across Four Semesters Centers of Competence

397 Publications On Web Of Science



38 Patents Granted

58 Published Patents MOUS: 90+WITH INSDUSTRIES / ACADEMIC INSTITUTIONS IN INDIA & ABROAD

TOTAL

EXECUTED MORE THAN RS.40 CRORES WORTH SPONSORED RESEARCH PROJECTS & CONSULTANCY WORKS SINCE 3 YEARS



RV College of Engineering®

Mysore Road, RV Vidyaniketan Post, Bengaluru - 560059, Kamataka, India

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Master of Technology in

VLSI DESIGN & EMBEDDED SYSTEM

SCHEME & SYLLABUS of I TO IV SEMESTER 2022 SCHEME



RV College of Engineering® Mysore Road, RV Vidyaniketan Poat, Bengaluru - 560059, Karnataka, Inda

Glossary of Abbreviations

1.	AS	Aerospace Engineering
2.	BS	Basic Sciences
3.	BT	Biotechnology
4.	СН	Chemical Engineering
5.	CHY	Chemistry
6.	CIE	Continuous Internal Evaluation
7.	CS	Computer Science & Engineering
8.	CV	Civil Engineering
9.	EC	Electronics & Communication Engineering
10.	EE	Electrical & Electronics Engineering
11.	EI	Electronics & Instrumentation Engineering
12.	ET	Electronics & Telecommunication Engineering
13.	GE	Global Elective
14.	HSS	Humanities and Social Sciences
15.	IM	Industrial Engineering & Management
16.	IS	Information Science & Engineering
17.	L	Laboratory
18.	MA	Mathematics
19.	MBT	M. Tech in Biotechnology
20.	MCE	M. Tech. in Computer Science & Engineering
21.	MCN	M. Tech. in Computer Network Engineering
22.	MCS	M. Tech. in Communication Systems
23.	MDC	M. Tech. in Digital Communication
24.	ME	Mechanical Engineering
25.	MHT	M. Tech. in Highway Technology
26.	MIT	M. Tech. in Information Technology
27.	MMD	M. Tech. in Machine Design
28.	MPD	M. Tech in Product Design & Manufacturing
29.	MPE	M. Tech. in Power Electronics
30.	MSE	M. Tech. in Software Engineering
31.	MST	M. Tech. in Structural Engineering
32.	MVE	M. Tech. in VLSI Design & Embedded Systems
33.	N	Internship
34.	Р	Projects (Minor / Major)
35.	PHY	Physics
36.	SDA	Skill Development Activity
37.	SEE	Semester End Examination
38.	Т	Theory
39.	TL	Theory Integrated with Laboratory
40.	VTU	Visvesvaraya Technological University

Go, change the world"



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POSTGRADUATE PROGRAMS

Sl. No	Core Department	Program	Code
1.	ВТ	M. Tech in Biotechnology	MBT
2.	CS	M. Tech in Computer Science & Engineering	MCE
3.	CS	M. Tech in Computer Network Engineering	MCN
4.	CV	M. Tech in Structural Engineering	MST
5.	CV	M. Tech in Highway Technology	MHT
6.	EC	M. Tech in VLSI Design & Embedded Systems	MVE
7.	EC	M. Tech in Communication Systems	MCS
8.	EE	M. Tech in Power Electronics	MPE
9.	ET	M. Tech in Digital Communication	MDC
10.	IS	M. Tech in Software Engineering	MSE
11.	IS	M. Tech in Information Technology	MIT
12.	ME	M. Tech in Product Design & Manufacturing	MPD
13.	ME	M. Tech in Machine Design	MMD



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DEPARTMENT OF ELECTRONICS & COMMUNICATION ENGINEERING

VISION

Imparting quality technical education through interdisciplinary research, innovation and teamwork for developing inclusive & sustainable technology in the area of Electronics and Communication Engineering

MISSION

1. To impart quality technical education to produce industry-ready engineers with a research outlook.

2. To train the Electronics & Communication Engineering graduates to meet future global challenges by inculcating a quest for modern technologies in the emerging areas.

3. To create centres of excellence in the field of Electronics & Communication Engineering with industrial and university collaborations.

4. To develop entrepreneurial skills among the graduates to create new employment opportunities

PROGRAMME OUTCOMES (PO)

M. Tech in **VLSI Design and Embedded Systems** graduates will be able to:

- PO1: Independently carry out research/investigation and development work to solve the practical problems related to VLSI Design and Embedded Systems.
- PO2: Write and present a substantial technical report/document in the field of VLSI Design and Embedded Systems
- PO3: Demonstrate a degree of mastery over the area of VLSI Design and Embedded Systems. The mastery should be level higher than the requirements of bachelor's in Electronics & Communication Engineering program.
- PO4: Abstract the requirements of modern microelectronics and smart systems to offer innovative solutions with available IPs and interfaces.
- PO5: Design and develop VLSI and Embedded modules with good economics to meet Quality of Service.
- PO6: Acquire professional and intellectual integrity, research ethics and execute socioconcern projects related to modern VLSI and Embedded Systems.



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M.T	ech in VLSI Des	ign & Embedded Systems: MVE										
I SE	MESTER M.Tec	h										
Sl. No.	Course Code	Course Title	Cr L	edit A T/ SDA	lloc P	ation Total	BoS	Category	CIE Duration (H)	Max Marks CIE	SEE Duration (H)	Max Marks SEE
1	MVE201T	Digital System Design with FPGA	3	1	0	4	EC	Theory	1.5	100	3	100
2	MVE202I	Digital IC Design	3	0	1	4	EC	Theory+Lab	1.5	100	3	100
3	MVE203T	Advanced Embedded System Design	3	1	0	4	EC	Theory	1.5	100	3	100
4	MVE204L	ARM CPUs Programming Lab	1	0	1	2	EC	Lab	1.5	50	3	50
5	MVE301AX	Elective A (Professional Elective)	3	0	0	3	EC	Theory	1.5	100	3	100
6	MVE302BX	Elective B (Professional Elective)	3	0	0	3	EC	Theory	1.5	100	3	100
Note	: For the course o	ode 22HSS42, Students need to select one ONLINE 1	MOC	C cou	irse	as reco	ommended	by HSS BoS.	This cours	e can be	e selected	

anytime between I to III semester and it will be evaluated during IV semester.

Code	Elective A (Professional Elective)	Code	Elective B (Professional Elective)
MVE301A1	Low Power VLSI Design	MVE302B1	Static Timing Analysis
MVE301A2	ASIC Design	MVE302B2	System On Chip Design
MVE301A3	VLSI Digital Signal Processing	MVE302B3	IC Technology
MVE301A4	Real Time Embedded Systems	MVE302B4	IOT System Design & Architecture
MVE301A5	Semiconductor Device Modelling	MVE302B5	VLSI for Data Conversion Circuits

II S	EMESTER M.T.	ech										
S1. No.	Course Code	Course Title	Cr L	edit A T/ SDA	lloc P	ation Total	BoS	Category	CIE Duration (H)	Max Marks CIE	SEE Duration (H)	Max Marks SEE
1	MIM431T	Research Methodology	3	0	0	3	IM	Theory	1.5	100	3	100
2	MVE331I	Analog IC Design	3	0	1	4	EC	Theory+Lab	1.5	100	3	100
З	MVE332T	System Verilog for Design & Verification	3	0	0	3	EC	Theory	1.5	100	3	100
4	MCS333CX	Elective C (Professional Elective)	3	0	0	3	EC	Theory	1.5	100	3	100
5	22XXX2DXXT	Elective G (Global Elective)	3	0	0	3	Res. BoS	Theory	1.5	100	3	100
6	MVE431L	Analog Layout Design Lab	1	0	1	2	EC	Lab	1.5	50	3	50
7	MHS131T	Professional Skills Development-I	2	0	0	2	HSS	Theory*	1.5	50	2	50



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* External Agency will be conducting the classes and both CIE and SEE will be evaluated by the Agency.

Code	Elective C (Professional Elective)
MCS333C1	Development of Modern SoCs for Wireless, Wireline and IOT applications
MVE333C2	.VLSI Memory Chip Design
MVE333C3	Robotics and Industrial Automation
MVE333C4	Automotive Electronics
MVE333C5	Physical Design

Elective G (Global E	lective)		
MBT331G	Bioinspired Engineering	MET331G	Tracking and Navigation Systems
MBT332G	Health Informatics	MIM331G	Project Management
MCS331G	Business Analytics	MIS331G	Database and Information Systems
MCV331G	Industrial and Occupational Health and Safety	MIS332G	Management Information Systems
MCV332G	Intelligent Transportation Systems	MMA331G	Statistical and Optimization Methods
MEC331G	Electronic System Design	MME331G	Industry 4.0
MEC332G	Evolution of Wireless Technologies		

III S	SEMESTER M.T	`ech										
S 1			Cr	edit A	lloca	ation			CIE	Max	SEE	Max
No	Course Code	Course Title	I.	Τ/	Р	Tota1	BoS	Category	Duration	Marks	Duration	Marks
110.			1	SDA	1	Total			(H)	CIE	(H)	SEE
1	MVE361T	Algorithms for VLSI Design Automation	3	1	0	4	EC	Theory	1.5	100	3	100
2	MVE337DX	Elective D (Professional Elective)	3	1	0	4	EC	Theory	1.5	100	3	100
3	MVE461N	Internship	0	0	6	6	EC	Internship	1.5	50	3	50
4	MVE461P	Minor Project	0	0	6	6	EC	Project	1.5	50	3	50



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Code	Elective D (Professional Elective)
MVE337D1	VLSI Testing
MVE337D2	High Speed Digital Design
MVE337D3	RFIC Design
MVE337D4	Signal Processing & ML on Microcontrollers
MVE337D5	MEMS and Smart System

IV S	EMESTER M.T	ech		in the second	1000							
Sl. No.	Course Code	Course Title	Cr L	T/	P	ation Total	BoS	Category	CIE Duration (H)	Max Marks CIE	SEE Duration (H)	Max Marks SEE
1	MVE491P	Major Project	0	0	18	18	EC	Project	1.5	100	3	100
2	MHS191	Professional Skills Development-II	2	0	0	2	HSS	NPTEL		50	ONLINE	50
Stud	lent need to sul	omit the certificate for the evaluation of Course code	MH	\$191		412 8		100 C 100 C 17	1510			

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		SEMESTER: I	1									
Course Code	: MVE201T	Digital System Design with FPGA	CIE Marks	: 100								
Credits L-T-P	dits L-T-P:3-1-0SEE Marks:ars:42L + 28T(Professional Core - 1)SEE Durations:											
Hours: 42L + 28T(Professional Core - 1)SEE Durations: 3												
Faculty Coordinator: Dr. Soumya K B												
UNIT - I 9 Hrs												
Introduction to and Constant. V Test-benches. V Logic and Signa Numbers. Introduction to Methodology: D Design Optimization-As Number Basics	Verilog and Desi Verilog Operators Verilog Primitives al Resolution in V Design Methodo Vesign Flow-Archi rea, Timing and M	ign Methodology: Verilog IEEE standards, Veri s, Number representation and Verilog ports,Sin . Logic Simulation, Design Verification, and Te Verilog, Test Methodology Signal Generators for logy: Digital Systems and Embedded Systems, itecture, Functional design and verification, Sy Power, System representation. UNIT - II lelling Styles: Number Basics: Unsigned and S	log Data Types: N nulation and Syn est Methodology: 1 r Test benches, S Real-world circu enthesis, Physical	et, Register thesis, Four-Value ized its. Design design. 9 Hrs xed-								
point and Float Boolean switch Behavioural Mc Flip-Flops and circuits. Datafle Delay and Cont Structural Mod Nested Modules. (Hand	ing-point Numbe ing function, Bin odelling: Latches Latches, Behavio ow Modelling: Bo inuous Assignme elling: Design of ls on using Xiling	ers. Boolean Functions and Boolean Algebra, V ary Coding. and Level-Sensitive Circuits in Verilog, Cyclic bural Models of Multiplexers, Encoders, Decode olean Equation-Based Models of Combinationa ents. Linear-Feedback Shift Register. Tasks & Combinational Logic, Verilog Structural Model	erilog models for Behavioural Moders and Arithmeti al Logic, Propagat Functions. Is, Top-Down Des	els of c ion ign and								
UNIT - III 8 Hrs												
Synthesis of Digital Sub-systems: Synthesis of Combinational Sub-systems: Introduction to Synthesis, Synthesis of Combinational Logic, Synthesis of Sequential Logic with Latches, Synthesis of Three-state Devices and Bus Interfaces. Synthesis of Sequential Sub-systems: Synthesis of Sequential Logic with Flip-Flops, Synthesis of Explicit State Machines, Registered Logic, State Encoding, Synthesis of Implicit State Machines, Registers and Counters. (Hand on using Xilinx Vivado)												
		UNIT - IV		8 Hrs								
System Implementation and Fabrics:CPLD vs FPGA Architecture - Programming Technologies-Chip I/O- Programmable Logic Blocks- Fabric and Architecture of FPGA. Xilinx Virtex 5.0 Architecture - Xilinx Virtex VI Architecture - ALTERA Cyclone II Architecture - ALTERA Stratix IV Architecture, Hardcore and Softcore FPGA. (Examples such as counter, sequence detector, sequence generated etc are implemented on Airtex-7 FPGA board)												
		UNIT - V		8 Hrs								
Processor Desig Addition, Subtr Controller Desig Computer Orga controllers, Par Transmission.	gn and System D action and Multi gn, Efficient STG nization, Instruc allel Buses, Seria	evelopment: Design of Processor Architectures plication (overview). Design: Hierarchical Deco -Based Sequential Binary Multiplier. Interfacin tion and Data, Memory Interfacing. I/O Interfa al	: Functional Unit mposition STG-B ng Concepts: Emb acing: I/O devices	s for ased bedded 5, I/O								
After going thro	nes: ough this course	the student will be able to:										



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CO	1	: Define IEEE-1364 standard and identify different styles of modelling to build digital systems.
CO	2	: Analyze digital systems and build small scale applications using Interfacing concepts.
CO	3	: Design and verify the behavior of digital circuits using digital flow.
CO	4	: Demonstrate the skill on cost-effective system designs through proper selection of implementation.

Reference Books

1. Advanced Digital Design With the Verilog HDL, Michael D. Ciletti, 2nd Edition, 2015, PHI, ISBN: 978–0–07–338054–4.

2. Digital Design: An Embedded Systems Approach Using VERILOG, Peter J. 1st Edition, 2010, Ashenden,

Elsevier, ISBN: 978-0-12-369527-7

3. Digital Systems Design Using Verilog, 1st Edition, 2015, Charles Roth, Lizy K. John, ByeongKil Lee, Cengage

Learning, ISBN-10: 1285051076

4. Fundamentals ofDigital Logic with Verilog Design, Stephen Brown and ZvonkoVranesic, 6th Edition, 2014,

McGraw Hill publication, ISBN: 978-0-07-338054-4

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100

Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full question from each unit.

ě	RUBRIC for CIE			RUBRIC for SEE				
SLNo	Content	Marks	Q. No	Contents	Marks			
1	Quizzes Q1 & Q2	20	Each u	nit consists of TWO questions of 20 Marks each. Answ	er FIVE			
2	Tests - T1 & T2	40		full questions selecting ONE from each unit [1 to 5].				
3	Experiential Learning - EL1 & EL2	40	182	Unit-1: Quantion 1 or 2	20			
	Total Marks	100	38.4	Unit-2: Quantion 3 or 4	20			
			586	Unit-3: Question 5 or 6	20			
			788	Unit-4: Question 7 or 8	20			
			9 & 10	Unit-5: Question 9 or 10	20			
				Total Marks	100			

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		SEMESTER: I			
Course Code	: MVE202I	Digital IC Design	CIE Marks	:	100
Credits L-T-P	: 3-0-1		SEE Marks	:	100
Hours	: 42 L + 28P	Theory & Practice - (Professional Core - 2)	SEE Durations	: 3	3 Hrs
Facu	lty Coordinator:	Dr. Kariyappa B S	- 1	I	
	5	UNIT - I			9 Hrs
CMOS inverter: Components of Complementary Design Conside Dynamic gates.	MOSFET- static Energy and Pow CMOS, Ratioed erations. Speed a	e & dynamic behavior, Static CMOS Inv ver CMOS Combinational Logic Circuit Logic, Pass Transistor Logic. Dynamic and Power Dissipation of Dynamic logic	rerter: static and dy Design: Static CMO CMOS Design: Dyr , Signal integrity iss	namic Bei S Design: Iamic Log Sues, Caso	havior, țic cading
		UNIT - II			9 Hrs
CMOS Sequent Pulse Based Re design: Memory core –	ial Logic Circuit gisters. Sense Ar ROM, SRAM, DF	Design: Static Latches and Registers. I mplifier based registers. Pipelining con- RAM, Sense amplifiers, CAM	Dynamic Latches an cepts. Memory & Ar	d Registe ray struct	rs. tures
		UNIT - III	6	1	8 Hrs
carry lookahead adde Interconnects: Issues: Timing	er, Multiplier- arr Interconnect Imp classification of	ray, carry save multiplier, Barrel shifter UNIT - IV Dact, Resistive, Capacitive and Inductiv digital systems - Synchronous Design -	r and Logarithmic s e Parasitics, Crosst Origins of Clock	hifter.	8 Hrs ol, Timing
Skew/Jitter an	d Impact on Perf	formance.	1		
Clock Distribut clocking. Self-T Signal Generati Self-Timed Sigr Locked Loop.	ion and Self-Tim imed Circuit Des ion, naling.Synchroni	ed Circuit Design: Clock Distribution t sign: Self-Timed Logic - An Asynchrono zers and Arbiters, Clock Synthesis and	echniques, Latch ba us Technique, Com Synchronization U	ased pletion- sing a Pha	ase-
		LABORATORY	100	28	Hrs
 MOS device C CMOS Static CMOS Inverte CMOS 2 Inpu Layout Simulat CMOS Inverte Realize 2-bit n Realize 6T an Analysis of Ti Case Study: A 	Characterization Inverter Charact er Dynamic Char t NAND Gate, Cl ion er, NAND and NC multiplier circuit d 8T SRAM. Pre- ming reports of a ASIC Design flow	eristics Facteristics MOS 2 Input NOR Gate, Compound/Co OR Layout & Post-Layout Simulation - using Half adder and AND gate. Layout Simulation and Post layout sim a given design	omplex Gates & Pre-	n of N Bit	counter
a a a					
After going three	nes:	the student will be able to:			
	· Investigate de	vice circuit & system aspects of digital	IC design		
CO2	: Analyze the fu	inctionality of digital integrated circuits	& systems		
CO3	: Design digital	integrated circuit & systems			
	0	0			



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CO4 : Evaluate the different performance parameters of a digital integrated circuits & systems

Reference Books

1. Jan M.Rabaey, Anantha Chadrakasan, Borivoje Nikolic, "Digital Integrated Circuits: A Design Perspective", (2/e), Pearson 2016, ISBN-13: 978-0130909961

2. Erik Brunvand, "Digital VLSI Chip Design with Cadence and Synopsys CAD Tools", 1st Edition, Pearson 2009, ISBN: 9780321547996

3. CMOS VLSI Design, Neil H.E. Weste, David Harris, Ayan Banerjee, 3rd Edition, 2006, Pearson Education, ISBN: 0321149017

4. Sung MO Kang, Yousuf Leblebici, "CMOS Digital Integrated Circuits"; Tata McGrawHill, (3/e), 2003, ISBN: 0-7923-7246-8

Scheme of Continuous Internal Evaluation (CIE): 10 + 30 + 30 + 30 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The average of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 30 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (10), Video based seminar

/presentation /demonstration (20) adding upto 30 marks.

Laboratory: Conduction of laboratory exercises, Lab report & observation & analysis (30 Marks), Lab Test (10 Marks) & Innovative Experiment/Concept Design & Implementation (10 Marks) adding up to 50 Marks. The final marks will be reduced to 30 Marks.

Scheme of Semester End Examination (SEE) for 100 marks: Each unit consists of TWO Questions of 16 Marks each. Answer FIVE full questions selecting one from each unit (from 1 to 5). Question No. 11 is compulsory (Laboratory component) for 20 Marks.

			Labora	itory		
	RUBRIC of CIE			RUBRIC of SEE		
SLNo	Content	Marks	Q. No	Contents	Mari	
1 Quizzos - Q1 & Q2 10				nit consists of TWO questions of 16 Marks each. Answ	er FT	
2 Tests - T1 & T2 30				on No. 11 is compulsory (Laboratory component) for 20	Mark	
3	Experiential Learning - EL1 & EL2	30	182	Unit-1: Question 1 or 2	16	
4	Laboratory	30	384	Unit-2: Question 3 or 4	16	
	Total Marks	100	5&6	Unit-3: Question 5 or 6	16	
			78.8	Unit-4: Question 7 or 8	16	
	NO SEE for Laboratory			Unit-5: Question 9 or 10	16	
				Laboratory Component (Compulsory)	20	
				Total Marks	1	



			SEMESTER: I			
Course Code	:	MVE203T	Advanced Embedded System Design	CIE Marks	:	100
Credits L-T-P	:	3-1-0		SEE Marks	:	100
Hours	:	42L + 28T	(Professional Core - 3)	SEE Durations	:	3 Hrs
Facu	ılty	v Coordinator:	Dr. Govinda Raju M			
			UNIT			9 Hrs
.		1 11 10	- I			
Introduction to) E	mbedded Syste	em Design	f D = =1 +: = 0+-		
Introduction, C)ha Tra	tracteristics of	Embedding Computing Applications, Concept of	of Real time Syste	ms,	
Challenges III F		ibedded System	d System Architecture	lications, Hardwar	re	
Instruction Set	· A·	nng, Embeuue rchitectures wi	th examples. Memory system Architecture: cac	hes Virtual Memo	arv	
Memory Manag	ver	nent I/O sub s	system: Busy wait I/O DMA Interrunt Driven	I/O Co-Processor	· &.	
Hardware Acce	ler	ators, Process	or performance Enhancement: Pipelining, Supe	rscalar Execution	. Mu	lti
Core CPUs, CP	U				, -	
Power Consum	pt	ion, Benchmar	king Standards: MIPS, MFLOPS, Coremark			
			UNIT			9 Hrs
			- 11			
CPU Bus: Bus Characteristics Watchdog Time	Pr s: F ers	otocols, Bus O RAM, EEPROM , Interrupt, Co	rganization, Introduction to SATA,PCI,PCI-e, M , Flash Memory, DRAM,DDR,; I/O Devices: Tim ntrollers, DMA Controllers, A/D and D/A Conv	emory Devices and ners and Counters rerters, LEDs,OLE	d the s, Ds	eir
		1.8	UNIT - III	Δ		8 Hrs
I2C,		aea System Ha	ardware – in Frogrammed 10, Memory Mapped 10	J, Interfacing Prof	cocol	s. 5F1,
I2C, CAN, Reset Cir Selection Criter	cu ria	its, Designing	with Processors: System Architecture, FPGA ba	D, Interfacing Prof	essor	8 Hrs
I2C, CAN, Reset Cir Selection Criter	ria	its, Designing	with Processors: System Architecture, FPGA ba	J, Interfacing Prof	essor	8 Hrs
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I2C, CAN, Reset Cir Selection Criter Designing Emb Languages, Int Generators, De Time, Energy & Program Size; I 2012/CERT	ria ped eg: bu & P Pro	ded System Ha its, Designing ded System So rated Developn ugger, Board Su ower, ogram Validatio	UNIT - IV oftware –I Application Software, System Software unit Environment tools: Editor, Compiler, Linka upport Library, Chip Support Library, Analysis on & Verification, Embedded System Coding Sta	D, Interfacing Prof used Design, Proce re, Use of High-Lev er, Automatic Cod and Optimization andards: MISRA C	vel : Exe	8 Hrs ecution 8 Hrs
I2C, CAN, Reset Cir Selection Criter Designing Emb Languages, Int Generators, De Time, Energy & Program Size; I 2012/CERT Designing Emb Process Comm Operating Syst Loading, Case & based Resource Monitoring	bed egg bu s P Pro	its, Designing its, Designing ded System So rated Developn gger, Board Su ower, ogram Validatio ded System So ications, Synch Performance: udy: Embeddeo	with Processors: System Architecture, FPGA ba UNIT - IV oftware –I Application Software, System Softwar nent Environment tools: Editor, Compiler, Linka apport Library, Chip Support Library, Analysis on & Verification, Embedded System Coding Sta UNIT - V oftware –II OS based Design, Real Time Kernel, hronization, Case Study: RTX-ARM/FreeRTOS, Response time Calculation, Interrupt Latency, I Control Applications-Software Coding of a PII	D, Interfacing Prof used Design, Proce re, Use of High-Lev er, Automatic Cod and Optimization andards: MISRA (Process& Thread, Evaluating and C Time Loading, Me D Controller, PID 7	vel le : Exc Joptin emor	8 Hrs ecution 8 Hrs r nizing y, ng, IoT
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RV College of

Engineering® Mysore Road, RV Vidyaniketan Post, Bengaluru - 560059, Kamataka, India

CO3	:	Demonstrate the concurrent execution of different operations with support of real time operating systems.
CO4	:	Engage in usage tools to formulate, design and analyze different Applications realized with embedded processors.

Reference Books

1. Embedded Systems – A contemporary Design Tool, James K Peckol, 2nd edition, John Weily, 2008, ISBN: 0-444-51616-6

2. Introduction to Embedded Systems, Shibu K V, 1st edition, Tata McGraw Hill Education Private Limited, 2009, ISBN: 10: 0070678790

3. Embedded Software Primer, David E.Simon, Addison Wesley, 2nd edition, John Weily, 2002, ISBN-13: 978-0201615692

4. The Intel Micro-processors, Architecture, Programming and Interfacing, Barry B.Brey, 6th Edition, Pearson

Education, 2008, ISBN-10: 8131726223

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full

question from each unit.

	RUBRIC for CIE			RUBRIC for SEE	
SLNo	Content	Marks	Q. No	Contents	Marks
1	Quizzes - Q1 & Q2	20	Each u	nit consists of TWO questions of 20 Marks each. Answ	er FIVE
2	Tests - T1 & T2	40		full questions selecting ONE from each unit [1 to 5].	
3	Experiential Learning - EL1 & EL2	40	182	Unit-1: Question 1 or 2	20
	Total Marks	100	384	Unit-2: Question 3 or 4	20
			586	Unit-3: Question 5 or 6	20
			788	Unit-4: Question 7 or 8	20
			9 & 10	Unit-5: Question 9 or 10	20
				Total Marks	100



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SEMESTER: 1												
Course Code		MVE204L	ARM CPUs Programming Lab	CIE Marks	:	50						
Credits L-T-P	:	1 - 0 - 1		SEE Marks	:	50						
Hours	:	14L + 28P	(Coding / Skill Laboratory)	SEE Durations	:	3 Hrs						
Faculty Coordinator: Dr. Govinda Raju M												
Со												
nte												
			nt									

Experiments on bare metal programming:

1. Write application program to interface LEDs and push buttons to GPIOs of LPC 1857 cortex M3 evaluation board and demonstrate polling-based IO operation.

2. Write Systick_handler to accurately control the delay between toggling of LEDs to support interrupt driven IO.

3. Write driver for ADC0 in LPC 1857 MCU. Display digital value on GLCD and demonstrate analog sensor interface. 4. Write I2C driver for LPC1857. Develop APIs to support I2C. 5. Write driver to support LM75a digital temperature sensor through I2C. Test the functionality by displaying temperature values on GLCD. 6. Write application program to realize FIR filter on STM32F4 cortex M4 development board. Test the filtering operation on signal generated from function generator and interfaced to STM32F4 development board through WolfsonPI codec.

Experiments using RTOS

1. Create a multitasking application program to demonstrate creation of tasks. Task1 is expected to control the blinking two LEDs and Task2 is to change font and colour of the textual display on GLCD concurrently. 2. Create multitasking program to demonstrate task synchronization. Task1 is expected to display LED blinking pattern and Task2 display textual message on GLCD. 3. Create a multitasking program to demonstrate event flags to synchronize task execution. Create four tasks to simulate the operation of stepper motor driver. 4. Create multitasking program to demonstrate IPC using mailbox. Create a task to read a digital value from ADC and send to another task executing concurrently through mailbox. Synchronize the execution of tasks. 5. Create a 'Blinky' project using RL-ARM real time Kernel to simulate the operations of step-motor driver. Use four LEDs blinking to simulate the activation of the four output driver stages. Create other two tasks executing concurrently and competing for GLCD. The first task displays status of LEDs blinking on GLCD and second task displays a string with changing colour of font and background.

Course Outcon	nes:
After going thro	ough this course th <mark>e student</mark> will be able to:
CO1	: Interpret the information provided in data sheets and schematic diagram to write driver
	code
	for different interfaces for micorocontorllers.
CO2	: Design embedded software to meet given constraints pertaining to both operational and
	non
	operational attributes.
CO3	: Demonstrate the use of real time operating system to support multitasking for concurrent
	execution of different operations.
CO4	: Engage in usage of tools to code application programs by using constructs provided by
	compiler and middleware software packages.
Reference Boo	ks
1. Embedded S	ystems – A contemporary Design Tool, James K Peckol, 2nd edition, John Weily, 2008,
ISBN:	

0-444-51616-6



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2. Introduction to Embedded Systems, Shibu K V, 1st edition, Tata McGraw Hill Education Private Limited, 2009, ISBN: 10: 0070678790

3. Embedded Software Primer, David E.Simon, Addison Wesley, 2nd edition, John Weily, 2002, ISBN-13: 978-0201615692

4. The Intel Micro-processors, Architecture, Programming and Interfacing, Barry B.Brey, 6th Edition, Pearson

Education, 2008, ISBN-10: 8131726223

Scheme of Continuous Internal Evaluation (CIE- Laboratory) : Only LAB Course 30 + 10 + 10 = 50. The Laboratory session is held every week as per the timetable and the performance of the student is evaluated in every session. The average of marks over number of experiments conducted over the weeks is considered for 30 Marks i.e (Lab Report, Observation & Analysis). The students are encouraged to implement additional innovative experiments in the lab (10 marks). At the end of the semester a test is conducted for 10 Marks (Lab

Test). This adds to 50 Marks.

Scheme of Semester End Examination (SEE- Laboratory) : Only LAB Course 40 + 10 =50. Students will be evaluated for Write-up, Experimental Setup, Experiment Conduction with Results, Analysis & Discussions for

40 Marks and Viva will be conducted for 10 Marks adding to 50 Marks.

	Only	LAB	Courses	with	50	Marks	
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1	RUBRIC FOR CIE		RUBRIC FOR SEE	
SI.No	Content	Marks	Content	Marks
1	Write Up, Setup, Conduction Results, Analysis & Discussions	30	1. Write Up, Setup, Conduction	40
2	Innovative Experiment/Concept Design & Implementation	10	2. Results, Analysis & Discussions	40
3	Laboratory Internal	10	Viva Voce	10
	Total Marks	50	Total Marks	50



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Course Code	:	MVE301A1	Low Power VLSI Design	CIE Marks	:	100
Credits L-T-P	:	3-0-0		SEE Marks	:	100
Hours	:	42L	Elective A (Professional Elective)	SEE Durations	:	3 Hrs
Facu	ılty	v Coordinator	r: Dr. Srividya P			
			UNIT - I			9 Hrs
Introduction Integrated circ Device & Techn Dynamic dissig	to cuit nol pat	Low power : ts. Emerging ogy Impact o ion in CMOS	Need for low power VLSI chips, Sources of Low power approaches, Physics of power n Low Power: , Transistor sizing & gate oxide thickness, In	of power dissipat dissipation in C mpact of technolo	ion MO ogy S	on Digital S devices. Scaling,
Technology & I	Je		UNIT - II			9 Hrs
Power estimat	tio	n methods				
Simulation Po estimation, sta correlation ana Probabilistic p techniques, sig	tic aly:	er analysis: S state power, sis in DSP sy ver analysis: l entropy	SPICE circuit simulators, gate level logic sim gate level capacitance estimation, architect stems, Monte Carlo simulation. Random logic signals, probability & frequen	ulation, capacitiv ure level analysis ncy, probabilistic	ve po , da pow	ower ta ver analysis
teeninques, sig	5110	li ciitiopy.	UNIT - III			8 Hrs
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Reference Books

1. Low Power Design Methodologies, Jan M. Rabaey and MassoudPedram, Kluwer Academic Publishers, 5th

reprint, ISBN 978-1-46 13-5975-3, 2002.

2. Practical Low Power Digital VLSI Design, Gary K. Yeap, Kluwer Academic Publishers, ISBN 978-1-4613-7778-8, 2002.

3. Low-Power CMOS VLSI Circuit DesignKaushik Roy and Sharat Prasad, John Wiley, 2000. ISBN 13 9788126520237

4. Low-Power VLSI Circuits and Systems, Ajit Pal, Springer publications, ISBN: ISBN 978-81-322-1936-1, 2015

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100

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EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full

question from each unit.

	RUBRIC fo	T CIE		_	RUBRIC for SEE	
SLNo	Content		Marks	Q. No	Contents	Marks
1	Quinces Q1 & Q2		20	Each u	nit consists of TWO questions of 20 Marks each. Answ	er FIVE
2	Tests - T1 & T2		40		full questions selecting ONE from each unit [1 to 5].	
з	Experiential Learning	ELI & EL2	40	182	Unit-1: Question 1 or 2	20
		Total Marks	100	384	Unit-2: Question 3 or 4	20
				586	Unit-3: Quantion 5 or 6	20
				788	Unit-4: Quantion 7 or 8	20
				9 & 10	Unit-5: Question 9 or 10	20
					Total Marks	100



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		SEMESTER: I		
Course Code	: MVE301A2	4910	CIE Marks	: 100
Credits L-T-P	: 3-0-0	ASIC Design	SEE Marks	: 100
lours	SEE Durations	: 3 Hrs		
Facu	lty Coordinator:	Prof. Sujatha Hiremath	I	- 1 - 1
	-	UNIT - I		9 Hrs
ASIC, Semi-cus gate array, Cha Combinational Sequential logi	stom based ASIC, annelless gate arr Logic Cell – c cell	, Standard Cell based ASIC, Gate array base ay, Structured gate array, Programmable log	d ASIC, Channeled	d
		UNIT - II		9 Hrs
Predicting dela optimum no. o Library cell des	y, logical area, log f stages. sign.	gical efficiency, logical paths, multistage cell	s, optimum delay,	and
		UNIT - III	60	8 Hrs
Physical Design planning tools, and power plan boals and Object	tion: n, CAD Tools, Sys Measurement of nning, and clock j ectives, Placemen	stem Partitioning, Estimating ASIC size, part Delay in Floor-planning, Floor-planning Too planning. Placement Terms and Definitions, t algorithms, iterative placement improveme	titioning methods. ols, Channel Defin Measurement of F nt, Time driven pla	Floor- ition, I/O Placement acement
Physical Design planning tools, and power plan Goals and Object nethods.	tion: n, CAD Tools, Sys Measurement of nning, and clock p ectives, Placemen	stem Partitioning, Estimating ASIC size, part Delay in Floor-planning, Floor-planning Too planning. Placement Terms and Definitions, t algorithms, iterative placement improveme UNIT - IV	titioning methods. ols, Channel Defini Measurement of F nt, Time driven pla	Floor- ition, I/O Placement acement 8 Hrs
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Go, change the world



3. Wayne Wolf, FPGA-Based System Design, Prentice Hall PTR, 2004

4. Andrew B. Kahng , Jens Lienig Igor L. Markov, Jin Hu, VLSI Physical Design: From Graph Partitioning to Timing Closure, Springer Dordrecht Heidelberg London New York, 2011

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full

question from each unit.

1	RUBRIC for	CIK		14	RUBRIC for SEE		
SLNo	Content		Marks	Q. No	Contents		Marks
1	Quizzes - Q1 & Q2		20	Each u	nit consists of TW <mark>O questions of 20 M</mark>	farks each. Answ	er FIVE
2	Tests - T1 & T2		40		full questions selecting ONE from e	ach unit [1 to 5].	
з	Experiential Learning	EL1 & EL2	40	142	Unit-1: Question 1 or 2		20
		Total Marks	100	384	Unit-2: Question 3 or 4		20
	and the second second			5&6	Unit-3: Question 5 or 6		20
				78.8	Unit-4: Question 7 or 8		20
				9 & 10	Unit-5: Question 9 or 10		20
						Total Marks	100

12



		SEMESTER: I			
Course Code	: MVE301A3	VI SI Digital Signal Processing	CIE Marks	:	100
Credits L-T-P	: 3-0-0	VLSI Digital Signal Flocessing	SEE Marks	:	100
Hours	: 42L	Elective A (Professional Elective)	SEE Durations	:	3 Hrs
Facul	ty Coordinator:	Dr. Abhay Deshpande			
		UNIT - I			9 Hrs
Introduction to demands, Scale	Digital Signal Pr d CMOS Techno	ocessing Systems Introduction, Typical DSF logies, Representations of DSP algorithms.	e algorithms, DSP	Ap	plication
		UNIT - II			9 Hrs
Pipelining and I Pipelining and Parallel pro	Parallel Processin	ng Introduction, Pipelining of FIR Digital Filt power using Candence tool.	ers, Parallel Proc	essi	ng,
•		UNIT - III			8 Hrs
Algorithmic stre	ength reduction i	in filters and transforms Introduction, Paral	lel FIR filters, Dis	cret	e Cosine
Transform and	Inverse DCT, Pa	rallel Architectures for Rank-Order Filters.			
		UNIT - IV			8 Hrs
Pipelined and p processing for I Cadence, pipelin Adaptive Digital	arallel Recursive IR filters, Low po ned filter design.	e and Adaptive Filters Introduction, Combine ower IIR digital filter design using pipelining	ed pipelining and and parallel proc	par essi	allel ing on
		UNIT - V			8 Hrs
Communication Signal Processin	n, Multimedia ng etc.		3		
After going thro	ugh this course	the student will be able to:			
CO1	: Analyze DSP a	rchitectures and CMOS technologies.			
CO2	: Apply pipelini	ng, parallel processing and retiming in DSP.			
CO3	: Design pipelin	ed and parallel recursive adaptive filters.			
CO4	: Develop applic	cations using general purpose digital signal	processors.		
Reference Boo	ks				
1. Keshab K. Pa Edition, ISBN: 8	rthi , "VLSI Digi 31-265-1098-6	tal Signal Processing Systems :Design and in	mplementation" V	Vile	y 1999, 3rd
2. Rulph chasse 2nd edition, ISBN: 9	eing, "Digital Sig 78-0470138663	nal Processing and Applications " with C671	3 and C6416 DS	K, V	Viley 2005,
3. Nasser Kehta Academic press	rnavaz, "Digital 2008, 2nd editi	Signal Processing System Design: Lab view on, ISBN: 978-0123744906.	based hybrid pro	grar	nming",
4. Naim Dahnor	un "Digital Signa	al Processing Implementation" Prentice Hall,	2000, ISBN: 978	-02	01619164



Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full

question from each unit.

RUBRIC for CIE			10 ×	RUBRIC for SEE		
SLNo	Content	Marks	Q. No	Contents	Marks	
1	Quizzes - Q1 & Q2	20	Each u	nit consists of TWO questions of 20 Marks each. Answ	wer FIVE	
2	Tests - T1 & T2	40		full questions selecting ONE from each unit [1 to 5].		
3	Experiential Learning - EL1 & EL2	40	182	Unit-1: Question 1 or 2	20	
	Total Marks	100	3&4	Unit-2: Question 3 or 4	20	
			586	Unit-3: Question 5 or 6	20	
			788	Unit-4: Question 7 or 8	20	
			9 & 10	Unit-5: Question 9 or 10	20	
				Total Marks	100	



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	SEMESTER: I			
Course Code : MVE301A4	Deal Wire a Druhe date d Oresta ma	CIE Marks	:	100
Credits L-T-P : 3-0-0	Real Time Embedded Systems	SEE Marks	:	100
Hours : 42L	Elective A (Professional Elective)	SEE Durations	:	3 Hrs
Faculty Coordinator:	Dr. Govinda Raju M	·		•
	UNIT - I			9 Hrs
Introduction: Overview, Archited	cture of Real Time Systems: Hardware and S	Software, Real Tir	ne Se	ervices.
System Resources: Resource An	alysis, Real Time Service Utility, Cyclic Exec	cutives, Timing C	onsti	raints and
Modelling of				
Timing Constraints, Application	s of Real Time System.			
	UNIT - II			9 Hrs
Processing: Scheduling Classes,	Scheduler Concepts, Pre-emptive Fixed Pri	ority Policy, Feas	ibility	y, Rate
Monotonic LUB, Necessary & Su	ifficient Feasibility, Dead Line Monotonic, D	ynamic Priority I	olicio	es. I/O
Resources: WCE1, Intermediate	I/O, Execution Efficiency.			0.11
	UNIT - III			8 Hrs
RTOS Services: Task Creation, I	nter Task Communication: Pipes, Message (Queues, Mail Box	, Mei	mory
Mapped Objects; Critical Section	n, Shared Data Problem, Synchronization: S	emaphores, Mut	ex; R	emote
Procedure and Sockets.	· Process Stack Management Dynamia Alla	action		
Real Time Memory Management	LINIT - IV	cation		8 Hrs
Handling Deserves Sharing and	Dependencies Among Deal Time Tealse Dea	ouros Charing or	2012	Deel
Handling Resource Sharing and	Dependencies Among Real-Inne Tasks Res	itanaa Drataaal (I	nong	Real-
Locker	Filolity Cennig Flotocol (FCF), Filolity Innel		-1F), I	ngnest
Protocol (HLP). Types of Priority	Inversion Under PCP, Racing, Deadlock, Liv	ve lock. Starvatio	n.	
	UNIT - V			8 Hrs
Examples of Real Time OS: VxW	orks: Task Management, Scheduling, Primi	tive Kernel Servio	ces, A	pplication
Program development using API	s, Introduction to AI for scheduling			
140				
Course Outcomes:	1 N N N N			
After going through this course	the student will be able to:	1.1		
CO1 : Aquire the con	acepts of real-time system and real-time ope	rating system.		
CO2 : Analyse the gi	ve <mark>n requir</mark> ements, design hardware <mark>& softw</mark> a	are for real time s	syster	ms.
CO3 : Apply tools for	[•] re <mark>al time f</mark> irm ware development & perform	ance analysis.		
CO4 : Design real tin	ne applications using RTOS to meet timing (Constraints.		
		S 12		
Reference Books				
1. Real-Time Embedded System	s and Components, Sam Siewert, 2007, Cer	ngage Learning In	idia E	Edition,
ISBN:				
9788131502532 2				
2. Real-Time Systems: Theory a:	nd Practice, Rajib Mall, 2007, Pearson, ISBN	N 978-81-317-00	69-3	
3. Real-Time Concepts for Embe	edded Systems, Qing Li and Carolyn Yao, 20	03 CMP Books,		
ISBN:1578201241				
4. Technical Reference Manuals	: VxWorks, Posix.			



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			SEMESTER: I			
Course Code	:	MVE301A5		CIE Marks	:	100
Credits L-T-P	:	3-0-0	Semiconductor Device Modelling	SEE Marks	:	100
Hours	:	42L	Elective A (Professional Elective)	SEE Durations	:	3 Hrs
Facu	ltv	v Coordinator:	Dr. Ramavenkateswaran N	1		
			UNIT - I			9 Hrs
Charge Carrier	rs	and Transport	t Modelling			
Crystal Structu	ire	, Semiconduct	or Models, Carrier Properties, State and Carri	er Distributions,	Εqι	uilibrium
Carrier Concen	tr	ations, Drift, D	iffusion, Recombination-Generation, Equatior	ns of State, Mode	lling	g &
Simulation exa	m	ples.				
			UNIT - II			9 Hrs
PN Junction D	ic	des:pn Junctio	on Electrostatics, Preliminaries, Quantitative I	Electrostatic Rela	atior	nships, I-V
Characteristics	,1	The Ideal Diode	Equation, Deviations from the Ideal, Small-S	ignal Admittance	, Re	everse-
Bias Junction (Са	pacitance, For	ward-Bias Diffusion Admittance, MS Contacts	and Schottky D	iode	es, Solar
cells and						
LEDs.						
			UNIT - III	6		8 Hrs
BJT: Electrosta	ati	cs, Performanc	e Parameters, Ideal Transistor Analysis, Gene	ral Solution, Sin	ıplif	ïed
Relationships,	Eł	pers-Moll Equa	tions and Model, Deviations from the Ideal, M	odern BJT Struc	ture	es.
			UNIT - IV	<u> </u>		8 Hrs
MOS: Electrost	at	ics, Capacitanc	ce-Voltage Characteristics, Quantitative ID/VI	O Relationships,	Squ	are-
Law Theory, Bu	111	c-Charge Theor	y, a.c. Response, Small-Signal Equivalent Circ	cuits, Cutoff Free	quer	ncy,
Small-Signal						
Characteristics		1.00				
			UNIT - V			8 Hrs
Emerging elec	tr	on devices (Qu	alitative approach): Introduction, HEMT, HI	BT, Fin-FET. Nar	10W1	re-FET,
quantum and r	nc	neculal devices	, energy storage and narvesting Electronics de	evices		
		in the second		100 C		
After going three	ne	es:	the student will be able to:			
	Ju I.	Annin course	ductor models to excluse corrier densities on	d		
C01	•	Apply semicon	ductor models to analyse carrier densities and		πι.	
C02	:	Analyse basic	governing equations to analyse semiconducto	r devices.	1	•
C03	:	Design the p-r	i junction, Schottky barrier diodes and emerg	ing semiconduct	or a	evices.
CO4	:	Model & Simu	late microelectronic devices using software to	ols.		
				1		
Reference Boo	k	5				
1. Robert F. Pie	err	et, "Semicondu	actor Device Fundamentals", Pearson, 2006, Is	SBN 9780201543	3933	3.
2. Y.P. Tsividis,	, C	Colin McAndrew	v, "Operation and modelling of the MOS Trans	itor", 3rd Editior	1, 20	014,
Oxford		050 01051501				
Univ Press, ISE		<u>:978-01951701</u>	153.	00100 1	• 1	
3. Iuan Iaur, 1	ıa	к н. ning, "Fur	idamentals of Modern VLSI Devices", 2ndediti	on, 2013Cambr	iage	
Press ISRN- 07	78	-1107635715				
4 Semiconduct	to	r Simulation To	ools "https://papohilb.org/groups/semicond	uctors"		
	.0.		solo, https://hanonab.org/groups/sellicolia	401010		



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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions

with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full question from each unit.

2	RUBRIC for CIE		10	RUBRIC for SEE	
SLNo	Content	Marks	Q. No	Contents	Marks
1	Quizzes - Q1 & Q2	20	Each u	mit consists of TWO questions of 20 Marks each. Anav	or FIVE
2	Tests - T1 & T2	40		full questions selecting ONE from each unit [1 to 5].	
3	Experiential Learning - EL1 & EL2	40	182	Unit-1: Question 1 or 2	20
	Total Marks	100	384	Unit-2: Question 3 or 4	20
			586	Unit-3: Question 5 or 6	20
			788	Unit-4: Question 7 or 8	20
			9 & 10	Unit-5: Question 9 or 10	20
				Total Marks	100



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		SEMESTER: I			
Course Code	: MVE302B1	Static Timing Analysis	CIE Marks	:	100
Credits L-T-P	: 3-0-0		SEE Marks	:	100
Hours	: 42L	Elective B (Professional Elective)	SEE Durations	:	3 Hrs
Facu	lty Coordinator:	Dr. Shylashree N			
		UNIT - I			9 Hrs
Introduction: B	asics of timing c	oncepts- Propagation delay, slew, timing arc	s,min and max tir	ning p	oaths,
clock domains.	Delay Concepts	for Digital Designing: Types of Delays in Dig	gital Circuits, Diffe	rent (Cause
for Delay Timin	g parameters of o	ligital circuits: Timing Parameters for Comb	inational Logic Ga	tes, T	iming
Parameters for	Sequential Circu	its, Concept of Delay Path in a Design, Cloc	k Concepts		
the timing anal	vsis point-to-po	an groups, modeling of external attributes,	virtual clocks, rel	ining	
	<i>yons, point to po</i>	IINIT - II			9 Hrs
Resources for S	Static Timing Ang	lysis Flow I ibraries Netlist Parasitics for De	law Calculation.D	evice	7 1113
Parasitics Inte	rconnects Paras	itic Extraction Formats linear v/s non-line	ar delay model	CVICC	
Clock Network	Optimization:Me	trics, clock skew-scheduling handling variat	oility. Parallel Tim	ing	
Optimization:C	ircuit partitionin	g for independent timing regions.		8	
Post-Silicon Tir	ning Validation:I	ntroduction, sources of post-silicon timing fa	ilure, post-silicor	ı tuni	ng
		UNIT - III			8 Hrs
Concepts of No Crosstalk Noise Analysis,Strate Cross talk Prev	ise and Crosstall e or Glitch, Types gy of Crosstalk o ention Methods	a for static timing Analysis: Coupling Capaci of Crosstalk Delta Delay, Noise Libraries, C n Nanometre Design: Cause for Crosstalk or	tance Concept, Ty crosstalk Effect on n Integrated Circu	rpe of Timin its,	ng
	1 200	UNIT - IV	100		8 Hrs
Constraints for Exceptions:Mu	STA:Clock Cons lticycle Path, Fal	traints, Other Timing Constraints, 5.2.2 Ext se Path, Clock Grouping, Case Analysis, Dis	ernal Delays of D able Timing, Path	UA,Ti with	ming Derate
	1. E.	UNIT - V			8 Hrs
Timing Violatio Multicycle Path Violation Check Domain,Crosst Violations,Tech	ns and Verification, Half Cycle Path , Input/output 7 alk Checks,Tech niques to Fix Ho	on:Slack, Critical Path of Timing Report, Set I, Timing Checks for Asynchronous Timing F Fiming Path Checks ,DRC Violation Check, M niques to Fix Timing Violation:Techniques to Id Violations,Time borrowing.	up Violation, Hold Paths, Recovery an Multi Speed Clock o Fix Setup	l Viola d Rer	ation, noval
	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1				
Course Outcor	nes:				
After going thro	ough this course	the student will be able to:			
CO1	: Apply the basi generated repo the techniques make the desi	c concepts of STA to evaluate the delay of th ort to identify critical issues and bottle neck s to gn to meet timing.	e circuit and anal for the violation a	yze tł nd su	ie iggest
CO2	: Identify cell de information to	elays from a library and calculate output slev calculate net delays. Also analyze cross talk	w degradation and c effect on timing a	l use ⁻ analys	wire-load sis.
CO3	: Write the own and its specification to	constraints file and create the environment	required for the g	iven d	lesign
CO4	: Set timing con timing problem	straints, including clocks and external delay ns.	y and analyze repo	ort to	identify
Reference Boo	ks				

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1. Static Timing Analysis for Nanometer Designs: A Practical Approach, J.Bhasker, R.Chadha, 2009, Springer,

ISBN:978-0-387-93820-2.

2. Static Timing Analysis for VLSI circuits, R.Jayagowri, Pushpendra S.Yadav,2018, MEDTECH, A Division of Scientific International, ISBN: 978-9-38-721006-6.

3. Timing Analysis and Optimization of Sequential Circuits, Naresh Maheshwari and Sachin S.Sapatnekar, 1999, Springer Science, Business Media, LLC, Library of Congress Cataloging-in-Publication Data, ISBN:978-1-4615-5637-4

4. Constraining Designs for Synthesis and Timing Analysis - A Practical Guide to Synopsys Design Constraints (SDC), Sridhar Gangadharan and Sanjay Churiwala, Springer Science, Business Media, LLC, Library of

Congress Cataloging-in-PublicationData, 2013, ISBN: 978-1-4614-3269-2

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full

question from each unit.

	RUBRIC fo	r CIE		1	RUBRIC for SEE	
SL.No	Content	1	Marks	Q. No	Contents	Marks
1	Quizzes - Q1 & Q2		20	Each u	mit consists of TWO questions of 20 Marka each. Answ	er FIVE
2	Tests - TI & T2		40	CSN100/C	full questions selecting ONE from each unit (1 to 5).	10535588
3	Experiential Learning	- EL1 & EL2	40	182	Unit-1: Question 1 or 2	20
	·	Total Marks	100	384	Unit-2: Question 3 or 4	20
				586	Unit-3: Question 5 or 6	20
				788	Unit-4: Question 7 or 8	20
				9 & 10	Unit-5: Question 9 or 10	20
				1	Total Marka	100



		SEMESTER: I								
Course Code	: MVE302B2	System on Chip Design	CIE Marks	:	100					
Credits L-T-P	: 3-0-0		SEE Marks	:	100					
Hours	: 42L	Elective B (Professional Elective)	SEE Durations	:	3 Hrs					
Faculty Coordinator: Dr. Kiran V										
UNIT - I										
Review of Moor and performand in SoC design of Productivity gay issues and the	e's law and CMO ce. Comparison o cost reduction, po p ways to improve	S scaling, benefits of System On Chip integr on System on Board, System on Chip, and S ower reduction, design effort reduction, perfo the gap – IP based design and design reuse.	ation in terms of o ystem-in-Package ormance maximiza	cost, . Typ ation	power, pical goals 					
		UNIT - II			9 Hrs					
vs bottom up, S design issues, S timing closure, Hardware Accelerators in	Specification required Soft IP vs Hard II Logic design issues	airement, Types of Specification, System Des P, IP verification and Integration, Hardware-S ues, Verification strategy, On chip buses and	sign Process, Syste Software co design 1 interfaces, Low F	em le 1, De Powe	evel sign for r,					
		UNIT - III			8 Hrs					
Embedded Men Cache coherend	nories, cache me ce. MESI protoco	mories, flash memories, embedded DRAM. T l and Directory-based coherence.	opics related to ca	ache	memories.					
	1	UNIT - IV			8 Hrs					
Interconnect ar Mesh-based No	chitectures for S C. Routing in an	oC. Bus architecture and its limitations. Net NoC. Packet switching and wormhole routin	twork on Chip (NC g.	DC) t	opologies.					
	1.5	UNIT - V			8 Hrs					
MPSOCS: What, design, Perform Application Platform for LT Course Outcor After going three CO1 CO2 CO3 CO4	nes: bugh this course Learn about the curse the definition of the second sec	the student will be able to: the blocks in the system on chip design and i esign flow and verification of IPs used in syst concepts of different memory and interconne Develop the algorithms required for the des	ts performance. em on chip. ection methods in ign of IP and SoC	SoC	Exposure					
	the concept of	MPSoCs	/							
Reference Boo	ks		-							
1. SudeepPasri Morgan Kaufma 2. Rao R. Tumr	cha and NikilDu ann Publishers © nala, Madhavans	tt, "On-Chip Communication Architectures: 2008. Swaminathan, "Introduction to system on pa	System on Chip Ir	nterc rizat	tion of the					
3 James V Do	okol "Embedded	Systems: A Contemporary Design Tool" Wil	ev Student Edition	n						
4. Michael Keat Academic Publishers, 2nd	ting, Pierre Brica	ud, "Reuse Methodology Manual for System	on Chip designs",	Klu	wer					

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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full question from each unit.

RUBRIC for CIE			RUBRIC for BEE		
SLNo	Content	Marks	Q. No	Contents	Marks
1	Quizzes - Q1 & Q2	20	Each u	nit consists of TWO questions of 20 Marks each. Aney	ver FIVE
2	Tests - T1 & T2	40		full questions selecting ONE from each unit (1 to 5).	
3	Experiential Learning - EL1 & EL2	40	182	Unit-1: Question 1 or 2	20
	Total Marica	100	384	Unit-2: Question 3 or 4	20
			586	Unit-3: Question 5 or 6	20
			748	Unit-4: Question 7 or 8	20
			9 & 10	Unit-5: Question 9 or 10	20
				Total Marks	100



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			SEMESTER: I					
Course Code	:	MVE302B3	IC Technology	CIE Marks	:	100		
Credits L-T-P	:	3-0-0		SEE Marks	:	100		
Hours	:	42L	Elective B (Professional Elective) SEE Durations			3 Hrs		
Facu	ılty	y Coordinator:	Dr. Ramavenkateswaran N					
			UNIT - I			9 Hrs		
An Introduction	n 1	to Microelectron	nic Fabrication: Semiconductor Substrates,	Crystallography and				
Crystal Structu Growth, Wafer	ire	e, Crystal Defec	ts, Czochralski Growth, Bridgman Growth o	f GaAs, Float Zone				
Preparation an	d	Specifications						
			UNIT - II			9 Hrs		
Hot Processing Models of Diffu Analysis of Diff Profiles, Diffusi	ar Isi fus ioi	nd Ion Implanta on, Analytic So sed n in SiO2, Simu	tion: Diffusion, Fick's Diffusion Equation in lutions of Fick's Law, Diffusion Coefficients : ilations of Diffusion Profiles	One Dimension, Ato for Common Dopants	mis 8,	stic		
			UNIT - III			8 Hrs		
Thermal Oxida Initial Oxidatio Oxidation and PolysiliconOxid Oxidations	tic n lat	on: The Deal–Gi Regime, The St tion, Silicon Ox	rove Model of Oxidation, The Linear and Par- ructure of SiO2, Oxide Characterization, The ynitrides, Alternative Gate Insulators, Oxida	abolic Rate Coefficier e Effects of Dopants I tion Systems, Numer	nts, Du ric	The ring		
UNIT - IV 8 H								
Channeling and Dielectrics, Ion Implantation S	d I ys	tems: Problems	and Concerns, Numerical Implanted Profile	nction Formation, Bu	irie	, d		
			UNIT - V			8 Hrs		
Methods, Cond Contacts,Conta Resistance, Me		ctivity Type,Con t surement Techr	htact Resistance and Schottky Barriers, Meta	of Methods				
Course Outcon	me	es:						
After going three CO1	ou :	gh this course Aquire the con	the student will be able to: cepts of fabrication process and characteriz	ation techniques of I	С			
		technology.						
C02	CO2 : Analysis of different process parameters in IC fabrications.							
C03	:	Evoluate differ	and standard operating procedure in iC labrication proce					
04	ŀ	Evaluate unier	ent analytic techniques in fabrication proces	55.				
Reference Boo	k	s						
1. Stephen A. C of	Ca	mpbell, "Fabric	ation Engineering at the Micro and Nanosca	le", Third Edition, U	niv	ersity		
Minnesota, Oxf	foi	d University Pr	ess, 2008.		-			
2. Dieter K. Scl	nr	oder, "Semicon	auctor Material and Device Characterization	, wiley - IEEE, 2006). ~~~			
University	1a	к п. Ning, "Fui	idamentais of Modern VLSI Devices, 2nded	luon, 2013 Cambrid	ge			
Fress, ISBN: 97	١ð	-110/035/15.						



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4. Richard Jaeger, "Introduction to Microelectronic Fabrication": Volume 5, Modular Series on Solid State Deviced, 13 November 2001.

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the

problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full

question from each unit.

3	RUBRIC for CIE			RUBRIC for SEE	
SLNo	Content	Marks	Q. No	Contents	Marks
1	Quizzes - Q1 & Q2	20	Each u	nit consists of TWO questions of 20 Marks each. Answ	er FIVE
2	Tests - T1 & T2	40		full questions selecting ONE from each unit [1 to 5].	
3	Experiential Learning - EL1 & EL2	40	1&2	Unit-1: Question 1 or 2	20
	Total Marka	100	384	Unit-2: Question 3 or 4	20
	5		586	Unit-3: Question 5 or 6	20
			788	Unit-4: Question 7 or 8	20
			9 & 10	Unit-5: Question 9 or 10	20
				Total Marks	100



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		SEMESTER: I							
Course Code	arse Code : MVE302B4 IOT System Design and Architecture CIE Marks								
Credits L-T-P	: 3-0-0		SEE Marks	:	100				
Hours	: 42L	Elective B (Professional Elective) SEE Durations							
Faculty Coordinator: Dr. Govinda Raju M									
		UNIT - I			9 Hrs				
solution, IoT us blocks of IoT- C architecture, Aj IoT Communication MQTT, CoAP, L	communication and s communication a pplications and s ation Architectur n models for IoT, oRaWAN, RTLS,	ent - Need and goals, IoT Architecture reference nd security Model, Service oriented architectur tandards. e and Protocols 6LoWPAN, IPv4/IPv6, IoT communication proto RPL, Communication APIs	e model, Function e, Event-driven	nal					
		UNIT - II			9 Hrs				
IoT Security an IoT risks and se access through Authentication	d Privacy ecurity challenge security groups /Authorization m	s, IoT security architecture - A trust model, Res Specific user access control, Data confidential nethods, Block chain for IoT security and privac	stricting network ity and availabili yy.	ty,	User				
		UNIT - III			8 Hrs				
Big Data analyt and framework Data Analytics warehousing, V Data based dec services. Edge interfaces, Prot Raspberry pi, A packages for ec security, Real t	in Cloud Layered 'irtualization for 'isions, Cloud da Computing Intro- ocol and standar IRM Cortex Proce lge computing, E ime applications	UNIT - IV I cloud architecture for data analytics, Elasticit Data-center automation, Real-time cloud data a ta lake, Exploratory data analysis, Open source duction to Edge/Fog computing, Edge nodes an ds for edge devices, IoT edge architecture, IoT s essors, Software Platforms for IoT Edge - Raspb dge of edge computing.	y in cloud for da analytics tools, A c cloud platforms ad gateway, Node supported hardw ian Pi OS, RIOT,	ta I S are to are Py	8 Hrs ervices- ad edge thon				
UNIT - V									
IoT Architectur Health care, Au IoT architectur societal requirements.	e: Use Cases Roa atomotive applica e for Home autor	Idmap for complete IoT solution, Open source I tions, Smart IoT architecture for Retail, Logistic nation, Industry applications, Smart city and o	oT platforms, IoT cs and Farming, ther applications	` sc Int to	olution to elligent cater the				
Course Outcor	nes:								
After going thro	ough this course	the student will be able to:							
CO1	: Assimilate the architecture.	technologies that enable IoT and interpret the	different compor	nen	ts in IoT				
CO2	: Envision the I effective design	oT communication architecture models and the n of IoT applications on different platforms.	protocol stack fo	or 1	the cost-				
CO3	: Analyze cloud intelligent.	platform services to perform IoT data analytics	and make the sy	yste	em				
CO4	: Perceive the d	ata analytics tools and gain knowledge to devise	e an intelligent Io	oT :	system.				



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Reference Books

Internet of Things- A hands-on approach, Arshdeep Bahga, Vijay Madisetti, Universities Press, 2015.
 Cloud Computing Security: Foundations and Challenges, John R. Vacca, CRC Press, 2016.

3. Internet of Things and Big Data Analytics towards Next-Generation Intelligence, Dey, Hassanien, Bhatt, Ashour and Satapathy, Springer, 2018.

4. Designing the Internet of Things, Adrian McEwen & Hakim Cassimally, Wiley, 2013.

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical

implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based

seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full

question from each unit.

RUBRIC for CIE				RUBRIC for SEE					
SLNo	Content		Marks	Q. No	Contents	Marks			
1 Quizzes - Q1 & Q2			20	Each unit consists of TWO questions of 20 Marks each. Answer F					
2	Tests - T1 & T2		40		full questions selecting ONE from each unit [1	to 5).			
3	Experiential Learning	EL1 & EL2	40	182	Unit-1: Question 1 or 2	20			
		Total Marka	100	3&4	Unit-2: Question 3 or 4	20			
				546	Unit-3: Question 5 or 6	20			
				7&8	Unit-4: Question 7 or 8	20			
				9 & 10	Unit-5: Question 9 or 10	20			
					Total	Marks 100			


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SEMESTER: I Course Code MVE302B5 CIE Marks 100 : **VLSI for Data Conversion Circuits** Credits L-T-P 3-0-0 SEE Marks 100 : Hours 42L Elective B (Professional Elective) **SEE** Durations : 3 Hrs Faculty Coordinator: Dr. Chinmaye R UNIT - I 9 Hrs Basic Sampling Circuits NMOS, PMOS and Transmission Gate switch, Distortion due to switch, Speed and Precision considerations, Charge injection, Clock feedthrough, Thermal noise in sample and holds, Charge injection cancellation - Dummy switch, complementary switches, differential circuits, Bottom plate sampling, Gate bootstrapped switch. UNIT - II 9 Hrs Building Blocks of Data Conversion Systems - Operational Amplifiers Two stage Opamp, design of buffer stage, Operational Transconductance Amplifier, compensating the Opamp for stability, characterizing the Opamp open loop gain, common mode range, common mode rejection ratio, power supply rejection ratio. CMOS Comparators: Regenerative latch, comparator metastability, Strong-ARM Latch Design UNIT - III 8 Hrs Switched Capacitor Amplifiers Common mode feedback (CMFB) - resistive CM detector, CMFB compensation, single- stage differential opamp. Switched Capacitor (SC) circuits- Parasitic Insensitive Switched Capacitor amplifiers, Non idealities in SC Amplifiers - Finite gain, DC offset, Gain-Bandwidth Product. Fully differential SC circuits, DC negative feedback in SC circuits. Switched-capacitor CMFB: design, analysis. UNIT - IV 8 Hrs Analog to Digital Converter- Static specifications: INL, DNL; Dynamic specifications: SNDR, DR, SFDR, linearity.Flash ADC, SAR ADC, Pipelined ADC, Sigma Delta ADC. UNIT - V 8 Hrs Digital to Analog Converter Static performance of DAC – DAC transfer characteristics, Ideal DAC transfer curve, offset, gain error, monotonicity, DNL and INL. Nyquist DAC architectures - Binaryweighted DAC, Unit- element (or thermometer-coded) DAC, Segmented DAC, Resistorstring, current-steering, Current cell design in current steering DAC, chargeredistribution DACs, High speed DACs. **Course Outcomes:** After going through this course the student will be able to: CO1 : Analyse and Design Sample and Hold circuits CO2 : Analyse Switched Capacitor Amplifiers and its non idealities. CO3 : Design various types of ADC/DAC for a given specification CO4 : Evaluate the different performance parameters of ADC/ DAC **Reference Books** 1. Behzad Razavi, "Principles of Data Conversion System Design" Wiley-IEEE Press, 1994 2. Fundamentals of Microelectronics, Behzad Razavi, 2nd Edition, 2013, Wiley, ISBN-10: 1118156323 3. Electronic Devices and Circuits, Jacob Millman, Christos C Halkias&Satyabrata Jit, 2nd edition, 2008, Tata McGraw Hill publication,. ISBN: 0070634556 4. David A.Johns, Ken Martin, "Analog Integrated Circuit Design" John Wiley & amp; Sons Inc. 1997



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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full

question from each unit.

RUBRIC for CIK				RUBRIC for SI	CF		
SLNo	Content		Marks	Q. No	Contents		Marks
1	Quizzea - Q1 & Q2		20	Each u	nit consists of TWO questions of 2	0 Marks each. Answ	er FIVE
2	Teats - TI & T2		40		full questions selecting ONE from	n each unit (1 to 5).	C-Croubs
3	Experiential Learning -	ELI & EL2	40	182	Unit-1: Question 1 or 2		20
	· · · · · · · · · · · · · · · · · · ·	Total Marks	100	3&4	Unit-2: Question 3 or 4		20
				586	Unit-3: Question 5 or 6		20
				788	Unit-4: Question 7 or 8	0.1	20
				9 & 10	Unit-5: Question 9 or 10		20
				1		Total Marka	100



			SEMESTER: II				
Course Code	:	MIM431T	RESEARCH METHODOLOGY CIE Marks	:	100		
Credits L-T-P	:	3-0-0	SEE Marks	:	100		
Hours	:	42L	Common Course to all M.Tech Programs SEE Durations	; :	3 Hrs		
Facu	lty	v Coordinator:	Dr. Rajeswara Rao K V S				
			UNIT - I		8 Hrs		
Research Prob	leı	n: Problem So	lving – General Problem Solving, Logical Approach, Soft Syste	em			
Approach, Crea Research Prob	ati lei	ive Approach, ns – Approach	Group Problem Solving Techniques for Idea Generation. For es to Research Problem, Exploration for Problem Identification	nul m,	ation of		
Hypothesis	1 1		N.1 11				
Generation and	d	Formulation of	the problem.		O IIm		
Decemb Deci	~ 40	· Emperimente	UNIT - II		9 Hrs		
Research Desig	gn Do	: Experimenta	Design – Principles of Experiment, Laboratory Experiment,	r of	:		
Experiment an	ле А	Ouasi Experin	perimental Design, Action. Research, Validity and Reliability		- -1		
Research Des	.u ori	Intive Research	nents. Ex l'ost l'acto Research – Exploratory Research, filsto	100	11		
Field Studies	Si	irvev Research	Qualitative Research Methods				
i icia otaaico,		arvey Research	UNIT - III		8 Hrs		
Research Desig	σn	for Data Acqu	isition: Measurement Design – Primary types of Measurement	nt s	cales		
Validity and Re	-1i	ability Measur	ement Sample Design – Non-Probability Sampling Probabili	tv	iculco,		
Sampling, Data	a (Collection Proc	edures – Sources of secondary data. Primary data collection	<i>cj</i>			
methods. Valid	lit	v and	autos - 2011/000 01 000011442. j uuta, 1 111142 j uuta 0011001101				
Reliability of da	ata	a collection pro	ocedures.				
			UNIT - IV		9 Hrs		
Data Analysis:	E	xploratory D <mark>at</mark>	a Analysis, Statistical Estimation, Hypothesis Testing, Parar	net	ric		
Non-Parametri	<i>د</i> ′	Tests Multiple	Regression Factor Analysis Cluster Analysis				
	C		UNIT - V		8 Hrs		
Research Prop	08	al Purpose T	zpes Development of Proposal Evaluation of Research Propo	sa	1		
Report Writing	: F	Pre-writing con	sideration. Format of Reporting, Briefing, Best practices for	Jοι	urnal		
writing.		8					
Course Outco	m	es:					
After going th	rc	ough this cour	se th <mark>e student</mark> will be abl <mark>e to:</mark>				
CO1		Recognize the	principles and concepts of research types, data types and an	nal	ysis		
	:	procedures.					
CO2	:	Apply approprinciples.	riate method for data collection and analyze the data using s	tat	istical		
CO3	CO3 Express research output in a structured report as per the technical and ethical						
C.04	•	Develop a res	earch design for the given engineering and management prof	let	n		
	•	context.	caren debign for the given engineering and management pro-				
Reference Boo	ok	s:					
1. Krishnaswa	mi	i, K.N., Sivaku	mar, A. I. and Mathirajan, M., Management Research Metho	101	ogy,		
Integration of I	-ri	inciples, Metho	ods and Techniques, 17th Impression, Pearson India Educati	on			
Services Pvt. L	td	, 2018. ISBN: 1	978-81-7758-563-6				
2. William M. I	ζ.	Trochim, Jam	es P. Donnelly, The Research Methods Knowledge Base, 3rd	Edi	ition,		
Atomic			70 150000010				
Dog Publishing	s,	2006, ISBN: 9	/8-1592602919				



3. Kothari C.R., Research Methodology Methods and Techniques, 4th Edition, New Age International Publishers, 2019, ISBN: 978-93-86649-22-5.

4. Levin, R.I. and Rubin, D.S., Statistics for Management, 8th Edition, Pearson Education: New Delhi, 2017, ISBN-13- 978-8184957495.

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks. **TESTS:** Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based

seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to

answer one full question from each unit.

RUBRIC for CIE			-	RUBRIC for SEE	
SLNo Content Marks			Q. No	Contents	Marks
1	Quizzes - Q1 & Q2	20	Each u	nit consists of TWO questions of 20 Marks each. Answ	er FIVE
2	Tests - Tl & T2	40		full questions selecting ONE from each unit (1 to 5).	
3	Experiential Learning - EL1 & EL2	40	1&2	Unit-1: Question 1 or 2	20
	Total Marks	100	3&4	Unit-2: Question 3 or 4	20
1		90 - XCAU	546	Unit-3: Question 5 or 6	20
			788	Unit-4: Question 7 or 8	20
			9 & 10	Unit-5: Question 9 or 10	20
				Total Marks	100



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ļ	i	SEMESTER: II	i		·
Course Code	MVE331I	Analog IC Design	CIE Marks	:	100
Credits L-T-P	: 3-0-1		SEE Marks	:	100
Hours	: 42L + 28P	Theory & Practice - (Professional Core - 3)	SEE Durations	:	3 Hrs
Facul	ty Coordinator:	Dr.Shylashree N			
		UNIT - I			9 Hrs
MOS transistors fT,noisemodel. S analysis of comr of circuits, Frequ Cascode. Curre currents.	: Components a Single stage Amp non source and uency response nt Mirror: Basic	available in a CMOS process, MOS small signal olifiers: Basic concepts, dc analysis, small signal common gate stage, power, bandwidth, impeda of CS amplifier, Cascode stage-Folded c Current Mirrors, Cascode current Mirrors, am	models, concept I analysis and n ance and frequen plifiers biased at	of oise icy s con	caling stant
		UNIT - II			9 Hrs
Differential Amp with active loads Operational Amp opamp frequence Two stage opamp-topology	olifiers: Single er s, Gilbert cell plifier:One stage cy response, Fol , frequency resp	nded and differential operation, Common mode e op-amp,two stage op-amp,Telescopic Cascode lded Cascode op-amp-dc gain, Telescopic and fo ponse, gain boosting, common mode feedback.	response, differe opamp,Telescop Ided Cascode op	ic Ca amp	l pair ascode 9, PSRR,
		UNIT - III			8 Hrs
Noise:Resistors, CGstage Feedba mechanisms, fee	MOSFET,Inputa ck:Non-idealitie edback topologie	andoutputreferrednoise,basicamplifierstages– C s-finite dc gain,effect of additional poles & zero es, Effect of loading.	Sand s,sense and retu	rn	
	1.5	UNIT - IV			8 Hrs
the Nyquist Crit Compensation–I current and con generators, redu Analog Filters: C sallen and key fi Phase Locked Lo	erion. Frequenc Domin ant pole, stant gm bias <u>ucing supply sen</u> Classification of ilters, KHN biqu	y Compensation: Concepts and Techniques for Miller Compensation Band gap reference: Band asitivity Low drop out regulators: Basic requires UNI T - V filters, transfer function of filters, Second order ad. ase locked loop, Charge pump PLL, Non-ideal e	Frequency I gap reference, o ments and const filters, active filters	Cons rain ters	stant ts 8 Hrs
Phase noise.App	lications	lase iseked loop, charge pullip 122, non lacar (uncerts officer to		
		LABORATORY	1	2	8 Hrs
 Studyof DCar Design of MO Design of sing Design of a MO Design of a ca Design of a ca Design of Tele Design of Tele Design of Bar Post-layout si 	ndsmallsignalmo S current source gle stage amplifi OS Differential a ascode amplifier escopic opamp tageCMOSOp-A nd GapReference mulation of any	odelsof aMOSTransistor ees and mirrors ers-CS Amplifier with different loads amplifier with an active load c, double cascode and triple cascode amplifier amp e circuit c two circuits			
Course OutcomAfter going throuCO1CO2CO3	agh this course Apply the know Analyze the fu Design and im	the student will be able to: wledge of MOSFET based discrete amplifier to in nctionality of analog circuit and systems. plement analog integrated circuits.	nvestigate variou	ıs de	signs.



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CO4 : Evaluate the different performance parameter of analog integrated circuits.

Reference Books

1. Design of Analog CMOS Integrated Circuits, Behzad Razavi, McGraw Hill Edition, 2002, ISBN:0-07-238032-2

2. CMOS Circuit Design, Layout and Simulation, R.Jacob Baker, Harry W. Liand David E.Boyce, IEEE Press, 2002, ISBN:81-203-1682-7

3. Analysis and design of Analog Integrated Circuits, Gray, Hurst, Lewis, and Meyer: 4thEdition, John Wiley &Sons, ISBN-10:0470245999

4. CMOS Analog Circuit Design, Phillip E. Allen and Douglas R. Holberg, 2ndEdition Oxford University Press, February 2002, ISBN:9780199765072

Scheme of Continuous Internal Evaluation (CIE): 10 + 30 + 30 + 30 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The average of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 30 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (10), Video based seminar

/presentation /demonstration (20) adding upto 30 marks.

Laboratory: Conduction of laboratory exercises, Lab report & observation & analysis (30 Marks), Lab Test (10 Marks) & Innovative Experiment/Concept Design & Implementation (10 Marks) adding up to 50 Marks. The final marks will be reduced to 30 Marks.

Scheme of Semester End Examination (SEE) for 100 marks: Each unit consists of TWO Questions of 16 Marks each. Answer FIVE full questions selecting one from each unit (from 1 to 5). Question No. 11 is compulsory (Laboratory component) for 20 Marks.

_	RUBRIC of CIE			RUBRIC of SEE			
SLNo	Content	Marks	Q. No	Contents	Mari		
1	Quizzes - Q1 & Q2	10	Each unit consists of TWO questions of 16 Marks each. Ans				
2	Tests - T1 & T2	30	full questions selecting ONE from each unit [1 to 5]. Question No. 11 is compulsory (Laboratory component) for 20				
3	Experiential Learning - EL1 & EL2	30	182	Unit-1: Question 1 or 2	16		
4	Laboratory	30	3 & 4	Unit-2: Question 3 or 4	16		
i .	Total Marks	100	5&6	Unit-3: Question 5 or 6	16		
1		1.00 S-1.000	78.8	Unit-4: Question 7 or 8	16		
	NO CEP Carl alamatan		9 & 10	Unit-5: Question 9 or 10	16		
	NO SEE for Laboratory			Laboratory Component (Compulsory)	20		
				Total Marks	1		



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SEMESTER: II								
Course Code : MVE332T	System Verilog for Design and Verification	CIE Marks	:	100				
Credits L-T-P : 3-0-0		SEE Marks	:	100				
Hours : 42 L	(Professional Core - 4)	SEE Durations	:	3 Hrs				
Faculty Coordinator:	Dr. Chinmaye R							
	UNIT - I			9 Hrs				
Introduction to SystemVerilog as key enhancements for hardware data types, System Verilog data Bit, byte, shortint, int, longint; 4 real, realtime. Enumerated data Type Conversion: Dynamic casti Multidimensional Arrays, Packed Verilog Tasks and Functions, En	s a Verification Lamguage(HDVL): SystemVerilog s design. Advantages of System Verilog over Verilog types, integer type and Non-integer type. Integer - State data types, reg, logic, integer. Non-Integer types, User Defined data types, Struct data types ng, Static Casting, Strings, Memories: Arrays, Dyn d Arrays, Associative Arrays, Queues, Array Metho hancements in S.V, Void Functions, Return State	tandards, Syster g, Data Types: Vo Type: 2 - State D r Type: time, sho , Interfaces, Pac namic Arrays, ods, Tasks and F ement, Passing	mVo erilo ata ortro kag	erilog og types, eal, ges, ctions:				
Arguments, Arguments Passing	by Name,	_						
Default Arguments, Passing Arg	uments by value, Passing Arguments by Reference	e.		0.11=0				
Treathan alt lead line and Oran and	UNII - II			9 HIS				
signals, SystemVerilog interfaces, SystemVerilog port connections, Interface instantiation 2.4. Interfaces Arguments, Interface Modports, Interface References, Tasks and functions in interface, Verilog Event Scheduler, SystemVerilog Event Scheduler, Clocking Block, Input and Output Skews, Typical Testbench Environment, Verification plan.								
	UNIT - III	2		8 Hrs				
Communication: OOP Concepts Overview of Classes, Properties a Null Object handles, Accessing M Assignments, Copying an Object Inheritance: Concept of Inheritan \$cast, Virtual Classes, Paramete Random Variables - rand and ra the class, Rand_mode and const Membership, Distribution Const Constraints. Threads and Inter-process Comm Threads, Fork-Join/Join_any/Jo	and Methods in the Classes, Instance/Object Crea Members, this Keyword, Creating an Object, Object Shallow Copy, Deep Copy. Ince, Super Keyword, Static properties, Overriding erized Classes. Constrained Randomization Indc, Randomize() Method - Pre/Post Randomize(raint_mode, Constraint and Inheritance, Constrain raints, Conditional Constraints implication (->) nunication pin_none, Communication –BuildingaTestbenchwi	ation, New Const ets Methods, Polym) methods, Cons int Overriding, S),. if/else, Inline ithThreadsandIF	orp orp stra et	etor, ohism - ints in				
	UNIT - IV			8 Hrs				
Universal Verification Methodology and Formal Verification Introduction to Open Verification Methodology and Universal Verification Methodology, Overview of OVM, UVM Base Classes and Simulation Phases in OVM and UVM macros. Environment structure of OVM and UVM, Connecting DUT and Testbench. Introduction to Formal verification andTypes of Formal techniques, Formal equivalence checking and Formal property checking, Class based Verification.								
	UNIT - V			8 Hrs				
Functional Coverage andAssertic Coverage Definition, Code Cover Coverpoints, Bins implicit bin Intersect, Select Expressions, Co Covergroup Built-in MethodsSa .get_instance_coverage(), .set_ins Introduction, Types of Assertions	on Based Verification: Functional Coverage age, Functional Coverage: Cover Group, Creating as, . Explicit bins, Bin creation, Vector and Scalar onditional Expression (iff), Illegal bins, Ignore bins ample(), .get_coverage(), stance_name(string), .start(), . stop() Assertion Bas s Immediate, . Concurrent, Assertion Properties	Cover Group Ins bins, Cross proc , Coverage Analy sed Verification s Writing Prop	tan luc ysis	ices, ts, ,				



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Sequences - .

Sequence Composition, . and, or, intersect, Advanced SVA Features - . Expect, Binding, Assertion Coverage

Course Outcomes:
After going through this course the student will be able to:
CO1 : Demonstrate the use SystemVerilog data types for digital system design and functional verification.
CO2 : Demonstrate the skill on writing test-benches for design digital systems and connecting them with the design.

CO3	Verify and Analyze the complete systems through robust verification method such as assertion based verification and class based verification.	
CO4	Design and verify the digital systems such as FIFOs, memories, ATM interfaces, etc. using the learnt methods and demonstrate the skills.	

Reference Books

1. C Spear, "SystemVerilog for Verification-A Guide to Learning the Testbench Language Features," Springer Science, IEEE press, ISBN-13: 978-0387-2703-64, 2006.

2. Stuart Sutherland, Simon Davidmann and Peter Flake, "SystemVerilog for Design - A Guide to Using SystemVerilog for Hardware Design and Modeling," 2E, Springer Science, ISBN-13: 978-0387-3339-91, 2006.

3. IEEE Computer Society, "IEEE Standard for SystemVerilog-Unified Hardware Design, Specification and Verification," IEEE Press, ISBN: 978-0-7381-6129-7, 2009

4. Doulos, "SystemVerilog golden reference guide-A concise guide to SystemVerilog IEEE Standard-1800-2009," Version 5.0, ISBN: 0-9547345-9-9, 2012.

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

RUBRIC for CIE				RUBRIC for SEE			
SI.No	Content	Marks	Q. No	Contents	Marks		
1	Quizzes - Q1 & Q2	20	Each u	ach unit consists of TWO questions of 20 Marks each. Answer FIVE full questions selecting ONE from each unit (1 to 5).			
2	Tests - T1 & T2	40					
3	Experiential Learning - EL1 & EL2	40	18:2	Unit-1: Question 1 or 2	20		
	Total Marka	100	384	Unit-2: Question 3 or 4	20		
	NO.3		586	Unit 3: Question 5 or 6	20		
			78.8	Unit-1: Question 7 or 8	20		
			9 & 10	Unit-5: Question 9 or 10	20		
				Total Marks	100		



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		SEMESTER: II		
Course Code	: MCS333C1	Development of Modem SoCs for Wireless, Wireline and IOT Applications	CIE Marks	: 100
Credits L-T-P	: 3-0-0	whenne and for Applications	SEE Marks	: 100
Hours	: 42 L	Elective C (Professional Elective)	SEE Durations	: 3 Hrs
Facu	alty Coordinator:	Dr. S Ravishankar		
		UNIT - I		9 Hrs
Algorithms for Applications, S	single carrier cor Single carrierChar	nmunications and Multicarrier Communication mo nnel estimation for DSL , Wi-Fi and cellular standar	dems Algorithms for rds	r MIMO
		UNIT - II		9 Hrs
DSL standards hardware and	for Transreceive firmware, DSL st	r, Synchronization, Channel estimation, Mapping s andards for Testing	tandards to Modem	SoC
		UNIT - III		8 Hrs
802.11 standa hardware and	rds for Transrece firmware, 802.11	iver, Synchronization,Channel estimation, Mapping standards for Testing	g standards to Mode	em SoC
	,	UNIT - IV		8 Hrs
LTE standards Modem SoC ha	for Transreceiver ardware and firm	r, Synchronization,Channel estimation, Protocol Sta ware, LTE standards for Testing	acks Mapping stand	ards to
		UNIT - V		8 Hrs
Course Outcos	mes: ough this course	the student will be able to:	Institutes for DOL	
COI	: Aquire the cor LTE.	acepts of synchronization and channel estimation a	Igorithms for DSL, V	WiFi and
CO2	: Associate the monitoring alg	standards sections to Training, Initialization and sh porithms	now time with in-ser	vice
CO3	: Analyse typica implement alg	l SoC platforms in terms of their hardware and sof orithms with task scheduling.	tware capabilities to)
CO4	: Develop runtin typical SoCs.	ne code to evaluate performance of a training, Initia	alization and showti	ime on the
Reference Boo	oks		· · · · · · · · · · · · · · · · · · ·	
1. ITU-T TELE	COMMUNICATIO	N STANDARDIZATION SECTOR , "Asymmetric digit	al subscriber line	
0 IFFF Stand	and for Informatic	, April 2007.	- Evolunce hetwoor	Sustema
Local and Metr (MAC) and Phy	opolitan Area Ne sical Layer (PHY)	tworks— Specific Requirements Part 11: Wireless L Specifications, IEEE Std 802.11 [™] -2020	AN Medium Access	Control
3. European Te and reception	elecommunication (3GPP TS 38.104	ns Standards Institute (ETSI), " 5G; NR;Base Statio version 16.4.0 Release 16)", July 2020	n (BS) radio transm	ission
4. ADSL: Stand	lards, Implement	ation, and Architecture, by Charles K. Summers Cl	RC Press, CRC Pres	s LLC,

ISBN: 084939595x Pub Date: 06/21/99



Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

RUBRIC for CIE			RUBRIC for SEE					
SLNo	Content	Marks	Q. No	Contents	Marks			
1	Quizzes - Q1 & Q2	20	Each u	ach unit consists of TWO questions of 20 Marks each. Answ				
2	Tests - TI & T2	40		full questions selecting ONE from each unit [1 to 5].				
3	Experiential Learning - EL1 & EL2	40	1&2	Unit-1: Question 1 or 2	20			
	Total Marica	100	384	Unit-2: Question 3 or 4	20			
1			586	Unit-3: Question 5 or 6	20			
			748	Unit-4: Question 7 or 8	20			
			9 & 10	Unit-5: Question 9 or 10	20			
				Total Marks	100			



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		SEMESTER: II			
Course Code	: MVE333C2	VLSI Memory Chip Design	CIE Marks	:	100
Credits L-T-P	: 3-0-0		SEE Marks	:	100
Hours	: 42 L	Elective C (Professional Elective)	SEE Durations	s :	3 Hrs
Facı	ilty Coordinator:	Dr.Shylashree N			
		UNIT - I			9 Hrs
An Introductio General Trends Non-Volatile M Cycles, Read M Influence of Te	n to Memory Chij s in DRAM Design emory Design: M lode Architecture mperature and S	p Design: The Internal Organization of Memory C n and Technology, General Trends in SRAM Desig ain Features of Non-Volatile Memories, Program, , Write Mode Architecture, Erase Mode Architectu upply Voltage.	hips, Categories of M 3n and Technology. Erase, Distributions ure, Elements of Rel:	lem s an iabil	lory Chip, .d lity,
		UNIT - II			9 Hrs
DRAM Circuits Operation of th and Relevant O On-Chip Testin	: Introduction, The DRAM Chip, Finder DRAM Chip, Finder Chicago and Chicago an	he catalog Specifications of the Standard DRAM, undamental Chip Technologies, The Multidivided d Relevant Circuits, Refresh-Relevant Circuits, Re	The Basic Configura Data Line and Word edundancy Techniqu	tion Lir les,	n and ne, Read
		UNIT - III			8 Hrs
Low-Power Mei Sources of Pow Organization o Array of Sector	mory Circuits:Int ver Dissipation in f the Memory Arr rs, Other Types of	the RAM Chip, Low-Power DRAM Circuits, Low- ay:Introduction: EPROM Memories, Flash Memor	pation in a RAM Sub Power SRAM Circuit Ty Organization: The	osys s. Tl Sec	stem, he ctors,An
	1-5	UNIT - IV			8 Hrs
Memories, Era Voltage Device Negative Voltag Temperature D	se Algorithm, Tes s, Charge Pumps ges, Voltage Regu Dependence.	t Algorithms. Circuits Used in Program and Eras , Different Types of Charge Pumps, High Voltage lation Principles, Gate Voltage Regulation, Drain	e Operations:Introdu Limiter, Charge Pun Voltage Regulation	ictio ips : and	on, Dual for
	1.0	UNIT - V			8 Hrs
Program and E FSM, Microcon UPROM Cells,	Crase Controller:F Itroller. Redundar The First Read Ar	SM Controller, STD Cell Implementation of the F ncy and Error Correction Codes:Redundancy, Red fter Power On Reset, Error Correction Codes.	SM, PLA Implementa lundancy & Read Pa	ation ath,	n of the Yield,
Course Outco After going thr	mes: ough this course	the student will be able to:	6		
CO1	: Aquire the kno	owledge about memory chip design and its techno	ology		
CO2	: Explore variou	as design strategies to be followed for designing D	RAM circuits		
CO3	: Design and op	timize semiconductor memory cell for a given spe	ecification		
CO4	: Design memor	y array of a given size and measure various perfo	ormance metrics.		
Reference Boo	oks				
1. VLSI-Design ISBN-10:81812	of Non-Volatile M 288076, ISBN-13	Memories: G.Campardo, R.Micheloni and D.Novos : 978-8181288073	sel, 2007, Springer,		
2. VLSI Memor : 3642087361,	y Chip Design, K ISBN-13 : 978-3	iyooItoh, Soft cover reprint of hardcover 1st ed. 2 642087363	001 edition, Springe	er, Is	SBN-10
3. Embedded M original 1st ed.	Memory Design fo 2014 edition,Sp	r Multi-core and system on chip, Baker Mohamm ringer, ISBN-10 : 1493948016, ISBN-13 : 978-14	nad,Softcover reprint 93948017.	t of 1	the
4. Cache and M Kaufmann (30	Memory Hierarchy June 1990), ISBI	y Design: A Performance Directed Approach, Stev N-10 : 1558601368, ISBN-13 : 978-1558601369.	enPrzyblylski, Morga	an	



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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

RUBRIC for CIE			RUBRIC for SEE		
SLNo	Content	Marks	Q. No	Contents	Marks
1	Quizzes - Q1 & Q2	20	Each unit consists of TWO questions of 20 Marks each. Accever F		wer FIVE
2	Tests - T1 & T2	40		full questions selecting ONE from each unit (1 to 5).	
3	Experiential Learning - EL1 & EL2	40	1&2	Unit 1: Question 1 or 2	20
1	Total Marks	100	384	Unit 2: Question 3 or 4	20
			586	Unit-3: Question 5 or 6	20
			78.8	Unit-4: Question 7 or 8	20
			9 & 10	Unit-5: Question 9 or 10	20
				Total Marke	100



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SEMESTER: II MVE333C3 Course Code CIE Marks 100 **Robotics and Industrial Automation** Credits L-T-P : 3-0-0 SEE Marks 100 42 L Elective C (Professional Elective) **SEE** Durations Hours 3 Hrs • Faculty Coordinator: Dr. Abhay Deshpande UNIT - I 9 Hrs Introduction: Automation and Robotics, Historical Development, Definitions, Basic Structure of Robots, Robot Anatomy, Complete Classification of Robots, Fundamentals about Robot Technology, Factors related to use Robot Performance, Basic Robot Configurations and their Relative Merits and Demerits, the Wrist & Gripper Subassemblies. Kinematics of Robot Manipulator: Introduction, General Mathematical Preliminaries onVectors& Matrices, Direct Kinematics problem, Geometry Based Direct kinematics problem, Coordinate and vector transformation using matrices, Rotation matrix, Inverse Transformations, Problems. UNIT - II 9 Hrs Trajectory Planning: - Introduction, Trajectory Interpolators, Basic Structure of TrajectoryInterpolators, Cubic Joint Trajectories. General Design Consideration on Trajectories:- 4-3-4 & 3-5-3 Trajectories. (SLE: Admissible Motion Trajectories) Dynamics of Robotic Manipulators: Introduction,. Preliminary Definitions, GeneralizedRobotic Coordinates, Jacobian for a Two link Manipulator, Euler Equations, TheLagrangian Equations of motion. UNIT - III 8 Hrs Robot Sensing & Vision: Various Sensors and their Classification, Use of Sensors and SensorBased System in Robotics, Machine Vision System, Description, Sensing, Digitizing, Image Processing and Analysis and Application of Machine Vision System, Robotic Assembly Sensors and Intelligent Sensors. Industrial Applications: Objectives, Automation in Manufacturing, Robot Application inIndustry, Task Programming, Robot Intelligence and Task Planning, Modern Robots, Future Application and Challenges and Case Studies. (SLE: Goals of AI Research, AI Techniques) UNIT - IV 8 Hrs Modeling and control: Kinematic modeling of multi-link flexible robots, Dynamics and control of flexible link manipulators. Overview of PLC Hardware, numeric data handling, system addressing, and programming software. Robot Manipulator Control Using PLC with Position Based and Image Based Algorithm. Case Study. UNIT - V 8 Hrs Programmable Digital Signal Processor Introduction, Evaluation and important features of programmable VLSI-DSP processor, application of VLSI-DSP processor in the field of Wireless Communication, Multimedia Signal Processing etc. **Course Outcomes:** After going through this course the student will be able to: CO1 : Analyze the process Modeling hierarchies, theoretical and empirical models. CO2 : Apply different Feedback & feed forward control techniques for theoretical and empirical models. CO3 : Comprehend the Decoupling controller, Instrumentation for process monitoring and preparation of P&I diagrams CO4 : Develop Statistical process control, supervisory control, direct digital control, distributed control, PC based automation. **Reference Books** 1. Fu, Lee and Gonzalez, "Robotics, control vision and intelligence". McGraw Hill International, 2007,2nd edition, ISBN: 978-0071004213. 2. John J. Craig, "Introduction to Robotics"- Addison Wesley Publishing, 2010, 3rd edition, ISBN: 978-0201543612



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3. Ghosal A, "Fundamental concepts and Analysis", Oxford University Press2008, 2nd edition, ISBN: 978-0195673913

4. Sebastian Thrun, "Probabilistic Robotics", The MIT Press, 2005, 2nd edition, ISBN:978-0262201629

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

_	RUBRIC for CIE			RUBRIC for SEE		
SLNo	Content	Marks	Q. No	Contents	Marks	
1	Quizzes - Q1 & Q2	20	Each u	Each unit consists of TWO questions of 20 Marks each. Answer Fl		
2	Tests - T1 & T2	-40		full questions selecting ONE from each unit [1 to 5].		
з	Experiential Learning - EL1 & EL2	40	1&2	Unit-1: Question 1 or 2	20	
	Total Maria	100	3&4	Unit-2: Question 3 or 4	20	
	02		5&6	Unit-3: Question 5 or 6	20	
			788	Unit-4: Question 7 or 8	20	
			9 & 10	Unit-5: Question 9 or 10	20	
			-	Total Marks	100	



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			SEMESTER: II				
Course Code	: MVE333C	4 A u	Automotive Electronics		IE Marks	: 100)
Credits L-T-P	: 3-0-0			SI	EE Marks	: 100)
Hours	: 42 L	Electi	ve C (Professional Elective	e) SI	EE Durations	: 3 H	rs
Facu	ulty Coordinat	or: Dr. Usha Rani I	C R				
			UNIT - I			9 H	rs
Engine Control Ignition Timing Motivation for terms, Definition on performance pressure Elect	of Automotive l, Internal Cor g, Drivetrain, S Electronic Eng on of Engine p e, Control Stra tronic Ignition	e: Evolution and Use nbustion Engines, S Suspensions, Brakes gine Control, Concep performance terms, 1 ategy, Electronic Fu	park Ignition Engines and s and Steering Systems. I bt of an Electronic Engine Engine mapping, Effect o el control system, Analys	otive, Automoti ad Alternative E Basics of electro e control syster f Air/Fuel ratio sis of intake ma	ve Systems, 1n ongines. Ignition onic engine com n, Definition of n, spark timing nifold	e Eng Syst trol: Gener and E	ral GR
pressure, Dicer			INIT - II			9 н	TS.
Automotive Sen Air Flow Senso Sensors for Fee Actuators: Sole Switches.	nsors and Act or, Engine Cra edback Contro enoids, Piezo F	uators: Automotive nkshaft Angular Pos I, Sensors for Drive Electric Force Genera	Control System Applicati ition Sensor, Throttle An Assistance System: Rac ators, Fluid mechanical A	ons of Sensors Igle Sensor, Ter Iar, Lidar, Video Actuators, Elect	and Actuators, nperature Sens o Technology. tric Motors and	Senso or,	ors:
		U U	NIT - III	14		8 H	rs
Control System Electronics (Di Control. Automotive Co topology. Buse Embedded Sof	n, Digital Spee gital only), An mmunication s in motor veh tware Develop	d Sensor, Throttle A tilock Brake System Systems: Automotiv ticles: CAN, Flex Ray ment Fundamentals	ctuator, Digital Cruise C (ABS), Electronic Suspective (NIT - IV e networking: Bus system r, LIN, Ethernet, IP, PSI5 of Software and software	control configur nsion System, 1 ms, Technical p , MOST, D2B a re development	ration, Cruise C Electronic Steer principles, netw nd DSI. Autom lifecycles. Over	ontrol ing 8 H ork otive view o	<u>rs</u> f
AUTOSAR met	hodology and	principles of AUTOS	AR Architecture. Introdu	action Internet	of Vehicles, V2V	/.	
Diagnostics an Onboard diagn based Air Bag Alternators in communication Diagnostics (O Electronic Syst Avoidance Rad navigation, Vid	d Safety in Au ostics, Off-bo systems, Case vehicles, Start n buses – Digi BD). Introduc tems: Alternat ar warning Sy leo based driv	tomotive: Timing Li ard diagnostics, Exp study on ON-BOAF ing motor systems, tal engine control sy tion to electric vehic ive Fuel Engines, El stems, Navigation: I er assistance system	ght, Engine Analyzer, Ele ert Systems, Occupant F D, OFF-BOARD diagnos Electrical circuits and wi stems, Introduction to a les. Experiential Learnin ectric and Hybrid vehicle Navigation Sensors, Radius, Night vision Systems.	ectronic Contro Protection Syste tics. Battery- ty iring in vehicles utomotive contr g Topics: Advar es, Fuel cell pow o Navigation, do	l System Diagn ems – Acceleron ypes and mainte s, vehicle netwo rollers, On-Boa nces in Automo vered cars, Coll ead reckoning	ostics neter enanc rk and rd cive ision	e, 1
Course Outco	mes:	no the student 11	a abla ta				
CO2	: Acquire the communica	e knowledge of autor ation interfaces in A pus types of sensors	notive domain fundamen utomotive systems. actuators and Motion C	ntals, need of E	lectronics and aes in Automoti	ve	
CO3	3 : Analyze dig automotive	ital engine control s systems.	ystems and Embedded S	Software's and I	ECU's used in		
CO4	: Evaluate th	ne concepts of Diagr	ostics, safety and advan	ces in Automot	ive electronic \overline{S}	ystem	s.



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Reference Books

1. Bosch, "Automotive Electrics and Automotive Electronics. System and components ,Networking and Hybrid drive", Fifth edition, Springer view 2014

2. Understanding Automotive Electronics, Williams. B. Ribbens, 6th Edition, 2003, Elsevier science, Newness publication, ISBN-9780080481494.

3. NajamuzZaman, "Automotive Electronics Design Fundamental" first edition, Springer 2015.

4. Hillier's, "Fundamentals of Motor Vehicle Technology on Chassis and Body Electronics", Fifth Edition, Nelson Thrones, 2007

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EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full question from each unit.

Dubalo for CIP & CFF The

2	RUBRIC for CIE			RUBRIC for SEE	
SLNo	Content	Marks	Q. No	Contents	Marks
1	Quizzes - Q1 & Q2	20	Each unit consists of TWO questions of 20 Marks each. Answer		wer FIVE
2	Tests - T1 & T2	40		full questions selecting ONE from each unit [1 to 5].	
3	Experiential Learning - EL1 & EL2	40	182	Unit-1: Question 1 or 2	20
	Total Marks	100	384	Unit-2: Question 3 or 4	20
			546	Unit-3: Question 5 or 6	20
			748	Unit-4: Question 7 or 8	20
			9 & 10	Unit-5: Quastion 9 or 10	20
				Total Marks	100



			Semest	er: II		
			PHYSICAL DE	SIGN		
Elective C: (Professional Elective)						
Course Code	100 Marks					
Credits: L:T:P	:	3:0:0		SEE	:	100 Marks
Total Hours	:	42 L		SEE Duration	:	03 Hours
			Unit-I			10 Hrs
Introduction Review of Combi- circuit and layo logic structures Sequential Log Introduction, B in logic synthes synthesis and to Floorplan Technology File Placement, Desi Placement Global Placemen	ina ut ic (asi is c ech ci gn	tional & Sequenti design, CMOS lo Synthesis cs of FSM concep of combinational a nology mapping, reuit Description of Floorplan Detail Placement.	al Logic circuit, gic gate design, t, Describe logic and sequential c Clocking strateg Unit – II , Design Constra	VLSI design Flow, Ve Basic physical desi synthesis process, I ircuits, Classify mul jes.	erilog/V ign of si Explain Itilevel I	HDL basics, CMOS imple gates, CMOS procedure involved ogic 08 Hrs rer Planning, Macro
		101	Unit -III			08 Hrs
Routing Global Routing, RC Extraction Resistance extra	De	tail Routing, Cloc on, Capacitance	ek tree synthesis extraction, Indu Unit -IV	, Power Analysis. ctance and impedar	nce (RLC) extraction. 08 Hrs
UPF fundament	als	concepts of Logi	c Equivalence C	heck (LEC) and Des	ign Low	Power Checks
(CLP). Static Timing A Foundry Library time, hold Time Skew(source & a Multi-Cycle Patl	Ana 7; L , co net	iberty format, Ga intamination dela work latency), Tir False Path, Retim	tes: Propagation y, Recovery time ning Paths, Mul-	Delays, Flops: Prop , Removal time, Clo ti-input path, Clock	bagation ock freq Budget	Delay, Setup uency, Jitter, , Multi-Clock,
~	-242		Unit -V			08 Hrs
Physical Verifi Study of CMOS gates, combinat Rules, Resolutio	s T ior	ion echnologies, DRC aal and sequentia Enhancement Rul	and Manufact d circuits DRC, les.	uring Issues, Basic LVS, Study of Ante	physica enna Ru	al design of simple ules, Layer Density

Design For Testing

Introduction to Digital Testing - Fault modelling, Fault Simulation, Testing for Single stuck faults, Design for Testability (DFT), Scan based designs – Compression Techniques, Built-In -Self-Test (BIST), Boundary Scan Test (IEEE 1149.1)

Physical Design Value Added Lab:

- 1. Write register transfer logic level code using Verilog for combinational and sequential digital systems.
- 2. Analyse combinational and sequential logic circuits by simulating.
- 3. Write Constraints and Perform logic synthesis of Verilog logic designs.
- Generate the synthesized netlist and analyse critical path delay, area, power, and performance of the digital system.
- Perform Low Power checks (CLP) & Logic Equivalence Checks (LEC) using the design (RTL/Netlist)
- Perform physical design flow: Use floorplan, placement, clock tree synthesis and routing steps.
- Back annotation: Extract resistance, capacitance, inductance and simulate the design. Static timing analysis checks:

Setup/Hold/Max_Transition/Max_Cap/Noise/Cross Talk/Min_Pulse_Width Physical Verification checks: DRC/ERC/SOFT/LVS/ANTENNA/DENSITY Design For Test: Scan Insertion, ATPG, MBIST, BSCAN implementation and verification

Course	Course Outcomes: After completing the course, the students will be able to					
CO1:	Explain the principles of physical design, including floor planning, placement, and routing, which are essential for creating efficient and reliable integrated circuits.					
CO2:	Analyse physical design problems and employ appropriate automation algorithms for partitioning, floor planning, placement, and routing.					
CO3:	Perform clock tree synthesis, power optimization, and low-power design, which are essential for designing complex integrated circuits.					
CO4:	Apply the various techniques used to verify the correctness of the physical design, including design rule checking (DRC), layout versus schematic (LVS) checks, and electrical rule checking (ERC) and scan chain insertion.					

Refe	erence Books
1.	Physical Design Essentials: An ASIC Design Implementation Perspective, Khosrow Golshan, 1 st Edition, Springer, ISBN-10: 44194219X, ISBN-13: 978-1441942197.
2.	Static Timing Analysis for Nanometer Designs, J. Bhashkar and Rakesh Chadha, 2009 th Edition, Springer-Verlag New York Inc, ISBN-10:0387938192, ISBN-13:978-0387938196.
3.	CMOS Digital Integrated Circuits Analysis and Design, Sung-Mo Kang and Yusuf Leblebici, 41st Edition, December 2002, McGraw-Hill Higher Education, ISBN-10: 9780071243421 ISBN-13: 978-0071243421.
4.	Digital Systems Testing and Testable Design, M. Abramovici, M. A. Breuer, and A. D. Friedman, Computer Science Press, 1990, ISBN: 0-7167-8179-4.



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RUBRIC for CIE				RUBRIC for SKE				
SLNo	Content	Marks	Q. No	Contents	Marks			
1	Quizzes - Q1 & Q2	20	Each u	nit consists of TWO questions of 20 Marks each. Answ	or FIVE			
2	Tests - T1 & T2	40		full questions selecting ONE from each unit (1 to 5).				
3	Experiential Learning - EL1 & EL2	40	182	Unit-1: Question 1 or 2	20			
	Total Marks	100	3&4	Unit-2: Question 3 or 4	20			
			5&6	Unit-3: Question 5 or 6	20			
			788	Unit-4: Question 7 or 8	20			
			9 & 10	Unit-5: Question 9 or 10	20			
				Total Marks	100			

Go, change the world Educational Inalitudiors." **RV College of Engineering*** Approved by ACTE. SEMESTER: II MBT331G CIE Marks 100 Course : **BIOINSPIRED ENGINEERING** Code Credits L-T-: 3-0-0 SEE Marks 100 : Ρ Hours : 42L Elective G (Global Elective) SEE 3 Hr : Durations Faculty Dr Nagashree Rao and Dr Ashwani Sharma Coordinator: UNIT - I 8 Hrs Introduction to Bio-inspired Engineering: Macromolecules, Stem cells; types and applications. Synthetic Biology; Bottom-up' and 'top-down' engineering approaches. Synthetic/ artificial life. Biological Clock, Genetic Algorithms. UNIT - II 9 Hrs Principles of bioinspired materials: Biological and synthetic materials, Self-assembly, hierarchy and evolution. Biopolymers, Bio-steel, Bio-composites, multi-functional biological materials. Thermal Properties. Antireflection and photo-thermal biomaterials, Microfluidics in biology, Invasive and non-invasive thermal detection inspired by skin UNIT - III 9 Hrs Lessons from Nature: Bioinspired Materials and mechanism: Firefly-Bioluminescence, Cockleburs -Velcro, Lotus leaf - Self-cleaning materials, Gecko - Gecko tape, Whale fins - Turbine blades, Box Fish / Bone -Bionic car, Shark skin - Friction reducing swim suits, Kingfisher beak - Bullet train, Coral - Calera cement, Forest floor / Ecosystem functioning - Flooring tiles, Morpho butterfly- Structural color, Namib beetle- Water collecting, Termite mound passive cooling, Birds/Insects- flights/ aerodynamics, Mosquito inspired micro needle. UNIT - IV 8 Hrs Biomedical Inspiration-Concept and applications: Organ system- Circulatory- artificial blood, artificial heart, pacemaker. Respiratory- artificial lungs. Excretory- Artificial kidney and skin. Artificial Support and replacement of human organs; artificial liver and pancreas. Total joint replacements- artificial limbs. Visual prosthesis -artificial eye/ bionic eye. UNIT - V 8 Hrs Biomimetics: Inventions in nature for Human Innovation: Photosynthesis and Photovoltaic cells, Bionic/Artificial leaf. Bio-ink and 3D-Bioprinting, Cellular automata, Biosensors: Artificial tongue and nose. Biomimetic echolation. Insect foot adaptations for adhesion. Thermal insulation and stcrage materials. Bees and Honeycomb Structure, Artificial Intelligence, Neural Networking and bio-robotics. Course Outcomes: After going through this course the student will be able to: CO1 : Elucidate the concepts and phenomenon of natural processes CO2 : Apply the basic principles for design and development of bioinspired structures CO3 : Analyse and append the concept of bio-mimetics for diverse applications CO4: Designing technical solutions by utilization of bio-inspiration modules. **Reference Books:** 1. D. Floreano and C. Mattiussi, Bio-Inspired Artificial Intelligence: Theories, Methods and Technologies, 1st edition, MIT Press, 2008, ISBN: 9780262062718 2. Guang Yang, Lin Xiao, and Lallepak Lamboni. Bioinspired Materials Science and Engineering. 1st edition, John Wiley, 2018, ISBN: 978-1-119-3903362 3. M.A. Meyers and P.Y. Chen. Biological Materials, Bioinspired Materials, and Biomaterials, 1st edition, Cambridge University Press, 2014, ISBN 978-1-107-01045. 4. Tao Deng. Bioinspired Engineering of Thermal Materials, 1st editon, Wiley-VCH Press, 2018. ISBN: 978-3-527-33834-4.

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Rev Loss	RV Educational Institutions " RV College of Engineering " Mathematics Affiner Instantics Affiner Insta		Go, change the world		
		SEMESTER: II			
Course Code	: MBT332G	HEALTH INFORMATICS	CIE Marks	:	100
Credits L-T- P	: 3-0-0		SEE Marks	:	100
Hours	SEE Durations	:	3 Hrs		
Coo	rdinator:	Dr it if manjeutatila ready			
ntroduction warehouse, o analytics, ch	, Healthca re d a lata allenges, role c	UNIT - I ata, information and knowledge: Data types, dat of informatics in analytics, future trends	a conversion, clini	ical	8 Hrs lata
Electronic he selecting and mplementin	ealth records: I 1 g EHR	introduction, scope for the e health records, chai	llenges, examples,	logi	cal steps t
		UNIT - III			8 Hrs
Data standa: <u>transport s</u> ta	rds and m <mark>edic</mark> andards, medic	al coding: Introduction, medical content standar al coding and reimbursement, future trends,	ds, termonology s	tand	ards,
		UNIT - IV			9 Hrs
lealthcare E nvolved, bar	Enterprise: Ove rriers, program	rview of Health Informatics: Introduction, Key pl s, organizations and career, HI Resources	layers in HI, organ	nizat	ions
	0.5	UNIT - V			9 Hrs
Course Outc After going th CO1 CO2 CO3 CO4 Reference B 1. Robert E. Fechnology B 2. Kathryn J 35233-826-1 3. William R 4. Pentti Nie: 3036500980 Scheme of C	 comes: hrough this continuous in the second sec	urse the student will be able to: the basic principles of Health informatics, e to data transformation and to analysis. E health records, identify the challenges. the significant factors as per the spatio-temporal factors as per the spatio-temporal factors and the edition, 2014, 18BN: 9 oshihashi, Health Informatics, Practical guide for oth edition, Informatics Education, 2014, 18BN: 9 on J. Ball, Health Informatics, Springer Series en Informatics, a Practical guide, 8th edition. 2022 I informatics and data analysis 1st edition, MDP ternal Evaluation (CIE): 20 + 40 + 40 = 100	requirements. r Healthcare and 1 978-0-9887529-2 dition, Springer, 2 , ISBN 978-1-387 I AG, 2021, ISBN	Infor -4 2005 -13 :	rmation , ISBN: 1- 175-2 978-
QUIZZES: Q be evaluated TESTS: Stud Bloom's Taxo Two tests with narks will b EXPERIENT mplementat 15), Video b Scheme of S	uizzes will be of for 10 Marks. dents will be evonomy Levels: ll be conducted e reduced to 40 IAL LEARNIN ion of the prob ased seminar/ Semester End	conducted in online/offline mode. Two quizzes with The sum of two quizzes will be the Final Quiz more valuated in test, descriptive questions with different Remembering, Understanding, Applying, Analyzi I. Each test will be evaluated for 50 Marks, addin O Marks. G: Students will be evaluated for their creativity lem. Case study-based teaching learning and Pr presentation/demonstration (25) adding upto 40 Examination (SEE) for 100 marks: The question	ill be conducted & arks. ent complexity lev ng, Evaluating, an ng upto 100 mark and practical ogram specific rec) marks.	s Ead rels (nd C s. Fi quire FIV	ch Quiz wi Revised reating). nal test ements E questio

C in term	ege of Engineering *		Go, change l	he a	orld
Tachtsdargana Istinisticity, Be	nger	ODWDOWDD, H			
Course Code	: MCS331G	BUSINESS ANALYTICS	CIE Marks	:	100
Credits L-T- P	: 3-0-0		SEE Marks	:	100
Hours	: 42L	Elective G (Global Elective)	SEE Durations	3 :	3 Hrs
Facu	ılty dinator:	Dr. Azra Nasreen and Dr. Badarinath K			
0001	uniator.	UNIT - I			9 Hrs
Overview of B Business Ana Tools: Statisti modelling.	dusiness analyt llytics Process ical Notation, I	and organization, competitive advantages of Business Ana bescriptive Statistical methods, Review of proba	ability distribution	kelati s. Sta on ar	onship of atistical id data
<u>8</u> ,		UNIT - II			9 Hrs
Trendiness an Important Re- solving, Visua	nd Regression . sources, Busin alizing and Exp	Analysis Modelling Relationships and Trends ir ess Analytics Personnel, Data and models for I loring Data, Business Analytics Technology.	n Data, simple Li Business analyti	inear cs, p	Regression. roblem
		UNIT - III			8 Hrs
Forecasting T Models for Sta Series with Se	echniques Qua ationary Time easonality, Reg	UNIT - IV alitative and Judgmental Forecasting, Statistica Series, Forecasting Models for Time Series with ression Forecasting with Casual Variables, Sel	al Forecasting M a Linear Trend, ecting Appropria	odels Fore ate Fe	8 Hrs s, Forecasting ecasting Time precasting
woucis.		UNIT - V			8 Hrs
Decision Anal Probabilities, Course Outc	lysis Formulati Decision Trees omes:	ng Decision Problems, Decision Strategies with , The Value of Information, Utility and Decision	n and without Ou n Making.	atcor	ne,
After going t	hrough this c	ourse the student will be able to:	luo huoinogo nro	hlow	
CO1	: Analyse, mod	le and solve decision problems in different set	ings	oblell	18
CO3	: Interpret rest scenario	alts/solutions and identify appropriate courses	of action for a g	given	business
CO4	: Demonstrate and following ethical practi	skills like investigation, effective communication ces by implementing solutions to decision mak	on, working in te ting problems	eam/	Individual
Reference Bo	ooks:				
1. Business a Dara G.	nalytics Princi	ples, Concepts, and Applications FT Press Ana	lytics, Marc J. S	chnie	ederjans,
Schniederjans 0133989402	s, Christopher	M. Starkey, 1st Edition, 2014, ISBN-13: 978-0	133989403, ISB	BN-10):
2. The Value DOI:10.1002	01 Business An 2/9781118983	alytics: Identifying the Path to Profitability, Ev. 881,1st Edition 2014, ISBN:978111898388	an Stubs , John $\frac{1}{1200780201}$	$\frac{\text{wile}}{0079}$	y & Sons,
10: 03219978 4. Predictive I	Business Analy	tics Forward Looking Capabilities to Improve F	Business, Gary C	Cokin	is and
Lawrence Ma	isei, wiiey; 1st	Euluoli, 2013, ISBN: 978-1-118-17550-9.			

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choice from each unit. Each question will carry 20 marks. Student will have to answer one full question from each unit.

The Lancest	ege of Engineen Approxition Approximation Ap	ng *	Go, change	the	world
		SEMESTER: II	1	T	1
Course Code	: MCV331	G INDUSTRIAL AND OCCUPATIONAL HEALTH	CIE Marks	:	100
Credits L-T- P	: 3-0-0	AND SAFETY	SEE Marks	:	100
Hours	: 42L	Elective G (Global Elective)	SEE Durations	:	3 Hrs
Facu Coor	lty dinator:	Dr.V.AnanthaRam			0011
	UNI	Γ-Ι			USHIS
Industrial sat causes and p wash rooms, codes. Fire pr	Yety: Accide reventive s drinking v revention a	ent, causes, types, results and control, mechanical a teps/procedure, describe salient points of factories ac vater layouts, light, cleanliness, fire, guarding, press and fire fighting, equipment and methods.	nd electrical l et 1948 for hea ure vessels, et	haza alth a tc, S	rds, types, and safety, afety color
		UNIT - II			09Hrs
work and health promo Management, professionals hazards, Ergo techniques, I controls, Wor of occupation	alth, Health otion. Heal Workers, Potential onomic haz nterpretati k practice al diseases	h hazards, workplace, economy and sustainable develop th protection and promotion Activities in the workp Workers' representatives and unions, Commun health hazards: Air contaminants, Chemical hazards ards, Psychosocial factors, Evaluation of health hazards on of findings recommended exposure limits. Cont controls, administrative controls. Occupational diseases, Prevention of occupational diseases.	lopment, Work place: Nationa nities, Occup , Biological ha ards: Exposure rolling hazard es: Definition,	ation ation zard e me s: E Char	a factor in vernments, nal health s, Physical asurement ngineering cacteristics
		UNIT - III			09Hrs
Hazardous M Gases, Meta Manufacturin Sensitizers an Temperature Related Healt Diaplay Torm	aterials cha s and Mo g Materials ad Teratoge and Pressi h Incidents	aracteristics and effects on health: Introduction, Cheme etallic Compounds, Particulates and Fibers, Alkal s, Chemical Substitutes, Allergens, Carcinogens, Muta ns, Recommended Chemical Exposure Limits. Physica are, Carcinogenicity, Mutagenicity and Teratogenicity. J, Eyestrain, Repetitive Motion, Lower Back Pain, Video	ical Agents, O ies and Oxid agens, Reprodu l Agents, Noise Ergonomic St o	rgan lizers uctiv and tress	ic Liquids, s, General e Hazards, Vibration, es: Stress-
	illais.	UNIT - IV			08 Hrs
Wear and Con types and app cup, ii. Press feed lubricati corrosion, con	rrosion and blications, l ure grease on, vii. Ri rosion pre	their prevention: Wear- types, causes, effects, wear nubrication methods, general sketch, working and app gun, iii. Splash lubrication, iv. Gravity lubrication, v. ng lubrication, Definition, principle and factors afferention methods.	reduction meth lications, i. Sc . Wick feed lul ecting the cor	nods, rew o orica rosic	, lubricants- down grease tion vi. Side on. Types of
		UNIT - V			08 Hrs
Periodic and repairing sch troubles and advantages o Machine tools preventive ma maintenance.	preventive emes, ove remedies f preventive s, ii. Pump intenance <u>Repair cyc</u>	maintenance: Periodic inspection-concept and nee chauling of mechanical components, over hauling of of electric motor, repair complexities and its use, e maintenance. Steps/procedure for periodic and p s, iii. Air compressors, iv. Diesel generating (DG) se of mechanical and electrical equipment, advantages o ele concept and importance.	d, degreasing of electrical m definition, ne preventive main ts, Program a f preventive	, cle notor eed, nten nd s	aning and c, common steps and ance of: I. chedule of
Course Outco After going t	omes: hrough th	s course the student will be able to:			
CO1	: Explain t	he Industrial and Occupational health and safety and	its importance	2.	
CO2	Demonst employee expose in	rate the exposure of different materials, occupational e can the industries.	environment to	o whi	ich the
03		ize the unterent type materials, with respect to safety	and nearth na	zard	S 01 IL.

	RV Educational Ins RV College of	Engineering
- AL	Advoctorum Instituter: Attituter In Annerer ann Tecnological Instituter: Balance	Approved by HCTE. New Date:

			SEMESTER: II			
Course Code	:	MCV332G	INTELLIGENT TRANSPORTATION SYSTEMS	CIE Marks	:	100
Credits L-T- P	:	3-0-0		SEE Marks	:	100
Hours	:	42L	Elective G (Global Elective)	SEE Durations	:	3 Hrs
Faculty Coor	di	nator:	Dr.Sunil S			
			UNIT - I			8 Hrs
Introduction Fundamenta streams, Tra	: - ls ffi	Historical Ba of Traffic Flov c signalization	ckground, Definition, Future prospectus, ITS training and edu w and Control- Traffic flow elements, Traffic flow models, Sho n and control principles, Ramp metering, Traffic simulation	ucational needs ck waves in Tra	ક. aff	ic
			UNIT - II			9 Hrs
ITS User serv Electronic Pa safety system and Project I Architecture, development	vic ay: ns TS , N to	ces-User servi ment, Comme , Information S Need of ITS ar pol	ces bundles, Travel and Traffic management, Public Transpor ercial Vehicles Operations, Emergency Management, Advanced Management, Maintenance and construction Management. IT chitecture, concept of Operations, National ITS Architecture,	tation Operatic l Vehicle Contr IS Architecture Architecture	on ol	s, and Regional
			UNIT - III		Π	9 Hrs
Traveller Info their benefits Advanced Pu <u>Multimodal 7</u>	ori s-l ibl fra	mation. Vario Freeway a nd i lic Transporta aveller Inform	us detection, identification and collection methods for ITS. ITS neident management systems, Advanced arterial traffic contra- tion Systems, ation systems	S Applications a ol systems,	an	d 8 Hrs
ITS Planning	r_′	Fransportatio	a planning and ITS Planning and the National ITS Archite	cture Planning	<u> </u>	for ITS
Integrating I National IT Communicat testing	rs S tio	architecture	rtation Planning, relevant case studies. ITS Standards-Standa and standards, ITS standards application areas, N stocol, Standards	rd development ational Trans	t p	process, prtation
			UNIT - V			8 Hrs
ITS Evaluation ITS component Enhance and support the o	on en 1 en	1 – Project sele ts, Evaluation forcement tra	ection at the planning level, Deployment Tracking, Impact Ass Guidelines, Challenges and Opportunities. ITS for Law Enfor ffic rules and regulations, ITS Funding options and ITS case	essment, Bene reenent: Introd studies	fit luo	s by ction,
0						
After going CO1 CO2 CO3	:0 th : :	Identify and Illustrate ITS Examine the	apply ITS applications at different levels architecture for planning process significance of ITS for various levels			
CO4	:	Compose the	importance of ITS in implimentions			
Reference B	0	oks:				
1. Pradip Ku Delhi,2018,I	m SE	ar Sarkar and 3N-97893874	l Amit Kumar Jain, "Intelligent Transport Systems", PHI Learn 72068	ning Private Lin	ni	ted,
2. Choudury publishers (3	№ 81	I A and Sadek March 2003);	A, "Fundamentals of Intelligent Transportation Systems Plar ISBN-10: 1580531601	nning" Artech H	lo	use
3. Bob Willia 59693-291-3	m 3	s, "Intelligent	transportation systems standards", Artech House, London, 2	008. ISBN-13:	9′	78-1-
4. Asier Pera Systems: Teo	llo h	os, Unai Herna nologies and A	andez-Jayo, Enrique Onieva, Ignacio Julio García Zuazola "In Applications" Wiley Publishing ©2015, ISBN:1118894782 978	telligent Transj 1118894781	po	rt

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Constraint a		ee. 1.	SEMESTER: II				
Course Code	:	MEC331G	ELECTRONIC SYSTEM DESIGN	CIE Marks	:	100	
Credits L-T- P	:	3-0-0		SEE Marks	:	100	
Hours	:	42L	Elective G (Global Elective)	SEE Durations	:	3 Hrs	
Faci		ty	Prof. Ravishankar Holla				
000	u	1112101.	UNIT - I		Т	9 Hrs	
Design Proce Guidance for Aided Design	ss P ((s & its Funda: Product Plann CAD)	mentals: Life Cycle of Electronic Products, Design and Develop ing, Design and Development, Technical Drawings, Circuit Dia	oment Process, agrams, Compu		er-	
			UNIT - II			9 Hrs	
System Alen Systems Des the below me Distribution, Systems, Rec	ig nt F	n Architectur tioned topics ailure of Elec mmendations	e, Electronic System Levels, System Protection Experiential I other than CIE) Reliability Analysis: Introduction, Calculation tronic, Components, Failure of Electronic Systems, Reliability for Improving Reliability of Electronic Systems	Learning: (4 qu Principles, Exp y Analysis of El	iz or	zes on nential ctronic	
			III			0 1115	
Thermal Mar. Principles, H Recommenda systems.	lea lea	gement and C at Transfer, ons for Therr	Cooling: Introduction - Terminology, Temperatures and Power Methods to Increase Heat Transfer, Application Examples nal Management of Electronic Systems, Cooling systems, liq	Dissipation, Ca in Electronic uid, air and no	al S on	culation bystems, cooling	
			UNIT - TV			8 Hrs	
Electromagne Introduction, Electrostatic Recycling Re Economy, Ma	eti D Qu	ic Compatibili Coupling Bet ischarge (ESI uirements and ufacture, Use	ity (EMC): ween System Components, Grounding Electronic Systems, D), Recommendations for EMC-compliant Systems Design UNIT - V d Design for Environmental Compliance: Introduction - Mot e, and Disposal of Electronic Systems in the Circular Econor prial Peopoling in the Disposal Process, Design and Develo	ivation and the		Fields, 8 Hrs Circular cling in	
Material Suit	ı al	oility in Desig	n and Development Recommendations for Environmentally (Compliant Syste	as m	isembry,	
material Suit	u	Juity III Deolg	in and Development, Recommendations for Drivitonmentary e	omphane syste	/11.	10	
Course Outc After going t	oı :h	mes: rough this c	ourse the student will be able to:				
CO1	:	Realize the fu requirements Electronic Sy	undamentals of Design, Architecture, thermal management, E of estem Design	MC and Recycli	in	g	
CO2	:	Analyze the v related concepts of in	arious application wise design requirements in Electronic sys	tems along with	h	the	
CO3	:	Use modern	open source tools to realize the various concepts of Electronic	system design			
CO4	:	Engage in se	It-study through assignments, simulations, case studies and j	projects			
Reference B	00	oks:			_		
1. Fundamer Publishing, IS 978-3-319-55	ita SE 58	als of Electror 3N 339-4. DOI:10	nic Systems Design, Jens Lienig, Hans Brümmer 2017, Spring	er Internationa	ıl		
2. "Embedde	d	System Desig	n", Marwedel, Peter, Springer Nature, 10.1007/978-3-030-60	910-8			
3. "Electroma	ag	netic Compat	ibility Engineering", Henry W. Ott, WILEY Publication, ISBN:	978-0-470-189	30	0-6	
4. "Handbool 0070266834	ζ (of Electronic \$	Systems Design" by Charles A. Harper, McGraw-Hill Inc.,US,	0070266832, 9	<i>}</i> 7	8-	

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			SEMESTER: II			_
Course Code	:	MEC332G	EVOLUTION OF WIRELESS	CIE Marks	:	100
Credits L-T- P	:	3-0-0	TECHNOLOGIES	SEE Marks	:	100
Hours	:	42L	Elective G (Global Elective)	SEE Durations	:	3 Hrs
Fact	ılı rd	ty inator:	Dr. Mahesh A			
	,		UNIT - I			9 Hrs
Introduction Frequency re Bluetooth, W	tc u ïF	o cellular syst se, Co-chann Yi, WWAN and	ems: Overview of Cellular Systems and evolution 2G/3G/4G/ el and Adjacent channel Interference, C/I, Handoff, Blocking, PAN.	5G, Cellular C Erlang Capaci	or ity	icepts –
	_		UNIT - II			9 Hrs
loss, Noise fi Capacity, OF Fundamenta	gu D	of 5G archite	, Multipath fading, Shadowing, Fading margin, Shadowing ma arge Scale Propagation effects and Channel Models UNIT - III cture: Difference between 4G and 5G, 5G Architecture, Plann	ing of 5G Netv	, C	hannel 8 Hrs ck,
Quality of Se	IV te	s s s s s s s s s s s s s s s s s s s	twork, Requirements, Security, Sim in 56 Era, Specifications,	Standardizat	101	1,
	it	0	UNIT - IV			8 Hrs
mmWave and	1	Visible Light (Communications: Back ground and concept of mmWave Communications and aballenges in EC	nunications, F	re	quency
bands, propa	iga		INIT - V			8 Hrs
Future Gene	ra	tions: Future	Generations (where is the 6G2) Health Considerations Identi	fiers Interface	20	Key
Derivation, L Virtualization Reality (VR/A	00 1, \R	cation Based 8 Network Slici R/XR). Case s	Services, Massive Internet of Things, Measurements, Network ng, Open Source, , User Equipment, Vehicle-to-Vehicle comm tudy- Bharath Stack	Functions Junications (V2	2V),Virtual
Course Outo After going	o: th	mes: rough this c	ourse the student will be able to:			
C01	:	Demonstrate of different wire	their understanding on functioning of wireless communication less communication systems and standards	n system and	ev	olution
C02	•	Compare dill	erent technologies used for wireless communication systems.	tion avatoma		
C03	•	Undate the l	an ability explain recent techniques for wheless communications	tion systems		
Reference B	•		dest trends in wheless communications			
1 Theodore	3	Rannanort "	Wireless Communications: Principles and Practice" Pearson	2nd Edition		
2. Aditva K .I	э. Эя	gannatham "	Principles of Modern Wireless Communications". McGraw Hill	. 2017		
3. Robin Cha	ita	ut, Robert Al	d, "Massive MIMO Systems for 5G and beyond Networks—Ove	erview, Recent	T1	rends,
and Future F	Re	search Direct	ion" Sensors, May 2020			
4. A. N. Uwa Fifth-Genera	ec tic	hia and N. M. on Wireless N	Mahyuddin, A Comprehensive Survey on Millimeter Wave, Cetworks: Feasibility and Challenges, in IEEE, Access, vol. 8, p	ommunication p. 62367-624	ιs : 14	for , 2020

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		SEMESTER: II			
Course Code	: MIM331G	PROJECT MANAGEMENT	CIE Marks	:	100
Credits L-7 P	- : 3-0-0		SEE Marks	:	100
Hours	: 42L	Elective G (Global Elective)	SEE Durations	:	3 Hrs
Fa	culty ordinator	Dr. Vikram N Bahadurdesai			
	or aniator.	UNIT - I			8 Hrs
Introducti Team Worl Methodolog	on : Project Plan , Project Planni gy.	ning, Need of Project Planning, Project Life Cycle ng Process, Work Breakdown Structure (WBS), I UNIT - II	e, Roles, Responsi introduction to Ag	bility ile	and
Capital Bu decision m budgeting	dgeting : Capita aking,facets of p	l Investments: Importance and Difficulties, phas project analysis, feasibility study – a schematic d	ses of capital budg liagram, objectives	geting s of c	g, levels of
		UNIT - III			9 Hrs
Tools & To diagrams a Computeri	chniques of Pr nd networks, Pr zed project mana	oject Management: Bar (GANTT) chart, bar char oject evaluation and review Techniques (PERT) agement	art for combined a Critical Path Meth	ctivit od (C	ties, logic CPM),
		UNIT - V			9 Hrs
USA – imp Methodolog Manageme measurem	bragement and prtance of the sa gy, hemes / Epic nt: Case studies ent.	Certification : An introduction to SEI, CMMI aroune for the industry and practitioners. PMBOK (cs / Stories, Implementing Agile. Domain Specific covering project planning, scheduling, use of to	d project manage 5 - Introduction to a Case Studies on pols & techniques,	ment Agil Proj perf	e ject ormance
0					
After goin	g through this 1 : Explain pro quality.	course the student will be able to: ject planning activities that accurately forecast j	project costs, time	lines	, and
CC	2 : Evaluate the	e budget and cost analysis of project feasibility.			
CC	3 : Analyze the	concepts, tools and techniques for managing pr	ojects.		
CC	4 : Illustrate pr from multip	oject management practices to meet the needs o le	of Domain specific	stak	eholders
Deference	sectors of th	ne economy (i.e. consulting, government, arts, m	edia, and charity	orgai	nizations).
1. Prasann	a Chandra, Proj	ect Planning Analysis Selection Financing Imple	mentation &	Revi	ew, Tata
2. Project I Guide), 5th	Management Ins Edition, 2013.	titute, A Guide to the Project Management Body ISBN: 978-1-935589-67-9	of Knowledge (PM	IBOK	<u> </u>
3. Harold I John Wiley	Kerzner, Project & Sons In	Management A System approach to Planning Sc c., 11th Edition, 2013, ISBN 978-1-118-02227-	heduling & С б.	Contr	olling,
4. Rory Bu Edition, 20	rke, Project Mar 04, ISBN: 9812-	agement – Planning and Controlling Techniques -53-121-1	s, John Wiley &an	ıp; S	ons, 4th

SEMESTER: II Course Code i MIS331G DATABASE AND INFORMATION SYSTEMS Credits L-T-P i 3-0-0 Elective G (Global Elective) Hours i 42L Elective G (Global Elective) Faculty Coordinator: Prof.Smitha G R UNIT - I Advanced Database Models, Systems, and Applications : Enhanced Data Models: Introduction to A Multimedia, and Deductive Databases . Distributed Database Concepts : Distributed Database Correst rangentation, Replication, and Allocation Techniques for Distributed Database Design, Overview and Recovery in Distributed Databases UNIT - II Introduction to Information Retrieval and Web Search : Information Retrieval (IR) Concepts Retrieval Queries in IR Systems , Text Preprocessing , Inverted Indexing, Evaluation Measures of Search Rel Analysis, Trends in Information Retrieval . UNIT - III Information Systems, Organizations and Strategy: Organizations and information systems, How in organization and business firms, Using information systems to gain competitive advantage, manag. Social issues in Information Systems: Understanding ethical and Social issues related to Information formation society. A Case study on business plann UNIT - IV Achieving Operational Excellence and Customer Intimacy: Enterprise systems, Supply chain manag. Customer relationship management(CRM) systems, Enterprise application. E-commerce: Digital M E-commerce web site. A Case study on ERP. UNIT - V </th <th>CIE Marks SEE Marks SEE Duration Active, Temporal ncepts, Data of Concurrency val Models, Type levance ,Web Se information syst agement issues, ion Systems, Eth ning.</th> <th>i si ssi co co so arc ems Eth nics yste cooc mm</th> <th>100 100 3 Hrs 8 Hrs patial, ntrol 8 Hrs h and 8 Hrs s impact ical and s in an 9 Hrs ems, ls: erce,</th>	CIE Marks SEE Marks SEE Duration Active, Temporal ncepts, Data of Concurrency val Models, Type levance ,Web Se information syst agement issues, ion Systems, Eth ning.	i si ssi co co so arc ems Eth nics yste cooc mm	100 100 3 Hrs 8 Hrs patial, ntrol 8 Hrs h and 8 Hrs s impact ical and s in an 9 Hrs ems, ls: erce,
Course Code Image: Missain and the internet, E-commerce business and technology, The moviled git and the internet, E-commerce business and technology, The moviled git and the internet, E-commerce business and technology, The moviled git: Course Code Image: Mark and the internet, E-commerce business and technology, The moviled git and the internet, E-commerce business and technology, The moviled git and the internet, E-commerce business and technology, The moviled git and the internet, E-commerce business and technology, The moviled git and the internet, E-commerce business and technology, The moviled git and the internet, E-commerce business and technology, The moviled git and the internet, E-commerce business and technology, The moviled git and the internet is the internet inter	CIE Marks SEE Marks SEE Duration Active, Temporal ncepts, Data of Concurrency val Models, Type levance ,Web Se information syst gement issues, ion Systems, Eth ing. agement(SCM) sy larkets Digital G and mobile E-con	: s: , SI Co ems Eth nics	100 100 3 Hrs 8 Hrs batial, ntrol 8 Hrs h and 8 Hrs ical and ical and 9 Hrs ems, ls: erce,
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Achieving Operational Excellence and Customer Intinacy: Enterprise systems, Supply chain mana Customer relationship management(CRM) systems, Enterprise application. E-commerce: Digital M E-commerce and the internet, E-commerce-business and technology, The mobile digital platform a Building and E-commerce web site. A Case study on ERP. UNIT - V Managing Knowledge:	agement(SCM) so	yste ood mm	ems, ls: .erce,
UNIT - V			
Managing Knowledge:			9 Hrs
Intelligent techniques. Enhancing Decision Making: Decision making and information systems, Bu enterprise. Business intelligence constituencies. Building Information Systems: Systems as planne Overview of systems development.	ige work system isiness intelliger ed organizationa	s, nce 1 cł	in the nange,
After going through this course the student will be able to:			
CO1 : Understand the different models for Infromation Retrieval.			
CO2 : Appricieate the technology of Information Retrieval and Web Search			
CO3: To understand the basic principles and working of information technology.			
Reference Books :			
1. Kenneth C. Laudon and Jane P. Laudon: Management Information System, Managing the Digita Education, 14th Global edition, 2016, ISBN:9781292094007.	al Firm, Pearson	L	
2. Fundamentals of Database Systems, Ramez Elmasri, Shamkant B. Navathe, 7th Edition, 2016, Copyright ©, ISBN-10: 0133970779	Published by Pe	ears	on,
 James A. O' Brien, George M. Marakas: Management Information Systems, Global McGraw Hill, 978-0072823110. Detalage Management Systems, Baska Basalaishaan and Jakanasa Oshaka 2nd Edition 2000 	, 10th Edition, 2		I, ISBN:
9780071231510	ло, мсспаw-нш,	151	DIN:
Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100 QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each 10 Marks. The sum of two quizzes will be the Final Quiz marks. TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (R Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will will be evaluated for 50 Marks, adding upto 100 marks. Final test marks will be reduced to 40 Mar EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implemer	h Quiz will be ev Revised Bloom's 7 rill be conducted rks. ntation of the pr	alu Tax I. Ea	ated for onomy ach test

seminar/presentation/demonstration (25) adding upto 40 marks.



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			SEMESTER: II			
Course Code	:	MIS331G	DATABASE AND INFORMATION SYSTEMS	CIE Marks	:	100
Credits L-T-P	:	3-0-0		SEE Marks	:	100
Hours	:	42L	Elective G (Global Elective)	SEE Durations		3 Hrs
Facı	ılt	y Coordinator:	Dr Mamatha G S			
			UNIT - I			8 Hrs
Advanced Dat	ab	ase Models, Sy	stems, and Applications : Enhanced Data Models: Introduction to Ac	ctive, Temporal, S	Sp	atial,
Multimedia, a	nd	l Deductive Dat	abases . Distributed Database Concepts : Distributed Database Con	.cepts, Data	~	
Fragmentation and Recovery	ı, in	Replication, an Distributed Da	d Allocation Techniques for Distributed Database Design, Overview (Itabases	of Concurrency C	Cor	itrol
			UNIT - II			8 Hrs
Introduction t	o]	Information Re	rieval and Web Search : Information Retrieval (IR) Concepts Retrieva	al Models, Types	of	
Queries in IR Analysis, Tren	Sy ds	stems , Text Pr in Information	eprocessing , Inverted Indexing, Evaluation Measures of Search Rele Retrieval .	wance ,Web Sear	rch	and
			UNIT - III			8 Hrs
Information S	ys	tems, Organiza	tions and Strategy: Organizations and information systems, How in	formation syster	ns	impact
organization a	n	d business firm	s, Using information systems to gain competitive advantage, manag	ement issues, Et	thi	cal and
Social issues i	n	Information Sy	stems: Understanding ethical and Social issues related to Informatic	on Systems, Ethio	cs	in an
information so	oci	ety, The moral	dimensions of information society. A Case study on business planni	ng.		
			UNIT - IV			9 Hrs
Achieving Ope	ra	tional Excellen	ce and Customer Intimacy: Enterprise systems, Supply chain manage	gement(SCM) sys	stei	.ns,
Customer rela	.t10	onship manage	ment(CRM) systems, Enterprise application. E-commerce: Digital Ma	irkets Digital Goo	Sas	3:
Building and	шо Е-	commerce web	site. A Case study on ERP.		me	iice,
	_		UNIT - V			9 Hrs
Managing Kno	w	ledge:				
The knowledg Intelligent tecl enterprise. Bu Overview of sy	e n hn Isi	management la liques. Enhance ness intelligence ems developme	ndscape, Enterprise-wide knowledge management system, Knowledg ng Decision Making: Decision making and information systems, Bus le constituencies. Building Information Systems: Systems as planned nt.	e work systems, siness intelligence organizational o	e i cha	n the ange,
Course Outco	m	ies: ough this cour	se the student will be able to:			
CO1	:	Understand th	e different models for Infromation Retrieval.			
CO2	:	Appricieate the	e technology of Information Retrieval and Web Search			
CO3	:	To understand	the basic principles and working of information technology.			
CO4	:	Describe the r	ble of information technology and information systems in business.			
Reference Bo	oł	ts:				
1. Kenneth C. Education, 14	La th	audon and Jan Global edition	e P. Laudon: Management Information System, Managing the Digital , 2016, ISBN:9781292094007.	Firm, Pearson		
2. Fundament Copyright © ,	al IS	s of Database S BN-10: 013397	ystems, Ramez Elmasri, Shamkant B. Navathe, 7th Edition, 2016, F 0779	Published by Pear	rsc	on,
3. James A. O 978-0072823	'Е 11	Brien, George M 0.	. Marakas: Management Information Systems, Global McGraw Hill,	10th Edition, 202	11	, ISBN:
4. Database M 97800712315	la: 10	nagement Syste)	ems, Raghu Ramakrishnan and Johannes Gehrke, 3rd Edition, 2003	, McGraw-Hill, IS	SB	N:

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pengoluru - buoyaw kamaraka, mola

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based

seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full question from each unit. Rubric for CIE & SEE Theory courses

RUBRIC for CIE RUBRIC for SEE SLNo Content Marks Q. No Contents Marks Quizzes - Q1 & Q2 20 1 Each unit consists of TWO questions of 20 Marks each. Answer FIVE full questions selecting ONE from each unit (1 to 5). Tests - TI & T2 2 40 3 Experiential Learning - EL1 & EL2 40 1 & 2 Unit-1: Question 1 or 2 20 3 & 4 Unit-2: Question 3 or 4 20 **Total Marks** 100 5 & 6 Unit-3: Question 5 or 6 20 7 & 8 Unit-4: Question 7 or 8 20 9 & 10 Unit-5: Question 9 or 10 20 **Total Marks** 100



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I

		SEMESTER: II		
Course Code	: MIS332G		CIE Marks	: 100
Credits I T D	. 3 0 0	MANAGEMENT INFORMATION SYSTEMS	SFF Morles	100
Hours	· 42L	Elective G (Global Elective)	SEE Marks	· 3 Hrs
Facul	ltv Coordinator:	Prof. Vanishree K	SEE D'arations	. 0 1110
	5	UNIT - I		8 Hrs
Overview: Intro Professional So activities, Copin Engineering, Ap management a systems in bus Requirements I	duction: oftware Developr ng with Change, gile Software De nd scaling agile iness today, Per Engineering and	nent, Software Engineering Ethics, Case studies. Softwar Process improvement. The Rational Unified Process. Co velopment: Introduction to agile methods, Agile developm methods. Information Systems in Global Business Today spectives on information systems, Contemporary approa UNIT - II System Modeling:	re Processes: Mo mputer Aided So nent techniques, y: The role of info uches to informat	dels, Process oftware Agile project ormation ion systems 9 Hrs
Software Requi Validation and models, Model systems, How i competitive adv	rements: Functi Change. System driven architect nformation syst vantage, manage	onal and Non-functional requirements. Requirements El a Modeling: Context models, Interaction models, Structur ure. Information Systems, Organizations and Strategy: C ems impact organization and business firms, Using infor ement issues	licitation, Specifi ral models, Beha Drganizations and rmation systems	cation, ivioural d information to gain
		UNIT - III		9 Hrs
Advanced Softw Dependable system Digital Markets	vare Engineering stems: Dependa A15 Availability bigital Goods:	UNIT - IV g: bility properties, Sociotechnical systems, dependable pro and reliability, reliability requirements, Reliability measu E-commerce and the internet, E-commerce-business and	cesses, formal n urements E-com d technology, A C	8 Hrs
		UNIT - V		8 Hrs
Software Mana Project Manage development, P Systems: Syste	gement: ement: Risk Man Project Schedulir ms as planned o mes:	agement, Managing People, Teamwork, Project Planning ng, Agile planning, Estimation Techniques, COCOMO cos organizational change, Overview of systems development	: Software Pricin st modeling. Buil	g, Plan driven ding Information
After going th	rough this cou	se the student will be able to:		
CO1	: Understand an	nd apply the fundamental concepts of software engineeri	ng for informatic	on systems.
CO2	: Develop the ki	nowledge about software engineering for management of	information syst	ems.
CO3	: Interpret and	recommend the use information technology to solve busi	ness problems.	
CO4	: Apply a frame	work and process for aligning organization's IT objectives	s with business s	strategy.
1. Kenneth C. I Education, 14t	o ks: Laudon and Jan h Global edition	e P. Laudon: Management Information System, Managin , 2016, ISBN:9781292094007.	ng the Digital Firm	n, Pearson
2. Ian Sommer 978813176216	ville,— Software 5	Engineering, 9th Edition, Pearson Education, 2013, ISB	N:	
3. W.S. Jawade	ekar: Manageme	nt Information Systems, Tata McGraw Hill, 2006, ISBN:	9780070616349	
4. James A. O' 10th Edition, 2	Brien, George M 011, ISBN: 978	l. Marakas: Management Information Systems, Global M 0072823110	cGraw Hill,	



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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based

seminar/presentation/demonstration (25) adding upto 40 marks.

Scheme of Semester End Examination (SEE) for 100 marks: The question paper will have FIVE questions with internal

choice from each unit. Each question will carry 20 marks. Student will have to answer one full question from each unit. Rubric for CIE & SEE Theory courses

	RUBRIC for CIE	1		RUBRIC for BEE	
SLNo	Content	Marks	Q. No	Contents	Marks
1	Quizzes - Q1 & Q2	20	Each u	nit consists of TWO questions of 20 Marks each. Answ	or FIVE
2	Tests - T1 & T2	40		full questions selecting ONE from each unit (1 to 5).	
3	Experiential Learning - EL1 &	EL2 40	1 & 2	Unit-1: Question 1 or 2	20
	Total	Marks 100	384	Unit-2: Question 3 or 4	20
		STRANS STR	5 & 6	Unit-3: Question 5 or 6	20
			78.8	Unit-4: Question 7 or 8	20
			9 & 10	Unit-5: Question 9 or 10	20
				Total Marks	100



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		SEMESTER: II		
Course Code	MMA331G	STATISTICAL AND OPTIMIZATION METHODS	CIE Marks	: 100
Credits L-T-P	3-0-0		SEE Marks	: 100
Hours	42L	Elective G (Global Elective)	SEE Durations	: 3 Hrs
Faculty Coordin	nator:	Dr. PRAKASH R		
		UNIT - I		9 Hrs
Probability mod and random ve Expected value (MGF), MGF of	Ifs: lels of N randon ctors, Functions s of sums, Prob the sum of inde	n variables, Vector notation, Marginal probability functions, Indepe s of random vectors, Expected value vector and Correlation matrix, ability density function of the sum of two random variables, Momen pendent random variables, Characteristic function and Probability	ndence of random Gaussian random nt Generating Fun generating function	variables vectors, ctions on.
	•• .•			8 Hrs
Estimation: Po and sufficiency likelihood, Baye	oint estimation, , Variance of a p esian estimatior	Estimator and estimate, Criteria for good estimates - unbiasedness point estimator, Methods of point estimation - Method of moments of parameters.	and Method of ma	ximum
		UNIT - III		9 Hrs
Null and altern regions and por and two-sided of samples (F, Chi	ative hypothesis wer, Standard N confidence inter i – square, Z, t -	les of Statistical Inference, Formulation of the problems with examples, Procedure for statistical testing, Type I and Type II errors: level of formal null distribution (Z-test), Z-tests for means and proportions, vals, P-value, Inference about variances, Special tests of significance - test).	ples. Test of hypot f significance, Reje Duality: two-side ce for large and sn	hesis - ection d tests nall
		UNIT - IV		8 Hrs
Artificial Neura variants, Loss f Machine Learr Data mining, H data, Statistica	I Networks: Intr Junctions in arti hing Algorithms Jierarchy Cluste I nature of Big o	oduction - Neuron model, Multilayer perceptions - Back propagation ficial neural networks, Stochastic gradient descent method. UNIT - V s: ring, k-Means Clustering, Distance Metric, Data mining for Big data lata, Support Vector Machines, Statistical Learning Theory, Linear	n algorithm and i a, Characteristics Support Vector M	s 8 Hrs of Big achine,
Kernel function	is and Nonlinea	r Support Vector Machines.		
Course Outcor After going th	nes: rough this cou	rse the student will be able to:		
CO1	Illustrate the formation a	fundamental concepts of statistics, random variables, estimation, in nd machine learning algorithms.	nferential statistic	s, fuzzy
CO2 :	Derive the solution statistics, fuzz	ution by applying the acquired knowledge of random variables, esti by optimization and machine learning algorithms to the problems of	mation, inferentia engineering appli	l cations.
CO3	Evaluate the sworld problem	solution of the problems using appropriate statistical and probabilit as arising in many practical situations.	y techniques to th	ie real
CO4 :	Compile the or optimization g	verall knowledge of statistics, probability distributions and estimati ained to engage in life – long learning.	ion, tests of hypot	nesis and
Reference Boo	ks:			
1. Roy D. Yates ISBN: 9789354	, David J. Good 243455.	man, "Probability and Stochastic Processes", 3rd Edition, An India	n Adaptation, Wile	y, 2021,
2. Douglas C. M & Sons, 2019, 2	Iontgomery and ISBN: 9781119	l George C. Runger, "Applied Statistics and Probability for Engineer 570615.	s", 7th Edition, Jo	ohn Wiley
3. Trevor Hastie Prediction", 2nd	e Robert Tibshir d Edition, Sprin	ani Jerome Friedman, "The Elements of Statistical Learning - Data ger, 2009 (Reprint 2017), ISBN-10: 0387848576, ISBN-13: 978038	Mining, Inference 7848570.	, and
4. Michael Bard 2014, ISBN- 13	on, "Probability 8: 978-1-4822-1	and Statistics for Computer Scientists", 2nd Edition, CRC Press, 410-9.		
5. Shai Shalev- Cambridge Uni	Shwartz and Sh versity Press, 20	nai Ben-David "Understanding Machine Learning: From Theory to A 014, ISBN: 978-1-107-05713-5.	lgorithms", 1st Ec	lition,



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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based

seminar/presentation/demonstration (25) adding upto 40 marks.

	RUBRIC for CIE		RUBRIC for SER			
SLNo	Content	Marks	Q. No	Contents	Marks	
1	Quizzes - Q1 & Q2	20	Each u	sch unit consists of TWO questions of 20 Marks each. Answer FIVE full questions selecting ONE from each unit (1 to 5).		
2	Tests - Tl & T2	40				
3	Experiential Learning - EL1 & EL2	40	1&2	Unit-1; Question 1 or 2	20	
	Total Marks	100	3&4	Unit-2: Question 3 or 4	20	
	60 C		586	Unit-3: Question 5 or 6	20	
			748	Unit-4: Question 7 or 8	20	
			9 & 10	Unit-5: Question 9 or 10	20	
				Total Marks	100	


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SEMESTER: II										
Course Code	:	MME331G	INDUSTRY 4.0	CIE Marks	:	100				
Credits L-T-P	:	3-0-0		SEE Marks	:	100				
Hours	:	42L	Elective G (Global Elective)	SEE Durations	:	3 Hrs				
Faci	ılt	y Coordinator:	Dr. Gopalakrishna H D							
			UNIT - I			8 Hrs				
Introduction, Industry 4.0 Introduction, Industry 4.0, RAMI 4.0 (Reference Architecture Model Industry 4.0), Servitization, Product Service-System (PSS) Industry 4.0 across the Sectors Introduction, Transportation 4.0: Multimodal Transportation Systems, Rail 4.0, Digital Transformation of Railways, Logistics 4.0 (Implications), Fundamentals of Industry 4.0, Introduction, Industry 4.0, RAMI 4.0 (Reference Architecture Model Industry 4.0), Servitization, Product Service-System (PSS) Industry 4.0 across the Sectors Introduction, Transportation 4.0: Multimodal Transportation Systems, Rail 4.0, Digital Transformation of Railways, Logistics 4.0 (Implications) UNIT - II 8 Hrs										
The Concept of	of 1	the IIoT: Moder	n Communication Protocols, Wireless Communication Technologies	, Proximity Netwo	ork	2				
Communicatio	on	Protocols, TCP	/IP, API: A Technical Perspective, Middleware Architecture.			0.11				
Data Analytics Conditioning, Internet of Th Standards, Se Advances in R Sensor Techno	s i Si ing cu cu cu col olo	n Manufacturin mart Remote M gs and New Val urity and Privac potics in the Er ogies, Artificial	ng: Introduction, Power Consumption in manufacturing, Anomaly De achinery Maintenance Systems with Komatsu, Quality Prediction in ue Proposition, Introduction, Internet of Things Examples, IoTs Valu y Concerns. a of Industry 4.0, Introduction, Recent Technological Components o Intelligence, Internet of Robotic Things, Cloud Robotics. UNIT - IV	etection in Air Steel Manufactu 1e Creation Barri f Robots, Advanc	ıriı ier: :ed	ng. s: 9 Hrs				
Additive Manı	ıfa	acturing Techno	plogies and Applications: Introduction, Additive Manufacturing (AM)	Technologies, St	er	. 0				
lithography, 3DP, Fused Deposition Modeling, Selective Laser Sintering, Laminated Object Manufacturing, Laser Engineered Net Shaping, Advantages of Additive Manufacturing, Disadvantages of Additive Manufacturing. Advances in Virtual Factory Research and Applications, The State of Art, The Virtual Factory Software, Limitations of the										
			UNIT - V		Τ	9 Hrs				
Augmented Reality: Definitions and application of AR, VR, MR, Limitations of AR, VR, Hardware devices and Software systems, Technical issues and challenges in AR, Industrial applications, IoT and the Need for Data Rationalization Internet of Things (IoT), Internet of Things Vision, Internet of Things (IoT) Frameworks, Architecture of Internet of Things (IoT), Visualizing the Internet of Things (IoT), Essential Technologies of the Internet of Things (IoT), Key Technologies Involved in Internet of Things, Enablers of IoT, Collaborative Operations , Training. Smart Factories: Introduction, Smart factories in action, Importance, Real world smart factories, The way forward. A Roadmap: Digital Transformation, Transforming Operational Processes, Business Models, Increase Operational Efficiency, Develop New Business Models.										
Course Outco	m	ies:								
CO1	:	Understand th	e opportunities, challenges brought about by Industry 4.0 for benef	its of organizatio	ns	and				
CO2	:	Analyze the eff	ectiveness of Smart Factories. Smart cities, Smart products and Sm	art services						
CO3	:	Apply the Indu	strial 4.0 concepts in a manufacturing plant to improve productivit	v and profits						
CO4	:	Evaluate the e	ffectiveness of Cloud Computing in a networked economy) F						
Reference Bo	01	ks:								
1. Alasdair Gi	lcl	nrist, Industry	4.0 The Industrial Internet Of Things. Apress Publisher. ISBN-13 (pl	ok): 978-1-4842-	20	46-7				
2. Alp Ustund 978-3-319-57	ag 86	g, Emre Cevikca	n, Industry 4.0: Managing The Digital Transformation, Springer, 20	18 ISBN						
3.Ovidiu Verm worlds, Rivers	nes P	san and Peer Fr ublishers, 2010	iess, Designing the industry - Internet of things connecting the phy 5 ISBN 978-87-93379-81-7	sical, digital and	vi	rtual				
4.Christoph J Logistics, Spri	ar ing	n Bartodziej, Th ger Gabler, 201	e concept Industry 4.0- An Empirical Analysis of Technologies and A 7 ISBN 978-3-6581-6502-4.	Applications in P	roc	luction				



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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based

seminar/presentation/demonstration (25) adding upto 40 marks.

_	RUBRIC for CIE		RUBRIC for SEE					
SLNo	Content	Marks	Q. No	Contents	Marks			
1	Quizzes - Q1 & Q2	20	Each u	ch unit consists of TWO questions of 20 Marks each. Answ				
2	Tests - T1 & T2	40		full questions selecting ONE from each unit (1 to 5).				
3	Experiential Learning - EL1 & EL2	40	1&2	Unit-1: Question 1 or 2	20			
	Total Marks	100	3&4	Unit-2: Question 3 or 4	20			
			586	Unit-3: Question 5 or 6	20			
			748	Unit-4: Question 7 or 8	20			
			9 & 10	Unit-5: Question 9 or 10	20			
				Total Marks	100			



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	1.1							T		
Course Code	:	MVE431L	Analo	g Lavoi	ıt Design Lab	CIE Mark	S	: 50		
Credits L-T-P	:	1 - 0 - 1		B		SEE Marl	٢S	:	50	
Hours	:	28P	(Codi	ing / Ski	ill Laboratory)	SEE Dura	ations	:	3 Hrs	
Fa	culty	Coordinator:	Dr. Arun Kumar F	.Chavai	ı					
									8 Hrs	
1. Design a s	tand	ard cell layout	of Inverter and AN	D gate 1	using 45nm CMOS technolo	ogy.			<u> </u>	
2. Design a s	tand	ard cell layout	of AOI/OAI using	45nm C	MOS technology					
3. Design a c	urre	nt mirror circu	it and perform pos	t layout	simulation using 45nm CM	IOS techn	ology.			
4. Design a s	ingle	e stage differen	tial amplifier and p	perform	post layout simulation usin	g 45nm C	MOS			
technology.		_								
5. Design a b	and	gap reference	circuit and perform	1 post la	yout simulation using 45nr	n CMOS te	echnolo)gy	у.	
6. Designs a	tive s	stage single en	ded VCO and perfo	orm post	a layout simulation using 45	onm CMOS	S techn	ol	ogy.	
7. Design a 6	T Bi	t cell circuit ar	id perform post lay	out sim	ulation using 45nm CMOS	technology	/. 			
o. Design a t	vo si	lage op-amp a	nd periorni post lay	out sin	iulation using 45mm CMOS	technolog	у.			
Course Outc	ome	s:	-115	nai	73 0 18)				
After going th	roug	gh this course	the student will be	able to:	CH Oak A					
CO1 : Apply the knowledge in layout design concepts such as antenna effect, latch-up,										
Electro-Migration, IR drop and self heat.										
CC	CO2 : Analyze the challenges in deep sub micron process using well proximity effect, LOD and									
		Shallow trencl	n isolation.							
CO3 : Verify chip layout design using all physical verification concepts and tools.										
CC	94 :	Design optimiz	zed analog circuit la	ayouts o	of VCO, Memory, BGR and of	current mi	rror.			
		100								
Scheme of C	onti	nuous Interna	al Evaluation (CIE	- Labora	atory) : Only LAB Course	30 + 10 + 1	10 = 50). [Гһе	
Laboratory se	essio	n is held every	week as per the ti	metable	and the performance of the	e student i	s evalu	at	ed in	
every session	. The	e average of m	arks over number o	of experi	ments conducted over the v	weeks is co	onsider	ed	for 30	
Marks i.e (La	o Re	port, Observat	10n & Analysis). In	e stude	nts are encouraged to imple	ement add	Itional i	In	novative	
Test) This ac	de ta	o 50 Marks	s). At the end of th	le semes	ster a test is conducted for i	to marks (Lau			
Scheme of S		ster End Even	nination (SFF In	horator	w) : Only LAB Course 40 +	10 - 50 8	tudente	<u> </u>	will be	
evaluated for	Writ	te-up Experim	ental Setup Exper	riment (Conduction with Results An	10 -30. З alvsis & Г	liacijasi	s v ini	ns for	
40 Marks and	1 Viv	a will be cond	ucted for 10 Marks	adding	to 50 Marks.	ary 515 @ L	1000000	101	10 101	
	-		Only LAB	Course	s with 50 Marks					
		R	JBRIC FOR CIE		RUBRIC F	OR SEE				
	SI.No		Content	Marks	Content		Marks			
		Write Up, Set	up, Conduction			~				
	1	Results, Anal	ysis & Discussions	30	1. Write Up, Setup, Conduct	tion	100			
	100	Innovative Ex	periment/Concept	10	2. Results, Analysis & Discu	issions	40			
	2	Design & Imp	lementation	10		AUTORO PORE				
	3	Laboratory In	ternal	10	Viva Voce		10			
	jaten) F	1	Total Marks	50	The second se	atal Marke	50			
	_		1 You mot ha	44		and this is	200			

SEMESTER: II



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SEMESTER: II									
Course Code	:	MHS131T	PROFESSIONAL SKILL	CIE Marks	:	50			
Credits L-T-P	:	2-0-0	DEVELOPMENT-T	SEE Marks	:	50			
Hours	:	28L	Common Course to all M.Tech Programs	SEE Durations	:	2 Hrs			
Facul	ty	Coordinator:	Dr. C.Bindu Ashwini						
UNIT - I 4 Hrs									
Communication Skills: Basics of Communication, Personal Skills & amp; Presentation Skills – Introduction, Application, Simulation, Attitudinal Development, Self Confidence, SWOC analysis. Resume Writing: Understanding the basic essentials for a resume, Resume writing tips Guidelines for better presentation of facts. Theory and Applications.									
			UNIT - II			8 Hrs			
Simple equations – Linear equations, Elimination Method, Substitution method, Inequalities. Reasoning – a. Verbal - Blood Relation, Sense of Direction, Arithmetic & amp; Alphabet.b. Non- Verbal reasoning - Visual Sequence, Visual analogy and classification. Analytical Reasoning - Single & amp; Multiple comparisons, Linear Sequencing. Logical Aptitude, - Syllogism, Venn-diagram method, Three statement syllogism, Deductive and inductive reasoning. Introduction to puzzle and games organizing information, parts of an argument, common flaws, arguments and assumptions. Verbal Analogies/Aptitude – introduction to different question types – analogies, Grammar review, sentence completions, sentence corrections, antonyms/synonyms, vocabulary building etc. Reading Comprehension, Problem Solving,									
		1 20	UNIT - III			6 Hrs			
Interview Skills Conversational technical interv on Stress Inter	Interview Skills: Questions asked & amp; how to handle them, Body language in interview, and Etiquette – Conversational and Professional, Dress code in interview, Professional attire and Grooming, Behavioral and technical interviews, Mock interviews - Mock interviews with different Panels. Practice on Stress Interviews, Technical Interviews, and General HR interviews								
		1.0	UNIT - IV			5 Hrs			
Interpersonal a maturity mode discussion(Ass	ino 1, o ert	d Managerial Sl decision makin tiveness) and p	kills: Optimal co-existence, cultural sensitivity g ability and analysis for brain storming; Grov resentation skills;	y, gender sensitivit up	y;	capability and			
		1.00	UNIT - V			5 Hrs			
Motivation: Sel speech with co ability.	f-r nc	notivation, grou Iusion. (Examp	ap motivation, Behavioral Management, Inspi les to be cited). Leadership Skills: Ethics and	rational and motiv Integrity, Goal Set	ati ttir	ional ng, leadership			
Course Outcon After going th	me ro	es: ugh this cours	e the student will be able to:						
CO1	:	Develop profes	sional skill to suit the industry requirement.						
CO2	:	Analyze proble	ms using quantitative and reasoning skills						
CO3	:	Develop leader	ship and inter personal working skills.						
CO4	:	Demonstrate v	erbal communication skills with appropriate	body language.					
Reference Boo	k	s:							
1. The 7 Habits ISBN: 0743272	s o 245	of Highly Effecti 55	ve People, Stephen R Covey Free Press, 2004	Edition,					
2. How to win friends and influence people, Dale Carnegie General Press, 1st Edition, 2016, ISBN: 9789380914787									



3. Crucial Conversation: Tools for Talking When Stakes are High, Kerry Patterson, Joseph Grenny, Ron Mcmillan 2012 Edition, McGraw-Hill Publication ISBN: 9780071772204

4. Ethnus, Aptimithra: Best Aptitude Book ,2014 Edition, Tata McGraw Hill ISBN: 9781259058738

Phase *	Activity
Ι	Test 1 is conducted after the completion of 9 hours of training programme (3 Classes). Question paper will have two parts. Part A will be Quiz for 10 Marks and Part B for 50 Marks Descriptive answers.
II	Test 2 is conducted after the completion of 18 hours of training programme (6 Classes). Question paper will have two parts. Part A will be Quiz for 10 Marks and Part B for 50 Marks Descriptive answers. Total test marks will be reduced to 30 Marks and Total Quiz marks will be 20 Marks. Final CIE would be 50 Marks
	CIE marks 20 Quiz + 30 Test = 50 Marks
Semester En	d Examination: SEE is conducted for 50 Marks for a duration of 2 hours.





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			SEMESTER: III				
Course Code	:	MVE361T	Algorithms for VLSI Design Automatio	n	CIE Marks	:	100
Credits L-T-P	:	3-1-0			SEE Marks	:	100
Hours	:	42L+28T	Professional Core - 5		SEE Durations	:	3 Hrs
Facu	lt	y Coordinator:	Dr. Shilpa D.R				
			UNIT - I				9 Hrs
Architectural le scheduling prob sequencing mod	eve bl de	el design &Scho ems, Schedulir els, Scheduling	duling Algorithms:Introduction to architectura g without and with resource constraints, Sche pipelined circuits, Resource sharing and bindi	al level o eduling a ing.	design, A model fo algorithms for ext	or	nded
UNIT - II							
Data Structure Algorithms, Bas Group migratio	a si n	nd Basic Algor c Data structur Algorithms, Si	hms: Basic Terminology, Graph Search Algories. Partitioning: Problem Formulation, Classific structure and evolution algorithm, ot	ithms, (ication o ther par	Computational Ge of Partitioning Alg titioning algorithr	201 301 118	netry ithms,
		1.51	UNIT - III				8 Hrs
Floor Planning	a	nd Pin Assignm	ent: Problem formulation, classification, Const	traint b	ased, Integer		
Problem formul	la [:]	sed, rectangula tion, Classifica	on, Simulation based, Partitioning based Place	ing algoi	rithms. Placemen Algorithms	t:	
			UNIT - IV				8 Hrs
path-based Algo single Layer rou	or Jt	rithms, Steiner ing, General riv	ree-based Algorithms Detailed Routing: Proble er routing, Single row routing	em form	nulation, Classific	at	ion
		1.00	UNIT - V	<u> </u>			8 Hrs
Channel, Clock system, delay c MMM Algorithm propagation alg	al ns	and Power Rout lculation for clo s, Geometric ma rithm.	ng: Two-layer channel routing Algorithms, De ck trees, Problem formulation, Clock routing A tching based Algorithms, Introduction to comp	sign con Algorithm paction	nsiderations for th ms, H-tree based , shadow	he Al	clocking gorithms,
		in the second second		100			
Course Outcon After going thro	n ou	es: gh this course	he student will be able to:				
CO1	:	Analyze each s	tage of VLSI design flow to develop a CAD tool	l for phy	vsical design.		
CO2	:	Apply design l	nowledge to develop algorithms for VLSI desig	n auton	nation.		
CO3	:	Evaluate the a	go <mark>rithms for</mark> optimizing VLSI design with resp	pect to s	peed, power and	ar	ea.
CO4	:	Create an opti	nized VLSI IC design technique using various	algorith	ims.		
				1.			
Reference Boo	k	s		1			
1. Synthesis an 0070163332	ıd	Optimization of	Digital Circuit, 1994, Giovanni De Micheli, M	IcGraw-	Hill, ISBN: 10-		
2. Algorithms fo 0-7923-8393-1	or	VLSI Physical	Design Automation, N.A. Sherwani, 2002, Kluv	war Aca	demic Publishers	, I	SBN:
3. An Introduct	ic	on to VLSI Phys	cal Design, M Sarraf Zadeh, C K Wong, 1996,	McGrav	w Hill, ISBN:0070)5′	71945
4. Algorithms for	or	VLSI Design A	tomation, S.H. Gerez, 1998, John Wiley & So	ons, ISE	3N: 978-0-471-98	48	39-4



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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

RUBRIC for CIE			RUBRIC for SEE						
SLNo	Content	Marks	Q. No	Contents	Marks				
1	Quizzes - Q1 & Q2	20	Each u	n unit consists of TWO questions of 20 Marks each. Answer FIVE					
2	Tests - T1 & T2	40		full questions selecting ONE from each unit [1 to 5].					
3	Experiential Learning - EL1 & EL2	40	182	Unit-1: Question 1 or 2	20				
	Total Maria	100	384	Unit-2: Question 3 or 4	20				
			586	Unit-3: Question 5 or 6	20				
			788	Unit-4: Question 7 or 8	20				
			9 & 10	Unit-5: Question 9 or 10	20				



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SEMESTER: III									
Course Code	:	MVE337D1	VLSI	Testing		CIE Marks	: 10	00	
Credits L-T-P	:	3-1-0				SEE Marks	: 10	00	
Hours	:	42L+28T	Elective D (Pro	fessional Elective)		SEE Durations	: 3	Hrs	
Facu	ılty	y Coordinator:	Prof. Sujatha Hiremath						
			UNIT - I				9	Hrs	
Testing Philosophy, yield and Reject ratio. Fault Modeling- Functional Testing, Structural Testing, Types of Fault Models, Stuck-at Faults, Bridging Faults, cross point faults, Fault Equivalence, Fault Dominance and checkpoint theorem.									
			UNIT - II				9	Hrs	
Combinational Methods, Roth Controllability, Probability-bas	C 's O sec	ircuit Test Gen D- Algorithm, F bservability, ar l Testability An	ration: A Basic ATPG Alg DDEM. Sequential ATPG 1 SCOAP measures for c lysis.	gorithm, Boolean Diffe : Time Frame Expans ombinational and seq	erence, in. Test uential	Path Sensitizatior ability Measure – circuits,	1		
			UNIT - III		6		8	Hrs	
Fault Simulation- Fault Simulation algorithm- Serial, Parallel, Deductive and Concurrent Fault Simulation, Comparison of fault simulation. Design for Testability- Ad-hoc, Structured DFT- Scan method, Scan Design Rules, Overheads of Scan Design, partial scan methods, multiple chain scan methods.									
		1	UNIT - IV	11/2	~		8	Hrs	
Built in self-tes Architectures: Standard - TAF	st: Wi P C	BIST Design ru ithout scan cha Controller, Test	es, Test pattern generat ns, with scan chains an nstructions, IEEE 1149.	ion for BIST, Output i d using Register recor 1 standard	respons nfigurat	e analysis, BIST ion. Boundary Sc	an		
		10	UNIT - V		1		8	Hrs	
Memory Testin BIST. Fault Dia Circuits Course Outcor After going thro	g d agi me	& BIST: Introdu nosis Logical Le es: gh this course	rel Diagnosis, Diagnosis	ult models & Test Algorithms by UUT reduction, Fa	orithms uult Dia	s, March Test. Mer gnosis for Combir	nor	y onal	
CO1	:	Apply the know	ledge of testing, fault me	odeling & fault covera	ge.				
CO2	:	Analysis of var Digital circuits	ous fault simulation me	hods, different testab	oility an	alysis and self tes	ting	۲ ۲	
CO3	:	Develop an alg	rithm for fault detection	and analysis of scan	design	and its limitation	s.		
CO4	CO4 : Design of different ATPG, and knowledge about different methods of BIST and Memory BIST associated with testing.								
Defense De	1-	~							
1. M. L. Bushn Circuits, Kluwe	eller	s l and V. D. Agra Academic Publ	wal, Essentials of Electro hers, 2000, ISBN:0-792	onic Testing for Digita 3-7991-8, 2	l, Memo	oryand Mixed-Sig	nal '	VLSI	
2. L. T. Wang, ISBN-13: 978-0	C.)-1	W. Wu, and X. 12-370597-6	Wen, VLSI Test Principle	s and Architectures, 1	Morgan	Kaufmann, 2006	,		
3. Parag.K.Lala	ı, 1	Digital Circuit 7	esting and Testability, A	cademic Press					
4. M. Abramov Science Press,	ici 19	, M. A. Breuer, 990, ISBN: 0-71	nd A. D. Friedman, Dig 57-8179-4	tal Systems Testing a	ndTesta	able Design, Com	pute	r	



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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

RUBRIC for CIK			-	1	RUBRIC for SEK			
SLNo	Content		Marks	Q. No	Contents	Marks		
1	Quizzes - Q1 & Q2	1 80	20	Each u	mit consists of TWO questions of 20 Marks each. Answ	ver FIVI		
2	Tests - T1 & T2	1. So	40		full questions selecting ONE from each unit [1 to 5].			
3	Experiential Learning	EL1 & EL2	40	1 & 2	Unit-1: Question 1 or 2	20		
		Total Marks	100	3&4	Unit-2: Question 3 or 4	20		
				586	Unit-3: Question 5 or 6	20		
				788	Unit-4: Question 7 or 8	20		
				9 & 10	Unit-5: Question 9 or 10	20		



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				SEMESTER: III				
Course Code	:	MVE337D2	High	Speed Digital Design		CIE Marks	:	100
Credits L-T-P	:	3-1-0				SEE Marks	:	100
Hours	:	42L+28T	Elective	e D (Professional Elective)		SEE Durations	:	3 Hrs
Facu	ılt	y Coordinator:	Dr. Srividya P					
			U	NIT - I				9 Hrs
Introduction to Capacitance and geometry and e transmission li	h nd ele	igh speed digit. inductance effective ctrical properti es, lossy RLC tr	l design: Frequen cts, high speed pr s of wires, Electri nsmission lines a	cy, time and distance issue coperties of logic gates, spec cal models of wires, transm and special transmission lin	es in digi ed and p nission li nes.	tal VLSI design. ower. Modeling of nes, lossless LC	w	ires,
			UN	NIT - II				9 Hrs
Power distribu bypass capacit power supply r analysis,cross	tic tor noi ta	on and Noise: F rs and symbiot ise, crosstalk a lk and Ground	ower supply netw c bypass capacito d inter symbol in pounce.	ork, local power regulation ors. Power supply isolation terference. Power distributi	n, IR dro Noise s .on on ch	ps, area bonding. sources in digital aips, Transient Por	sy we)n-chip /stems, er
			UN	IT - III	60			8 Hrs
Signaling conv media, signalir terminations, t	en 1g ra	tion and circui over RC interco nsmitter and re	s: Signaling mode nnect, driving loss ceiver circuits.	s for transmission lines, si sy LC lines, simultaneous b	gnaling o pi-directi	over lumped trans onal signaling	mi	ission
		1	UN	IT - IV	C N =			8 Hrs
Gate Logic, DCYS Logic with the Pass Gate, Complementary Pass Gate Logic, Swing-Restored Pass Gate Logic, Energy-Economized Pass Transistor Logic. (ii) Clocked Logic Styles: Single-Rail Domino Logic: Domino CMOS, Multiple Output Domino Logic, Compound Domino Logic, Noise Tolerant Precharge								
			UN	NIT - V				8 Hrs
Latching Strat Design, Latch Double-Edge-T Differential Lat	eg In `rig	ies: Basic Latc pplementation T ggered Flip-Flop n, Differential F	Design: Storage atching single-en s Differential Logi p-Flops	Elements, Static and Dyn ded logic: pseudo Inverter c: DCVS Latches, Static Ra	namic La Latch, 1 am Latch	tches, Latch, Noi Frue Single Phase es, Ratio Insensiti	se Cive	/Robust Clocking,
Course Outco	m	es:						
After going thr	ou L.	gh this course	he student will be	able to:				
C01		Analyze the sp digital systems	aracteristics of tra	ansmission lines, Power sup	pply netv	vork and Noise so	ur	ces in
CO3	:	Apply different	Clocked & non cl	ocked digital Logics in desi	gns			
CO4	· :	Evaluate the p	erformance of vari	ious transmission lines and	l digital o	circuits.		
Reference Boo 1. William S. D 0-521-59292-5 2. Kerry Berns Nowak, Norma	ok Dal 5. tei n	s ly & John W. P n, Keith M. Car J. Rohrer., "Hig	ulton, "Digital Sy rig, Christopher M 1 Speed CMOS De	stems Engineering", Camb M. Durham, Patrick R. Han esign Styles", Kluwer Acade	ridge Un sen, Dav emic Pub	iversity Press, 199 id Hogenmiller, Ed lishers in 1999, IS	98. dw SB	. ISBN 7ard J. BN
978-1-4613-75 3. Masakazu S 978-02016348	549 hc 39	9-4. oji, "High Speed).	Digital Circuits",	Addison Wesley Publishing	Compar	ny, 1996. ISBN		



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4. Howard Johnson & Martin Graham, "High Speed Digital Design" A Handbook of Black Magic, Prentice Hall PTR, 1993.

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

<u> </u>	RUBRIC for CIE	-	RUBRIC for SEE					
SLNo	Content	Marks	Q. No	Contents	Marks			
1	Quizzes - Q1 & Q2	20	Each u	ch unit consists of TWO questions of 20 Marks each. Answer FIVE				
2	Tests - TI & T2	40		full questions selecting ONE from each unit (1 to 5).				
з	Experiential Learning - EL1 & EL2	40	182	Unit-1: Question 1 or 2	20			
	Total Marks	100	384	Unit-2: Question 3 or 4	20			
1	and a second of the second of	·	586	Unit-3: Question 5 or 6	20			
			788	Unit-4: Question 7 or 8	20			
			9 & 10	Unit-5: Question 9 or 10	20			
				Total Marks	100			



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		SEMESTER: III						
Course Code	: MVE337D3	RFIC Design	CIE Marks	: 100				
Credits L-T-P	: 3-1-0	.	SEE Marks	: 100				
Hours	: 42L+28T	Elective D (Professional Elective)	SEE Durations	: 3 Hrs				
Facu	lty Coordinator:	Dr. Chinmaye R						
		UNIT - I		9 Hrs				
Basic concepts in RF design - Units in RF design, Nonlinearity and Time Variance, Effects of nonlinearity – harmonic distortion, gain compression – 1 dB compression point, desensitization, blocking, cross modulation, intermodulation – third intercept point, cascaded nonlinear stages – IM spectra in a cascade. Noise in RF circuits - Representation of noise in circuits – input referred noise, Noise figure, Noise figure of cascaded stages, Noise figure of lossy circuits, Sensitivity, dynamic range – spurious free dynamic range (SFDR).								
		UNIT - II	5 ()	9 Hrs				
Transceiver architectures – channel selection and band selection, Heterodyne – constant LO and constant IF downconversion, problem of image, image rejection vs channel selection, dual IF topology, Homodyne – simple homodyne and homodyne with quadrature down conversion, issues in homodyne receivers, Image Reject – Hartley & Weaver architecture. Transmitter architectures - Direct conversion and two-step transmitters. Review of two port parameters and their significance. Nanoscale MOSFETs - Parasitic resistances (Rs, Rd, Rg), parasitic capacitances (Cgs, Cgd,), simplified and extrinsic small-signal models. High-frequency figures of merit: fT and fMAX								
	1	UNIT - III		8 Hrs				
conversion, basic matching networks- L, Pi-match networks – design example. Low noise Amplifier - Performance parameters, Problem of Input matching, CS stage with inductive load, Cascode CS stage with inductive degeneration (MOSFET circuits only), Noise figure calculation, Amplifier bandwidth extension techniques, Millimeter Wave LNAs UNIT - IV 8 Hrs Mixer - Performance parameters, Mixer noise figures, single balanced and double balanced (active and passive) – working (MOSFET circuits only), Millimeter Wave Mixers. Oscillators - Performance parameters, Feedback view and one port view of oscillators, Cross coupled oscillator, three point oscillators, (MOSFET circuits only),								
		UNIT - V		8 Hrs				
Phase Locked I simple PLL, Typ and Down Skew Course Outcon After going three CO1 CO2 CO3 CO4	Loops - Basic com pe II PLLs - PFD, w and Width Miss nes: ough this course : Investigate the : Analyze CMOS : Design and im : Evaluate the c	cepts - Phase detector, Type I PLL, Dynamics of simp charge pump, charge pump PLL, PFD/CP Nonidealiti match, Charge Injection and clock feedthrough. the student will be able to: e functionality of a typical RF system. S circuits and its impact on Radio frequency and Milli plement various circuit blocks for RF transceiver cha lifferent performance parameters used in RF design.	le PLL, Drawbacks es (concepts only) 	of – Up 				
Reference Boo	ks							
1. Behzad Raza	vi, "RF Microelec	tronics", 2nd Edition Pearson Education, 2012, ISB	N : 13:9780137134	731				
2.Thomas H Le University Pres	e, "The Design c s, 2004, ISBN : 9	f CMOS Radio Frequency Integrated Circuits",2nd Ec 9780511817281	lition, Cambridge					
3. John Rogers 1-58053-502-x	,CalvinPlett, "Ra	dio Frequency Integrated Circuits Design", Artech Ho	use, 2003, ISBN :					
4. S. Voinigescr 1st edition, 202	u, ["] High-Frequen 13, ISBN : 978-0	cy Integrated Circuits", The Cambridge RF and Micro 521873024	wave Engineering	Series,				



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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

	RUBRIC for CIE	_		RUBRIC for SEE	
SLNo	Content	Marks	Q. No	Contents	Marks
1	Quizzes - Q1 & Q2	20	Each u	mit consists of TWO questions of 20 Marks each. Answ	er FIVE
2	Tests - T1 & T2	40		full quastions selecting ONE from each unit (1 to 5).	
3	Experiential Learning - EL1 & EL2	40	1&2	Unit-1: Question 1 or 2	20
1	Total Marks	100	344	Unit-2: Question 3 or 4	20
	125		586	Unit-3: Question 5 or 6	20
			78.8	Unit-4: Question 7 or 8	20
			9 & 10	Unit-5: Question 9 or 10	20
				Total Marks	100



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				SEMESTE	R: III			
Course Code	:	MVE337D4	Signal Pro	ocessing & ML	on Microcontrollers	CIE Marks	:	100
Credits L-T-P	:	3-1-0	_	_		SEE Marks	:	100
Hours	:	42L+28T	Ele	ective D (Profess	sional Elective)	SEE Durations	:	3 Hrs
Facul	lty	Coordinator:	Prof. Maheno	dra B M				
				UNIT - I				9 Hrs
Introduction: AI TI Math and DS Stereo Codecs I Discovery, WM5 Demonstration	RN SP np 510 of	A Profiles, ARM Libraries Anal out and Outpu 02 Codecs Prog Polling, Interr	Cortex M Fa og Input and , Data comm gramming Ex upts and DM	mily, Digital Si Output Digital unication using amples: Configu A based IO. Fix	gnal Controller Vs Digit Signal Processing Syste g Polling, Interrupts, DM uration of Codecs, Real ed point tool box in MA'	al Signal Processor, em, Data Representa MA Practice: STM32 Time Input and Out TLAB.	C ati F ² tp	CMSIS, Ion, 107 ut,
				UNIT - II				9 Hrs
Sampling, Reco Radix-2 Practice WM5102 Antial Real-Time, Spec	ns e: ia: ctr	Struction and A Sampling and sing Filter, Dis al Leakage	liasing - Time Aliasing – Ge crete Fourier	e and Frequenc nerating Sinuso Transform of a UNIT - III	y Domains, Fast Fourie bids of Arbitrary Freque Sequence of Real Num	er Transform - Deriv ncy, Step Response bers, FFT of A Signa	at o: 1 i	f the in 8 Hrs
and Random Fo	ve: pre	ests (Signal pro	cessing Pers	pective), Introdu	iction to TinyML, Tenso	r Flow, Keras.	S10	on tree
			67	UNIT - IV	128	·		8 Hrs
Model & Applica chain, Building	ati aı	on developmer nd training an	t: ML/ DL w appl <mark>ic</mark> ation, l	ork flow, Buildi Deployment on	ng and training a mode Microcontrollers.	l, Machine Learning	; T	`ool
		1.5		UNIT - V				8 Hrs
Tensor flow Lite Optimizing Ene	e fo rg	or Microcontro y Usage, Optin	lers: Building izing Model a	g and training t and Binary Size	he models for applicatic , Debugging, Privacy, S	ons, Optimizing Late ecurity and Deployr	en ne	cy, ent.
After going thro	ne ug	s: gh this course	he student w	vill be able to:				
CO1	:	Identify differe	nt blocks of s	signal processin	g chain a <mark>nd cons</mark> tructs	of tiny ML.		
CO2	:	Evaluate the a processing and	chitecture of ML applicat	f ARM CPUs to a ions.	identify their suitability	for realizing signal		
CO3	:	Realize signal use of software	processing op libraries.	perations and M	L applications on differ	ent architectures by	7 r	naking
CO4	:	Design and an	alyze the app	lications to real	ize on embedded develo	opment boards.		
Boforoneo Boo	1-0		1.5					
1.Donald S Rea 118-85904-9	д у,	Digital Signal	Processing or	n using ARM Co	ortex M4, 2016, John W	ïley & Sons, ISBN 9	78	3-1-
2. ARM-based I Program, ISBN-	Dig 1	gital Signal Pro 0: 9780470930	cessing Lab-i 863	n-a-Box, ARM U	University Program, Wo	rld Wide Education		
3. Technical ref	er	ence manual fo	r ARM proce	ssor cores inclu	iding Cortex M, Wolfson	n PI Codec, Keil Prod	lu	cts
4. Pete Warden, Microcontrollers	, T s,	inyML: Machir O'Reilly Media	e Learning w 1st edition,	vith TensorFlow ISBN-10 : 1492	Lite on Arduino and Ul 052043, ISBN-13 : 978	tra-Low-Power -1492052043		



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Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

RUBRIC for CIE				RUBRIC for SKE			
SLNo	Content	Marks	Q. No	Contents	Marks		
1	Quizzes - Q1 & Q2	20	Each u	mit consists of TWO questions of 20 Marks each. Answ	mr FIVE		
2	Tests - TI & T2	40		full questions selecting ONE from each unit (1 to 5).	<u>.</u>		
3	Experiential Learning - EL1 & EL2	40	182	Unit-1: Question 1 or 2	20		
	Total Marka	100	3&4	Unit-2: Question 3 or 4	20		
			586	Unit-3: Question 5 or 6	20		
			748	Unit-4: Question 7 or 8	20		
			9 & 10	Unit-5: Question 9 or 10	20		
				Total Marks	100		



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			SEMESTER: III			
Course Code	:	MVE337D5	MEMS and Smart Systems	CIE Marks	:	100
Credits L-T-P	:	3-1-0	-	SEE Marks	:	100
Hours	:	42L+28T	Elective D (Professional Elective)	SEE Durations	:	3 Hrs
Facu	ılty	y Coordinator:	Dr. Ramavenkateswaran N			
			UNIT - I			9 Hrs
Introduction to and system, In Evolution of m Commercial pr Modelling: Sca electrostatic fo effects in the o	o M teg icr od lin rce pti	licro and Smar grated Microsys o-manufacturi ucts. g issues, Scalin es, scaling in el ical domain, sc	t Systems: Introduction, Microsystem vs MEMS, Sma stems, Application of Smart Materials and Microsyste ng. Multi-disciplinary aspects. Applications areas. ng in geometry, Scaling in rigid body dynamics, scalin ectromagnetic forces, scaling in electricity, scaling in aling in biochemical phenomena	ert Materials, struc ems. Feynman's vis ng in fluid dynamics. so		n, ling
	-	· · · ·	UNIT - II			9 Hrs
Micro and Sma systems. Senso accelerometer, micro relay, pio sensors, Electr	ors pi ezo	Devices and S s: silicon capac ezo-resistive pro- electric based tatic Comb driv	ystems: Principles Definitions and salient features of itive essure sensor, Actuators: silicon micro-mirror arrays inkjet print head, electro-thermal actuator. portable we, Microsystems at Radio frequency	sensors, actuators s, magnetic blood analyzer, fit	s, s	and r optic
		1.1	UNIT - III			8 Hrs
deposition, etc. bonding based Electronics Cir Differential Am Conversion, Pr	hii pi cu ipl ac	ng (wet and dry rocess flows. its for Micro an ifier, Instrumentical Signal Con-), wafer-bonding, and metallization, Silicon microma UNIT - IV Ind Smart Systems: Electronic Amplifiers, Signal Conc Intation Amplifier, Wheatstone Bridge, Phase Locked I Inditioning Circuits: Differential Charge Measurement personance of the second	chining: surface, b litioning Circuits: .oop,Analog to Digi , Switched Capacit	ul ita	k , 8 Hrs 1
circuits, circui	.15	ior inequency i	UNIT - V			8 Hrs
Electronics, Cipackaging, Typsensors, accele	rcu es ero	uits and Packa of Microsyster meters, micro	ging: Micro Systems Packaging, objectives and specia n Packages ,Packaging Technologies Case study of de heater.	l issues in micro s evices Cantilevers,	ys Pi	tem ressure
After going thr	me נור	es: gh this course	the student will be able to:			
	1.	Describe work	ing principles and packaging techniques in MFMS at	nd smarts stems		
CO2	•	Analyze variou	is sensors and actuator circuits for MEMS and smart	svstems.		
C03		Design of elect	ronic circuits sensor and actuators for MEMS and s	mart systems		
CO4	:	Evaluate the p	performance of electronic circuits for micro and smart	systems.		
Reference Boo) k	S				
1.MEMS & Mic	ro	systems: Desig	n and Manufacture, Tai-Ran Tsu, Tata Mc-Graw-Hill	.ISBN- 13:9780070	04	87093
2. Micro and S 978812652715	ma 51	art Systems, K.	J.Vinoy, G.K.Ananthasuresh, S.Gopalakrishnan, K.N	Bhat, Wiley India	, I	SBN:
3. Microsystem 0-7923-7246-8	is 3.	Design, S. D. S	enturia, Kluwer Academic Publishers, Boston, USA,	2001, ISBN		



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4. Analysis and Design Principles of MEMS Devices, Minhang Bao, Elsevier, Amsterdam, Netherlands, ISBN 0-444-51616-6.

Scheme of Continuous Internal Evaluation (CIE): 20 + 40 + 40 = 100

QUIZZES: Quizzes will be conducted in online/offline mode. Two quizzes will be conducted & Each Quiz will be evaluated for 10 Marks. The sum of two quizzes will be the Final Quiz marks.

TESTS: Students will be evaluated in test, descriptive questions with different complexity levels (Revised Bloom's Taxonomy Levels: Remembering, Understanding, Applying, Analyzing, Evaluating, and Creating). Two tests will be conducted. Each test will be evaluated for 50 Marks, adding upto 100 Marks. Final test marks will be reduced to 40 Marks.

EXPERIENTIAL LEARNING: Students will be evaluated for their creativity and practical implementation of the problem. Case study-based teaching learning and Program specific requirements (15), Video based seminar/presentation/demonstration (25) adding upto 40 marks.

1	RUBRIC for	CIK	_	-	RUBRIC for SEE	
SLNo	Content	110000	Marks	Q. No	Contents	Marks
L	Quizzes - Q1 & Q2	1.50	20	Each u	mit consists of TWO questions of 20 Marks each. Answ	wer FIVE
2	Tests - T1 & T2	1-22	40		full questions selecting ONE from each unit [1 to 5].	105
3	Experiential Learning	EL1 & EL2	40	182	Unit-1: Question 1 or 2	20
	- 204 	Total Marks	100	3&4	Unit-2: Question 3 or 4	20
1	0.5	101		586	Unit-3: Question 5 or 6	20
				788	Unit-4: Quantion 7 or 8	20
				9 & 10	Unit-5: Question 9 or 10	20
					Total Marks	100



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SEMESTER III

Course Code	:	MVE461N	INTERNSHIP	CIE Marks	:	50
Credits L-T-P	:	0 - 0 - 6		SEE Marks	:	50
Hours/Week	:	12		SEE Durations	:	3 Hrs

Guidelines:

1. The duration of the internship shall be for a period of 6 weeks on full time basis after II semester final exams and before the commencement of III semester.

2. The student must submit letters from the industry clearly specifying his / her name and the duration of the internship on the company letter head with authorized signature.

3. Internship must be related to the field of specialization of the respective PG programme in which the student has enrolled.

4. Students undergoing internship training are advised to report their progress and submit periodic progress reports to their respective guides.

5. Students have to present the internship activities carried out to the departmental committee and only upon approval by the committee, the student can proceed to prepare and submit the hard copy of the final internship report. 6. The reports shall be printed on A4 size with 1.5 spacing and Times New Roman with font size 12, outer cover of the report (wrapper) has to be softbound in Ivory color for PG circuit

Programs and Light Blue for Non-Circuit Programs.

Course Outcomes: After going through the internship the student will be able to

CO1: Apply Engineering and Management principles to solve the problems CO2:

Analyze real-time problems and suggest alternate solutions

CO3: Communicate effectively and work in teams

CO4: Imbibe the practice of professional ethics and lifelong learning

Scheme of Continuous Internal Evaluation (CIE):

The evaluation committee shall consist of Guide, Professor, Associate Professor/Assistant Professor. The committee shall assess the presentation and the progress reports.

Reviews	Activity	Weightag
т	Application of Engineering knowledge in industries, ability to comprehend the	4.0%
1	functioning of the Organization/ Departments.	4070
TT	Importance of Resource Management, Environment and Sustainability.	60%
11	Demonstration and Presentation of Internship work with Report Submission	0070

Scheme for Semester End Evaluation (SEE):

The SEE examination shall be conducted by an external examiner (domain expert) and an internal examiner. Evaluation shall be done in batches, not exceeding 6 students per batch.



SEMESTER III

Course Code	:	MVE461P		CIE Marks	:	50
Credits L-T-P	:	0 - 0 - 6	MINOR PROJECT	SEE Marks	:	50
Hours/Week	:	12		SEE Durations	:	3 Hrs

Guidelines:

1. Each project group will consist of maximum of two students.

2. Each student / group has to select a contemporary topic that will use the technical knowledge of their program of study after intensive literature survey.

- 3. Allocation of the guides preferably in accordance with the expertise of the faculty.
- 4. The minor project would be performed in-house.

5. The implementation of the project must be preferably carried out using the resources available in the department/college.

Course Outcomes: After completing the course, the students will be able to

CO1: Conceptualize, design and implement solutions for specific problems.

- CO2: Communicate the solutions through presentations and technical reports.
- CO3: Apply resource managements skills for projects.

CO4: Synthesize self-learning, team work and ethics.

Scheme of Continuous Internal Examination

Evaluation shall be carried out in three reviews. The evaluation committee shall consist of Guide, Professor and Associate Professor/Assistant Professor.

Phase *	Activity	Weightage
Ι	Approval of the selected topic, formulation of Problem Statement and Objectives with Synopsis submission	20 %
II	Mid-term seminar to review the progress of the work with documentation	40 %
III	Oral presentation, demonstration and submission of project report	40 %
* Phase wise :	rubrics to be prepared by the respective departments	·

CIE Evaluation shall be done with weightage / distribution as follows:	1/
• Selection of the topic & formulation of Problem Statement and Objectives	10 %
• Design and simulation/ Algorithm development/ Experimental setup	25 %
Conducting experiments/ Implementation / Testing	25 %
Demonstration & Presentation	25 %
• Report writing	15 %

Scheme of Semester End Examination (SEE):

The evaluation will be done by ONE senior faculty from the department and ONE external faculty member from Academia / Industry / Research Organization. The following weightages would be given for the examination. Evaluation will be done in batches, not exceeding 6 students.

- Brief write up about the project 05%
- \bullet Methodology and Experimental Results & Discussion 20%
- \bullet Presentation / Demonstration of the Project 25%
- Report 20%
- Viva Voce 30%



	1 1			
Course Code	: MVE491P		CIE Marks	: 100
Credits L-T-P	: 0 - 0 - 18	MAJOR PROJECT	SEE Marks	: 100
Hours/Week	: 36		SEE Durations	: 3 Hrs
Guidelines:	1 1		1	1 1
 Major Project Students mu Project diary sig It is mandate Conferences or The reports so cover of the rep Circuit Program Course Outcom CO1: Conceptua Communicate to CO3: Apply projector CO4: Synthesize Scheme of Correct	t is to be carried o ust adhere to the P gned by their guide ory for the student Journals shall be printed or ort (wrapper) has ns nes: After comple alize, Design and 1 he solutions throu ject and resource is the self-learning, su	ut for a duration of 18 weeks roject Presentation Schedule, report to their guide of e 4. Students must execute the Major Project individ is to present/publish their project work in National/ a A4 size with 1.5 spacing and Times New Roman wit to be soft bound and in Ivory color for PG circuit Pro- eting the course, the students will be able to Implement solutions for specific problems. CO2: agh presentations and technical reports. managements skills, professional ethics and societa stainable solutions and demonstrate life-long learning Examination	on a weekly basis dually and not in /International ith font size 12, or ograms and Light l concerns ng	and get their teams. uter Blue for Non-
Evaluation shal Professor/Assis	ll be carried out in stant Professor.	three reviews. The evaluation committee shall cons	sist of Guide, Profe	essor, Associate
Evaluation shal Professor/Assis	ll be carried out in stant Professor.	three reviews. The evaluation committee shall cons	sist of Guide, Profe	essor, Associate
Evaluation shal Professor/Assis Phase *	Il be carried out in stant Professor.	three reviews. The evaluation committee shall cons Activity	sist of Guide, Profe	weightage
Evaluation shal Professor/Assis Phase * I	ll be carried out in stant Professor.	Activity ect Title, Formulation of Problem Statement and Obj	sist of Guide, Profe	Weightage
Evaluation shal Professor/Assis Phase * I II	ll be carried out in stant Professor. Selection of Proje Design, Impleme	Activity ect Title, Formulation of Problem Statement and Obj ntation and Testing	ectives	Weightage 20 % 40 %
Evaluation shal Professor/Assis Phase * I II II	ll be carried out in stant Professor. Selection of Proje Design, Impleme Experimental Res Report Writing an	Activity Activi	sist of Guide, Profession of G	Weightage 20 % 40 %
Evaluation shal Professor/Assis Phase * I II II * Phase wise ru	ll be carried out in stant Professor. Selection of Proje Design, Impleme Experimental Res Report Writing an brics to be prepar	Activity Activity act Title, Formulation of Problem Statement and Obj ntation and Testing sult & Analysis, Conclusions and Future Scope of W and Paper Publication ed by the respective departments	sist of Guide, Profession of G	Weightage 20 % 40 % 40 %
Evaluation shal Professor/Assis Phase * I II II * Phase wise ru	ll be carried out in stant Professor. Selection of Proje Design, Implement Experimental Res Report Writing an brics to be prepare	Activity Activi	sist of Guide, Profester	Weightage 20 % 40 % 40 %
Evaluation shal Professor/Assis Phase * I II II * Phase wise ru Scheme for Se Major Project S Project Report a Stage-1 Report Stage-2 Projec reports from Gu	Il be carried out in stant Professor. Selection of Proje Design, Impleme: Experimental Res Report Writing an brics to be prepar- brics to be prepar- mester End Evalu EE evaluation sha and CIE marks. t Evaluation: Eval t Viva-voce: Majo uide and External	Activity Activi	sist of Guide, Profession fectives /ork, fulfilment of subrest and an External receipt of evaluation	Weightage 20 % 40 % 40 % anission of examiner. on
Evaluation shal Professor/Assis Phase * I II II * Phase wise ru Scheme for Set Major Project Stage-1 Report Stage-2 Projec reports from Gu	Il be carried out in stant Professor. Selection of Proje Design, Impleme Experimental Res Report Writing an brics to be prepar- brics to be prepar	Activity Activi	sist of Guide, Profession ectives /ork, fulfilment of subrest and an External receipt of evaluation	Weightage 20 % 40 % 40 % inission of examiner. on
Evaluation shal Professor/Assis Phase * I II II * Phase wise ru Scheme for Se Major Project S Project Report a Stage-1 Report Stage-2 Projec reports from Gu	Il be carried out in stant Professor. Selection of Proje Design, Impleme: Experimental Res Beport Writing an brics to be prepare brics to be prepare mester End Evalu EE evaluation sha and CIE marks. t Evaluation: Evaluation: Evaluation: Evaluation: Evaluation: Evaluation t Viva-voce: Majo uide and External	Activity Activi	sist of Guide, Profession fectives /ork, fulfilment of subrest and an External receipt of evaluation	Weightage 20 % 40 % 40 % anission of examiner. on
Evaluation shal Professor/Assis Phase * I II II * Phase wise ru Scheme for Set Major Project S Project Report a Stage-1 Report Stage-2 Projec reports from Gu SEE procedure Report	Il be carried out in stant Professor. Selection of Proje Design, Impleme Experimental Res Report Writing an brics to be prepar- brics to be prepar	Activity Activi	sist of Guide, Professional State of Guide, Profession State of Guide, Profession State of St	Weightage 20 % 40 % 40 % unission of examiner. on 20 % 20
Evaluation shal Professor/Assis Phase * I II II * Phase wise ru Scheme for Se: Major Project S: Project Report a Stage-1 Report Stage-2 Projec: reports from Gu SEE procedure Report Evaluation	Il be carried out in stant Professor. Selection of Proje Design, Impleme: Experimental Res Report Writing an brics to be prepar- brics to be prepar- mester End Evalu EE evaluation sha and CIE marks. t Evaluation: Evaluation: Evaluation: Evaluation t Viva-voce: Majo uide and External ide and External internal Examine External Examine	Activity Constrained of Problem Statement and Obj Constrained of Problem Statement and Obj Constrained and Testing Sult & Analysis, Conclusions and Future Scope of W Constrained by the respective departments Constrained of Project Report shall be done by the Guide r Project Viva-voce examination is conducted after r examiner. Constrained of Marks er: 100 Marks	sist of Guide, Profession fectives /ork, fulfilment of subrest e and an External receipt of evaluation = 2 200 / 2 = 100	Weightage 20 % 40 % 40 % 40 % anission of examiner. on 200 A
Evaluation shal Professor/Assis Phase * I II II * Phase wise ru Scheme for Set Major Project S Project Report Stage-1 Report Stage-2 Projec reports from Gu SEE procedure Report Evaluation Viva-Voce	Il be carried out in stant Professor. Selection of Proje Design, Impleme Experimental Res Report Writing an brics to be prepar- brics to be prepar	Activity Activity	sist of Guide, Professional State of Guide, Professional State of	Weightage 20 % 40 % 40 % 40 % Description A B

SEMESTER IV



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Curriculum Design Process



Performace

< Expected

No

Yes

Remedial



Methods/Redefine CO's

Data and Students



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Process For Course Outcome Attainment





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Program Outcome Attainment Process



INNOVATIVE TEAMS OF RVCE

- 1. Ashwa Racing : Ashwa Mobility Foundation (AMF) is a student R&D platform that designs and fabricates Formula-themed race cars and future mobility solutions to tackle urban transportation problems.
- 2. Astra Robotics Team : Involved in the design, fabrication, and building of application-specific robots.
- 3. Coding Club : To facilitate students in acquiring the skills, confidence, and opportunities to change their world using coding. The club aims to help students become successful in GSoC, ACM-ICPC, and other recognized coding competitions.
- 4. Entrepreneurship Development Cell : E-Cell is a student-run body that aims to promote entrepreneurship by conducting workshops, speaker sessions, and discussions on business and its aspects. The organization possesses a mentor board to help startups grow.
- 5. Frequency Club Team : This team contributes to both software and hardware domains, mainly focusing on Artificial Intelligence, Machine Learning, and its advances.
- 6. Team Garuda : Design and development of a supermileage urban concept electric car. Indigenous development of E-mobility products.
- 7. Team Jatayu : Aims to build a low-cost Unmanned Aerial Vehicle capable of autonomous navigation, obstacle avoidance, object detection, localization, classification, and air drop of a package of optimum weight.
- 8. Solar Car : Aims to build a roadworthy solar electric vehicle to contribute to a green and sustainable environment.
- 9. Team Antariksh : A Space Technology Student Club whose goal is to understand, disseminate, and apply engineering skills for innovation in the field of Space technology, including the development of operational rockets of various altitude platforms.
- 10. Team Chimera : Building a Formula Electric Car through research and development in E-Mobility. Electrifying Formula Racing.
- 11. Helios Racing Team : Involved in the design, manufacturing, and testing of All-Terrain Vehicles and other supportive tasks for the functioning of the team. Participating in BAJA competitions organized by SAE in India and the USA.
- 12. Team Hydra : Developing autonomous underwater vehicles for various real-world applications such as water purification, solid waste detection and disposal, etc.
- 13. Team Krushi : Aims to develop low-cost equipment to help farmers in cultivating and harvesting. Uses new technology applications to reduce labor time and cost for farmers. Aims at developing implements for tractors.
- 14. Team Vyoma : Design, fabrication, and testing of radio-controlled aircraft and research on various types of unmanned aerial vehicles.
- 15. Team Dhruva : Organizing activities like guizzes based on astronomy, stargazing, and telescope handling sessions. Construction of a standard observatory and working on small projects with organizations like ICTS, IIA, ARIES, etc.
- 16. Ham Club : To popularize Amateur Radio as a hobby among students, alongside exploring technical innovations in the communications domain. Intended to provide human capital for service to the nation during times of natural calamities.

Cultural Activity Teams

- AALAP (Music club)
- 2. DEBSOC (Debating society)
- 3. CARV (Dramatics club)
- FOOTPRINTS (Dance club) 4.
- QUIZCORP (Quizzing society) ROTARACT (Social welfare club) 5.
- 6.
- RAAG (Youth club) 7.
- EVOKE (Fashion team) 8.
- f/6.3 (Photography club) 9
- 10. CARV ACCESS (Film-making







NCC of RVCE

VISION

Leadership in Quality Technical Education, Interdisciplinary Research & Innovation, with a Focus on Sustainable and Inclusive Technology

MISSION

- To deliver outcome based Quality education, emphasizing on experientiallearning with the state of the art infrastructure.
- To create a conducive environment for interdisciplinary research and innovation.
- To develop professionals through holistic education focusing on individual growth, discipline, integrity, ethics and social sensitivity.
- To nurture industry-institution collaboration leading to competency enhancement and entrepreneurship.
- To focus on technologies that are sustainable and inclusive, benefiting all sections of the society.

QUALITY POLICY

Achieving Excellence in Technical Education, Research and Consulting through an Outcome Based Curriculum focusing on Continuous Improvement and Innovation by Benchmarking against the global Best Practices.

CORE VALUES

Professionalism, Commitment, Integrity, Team Work, Innovation



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